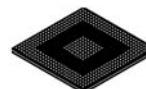
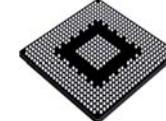




## MPC5676R



TEPBGA-416  
27 mm x 27 mm



TEPBGA-516  
27mm x 27mm

## MPC5676R Microcontroller Data Sheet

On-chip modules available within the family include the following features:

- Two identical dual issue, 32-bit CPU core complexes (e200z7), each with
  - Power Architecture embedded specification compliance
  - Instruction set enhancement allowing variable length encoding (VLE), optional encoding of mixed 16-bit and 32-bit instructions, for code size footprint reduction
  - Signal processing extension (SPE) instruction support for digital signal processing (DSP)
  - Single-precision floating point operations (FPU)
  - 16 KB I-Cache and 16 KB D-Cache
  - Hardware cache coherency between cores
- 16 Hardware semaphores
- 3 channel CRC module
- 6MB on-chip flash
  - Supports read during program and erase operations, and multiple blocks allowing EEPROM emulation
- 384KB on-chip general-purpose SRAM including 48KB of standby RAM
- Two multi-channel direct memory access controllers (eDMA)
  - 64 channels per eDMA
- Dual core Interrupt controller (INTC)
- Phase-locked loop with FM modulation (FMPLL)
- Crossbar switch architecture for concurrent access to peripherals, flash, or RAM from multiple bus masters
- External Bus Interface (EBI) for calibration and application development
- System integration unit (SIU) with error correction status module (ECSM)
- Four protected port output pins (PPO)
- Boot assist module (BAM) supports serial bootload via CAN or SCI
- Three second-generation enhanced time processor units (eTPU2)
- Up to 96 eTPU2 channels (32 channels per eTPU2)
  - total of 36 KB code RAM
  - total of 9 KB parameter RAM
- Enhanced modular input output system supporting 32 unified channels (eMIOS) with each channel capable of single action, double action, pulse width modulation (PWM) and modulus counter operation
- Two enhanced queued analog-to-digital converter (eQADC) modules with
  - two separate analog converters per eQADC module
  - support for a total of 64 analog input pins, expandable to 176 inputs with off-chip multiplexers
  - one absolute reference ADC channel
  - interface to twelve hardware decimation filters
  - enhanced ‘Tap’ command to route any conversion to two separate decimation filters
  - Temperature sensor
- Five deserial serial peripheral interface (DSPI) modules
- Three enhanced serial communication interface (eSCI) modules
- Four controller area network (FlexCAN) modules
- Dual-channel FlexRay controller
- Nexus development interface (NDI) per IEEE-ISTO 5001-2003 standard, with some support for 2010 standard.
- Device and board test support per Joint Test Action Group (JTAG) (IEEE 1149.1)
- On-chip voltage regulator controller regulates supply voltage down to 1.2 V for core logic
- Self Test capability

This document contains information on a product under development. Freescale reserves the right to change or discontinue this product without notice.

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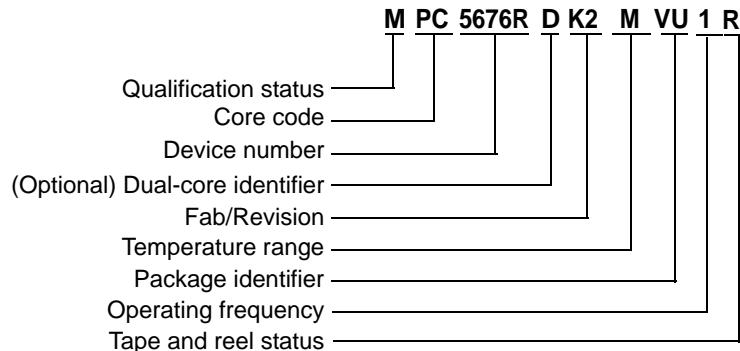
# Table of Contents

1	Ordering Information.....	3
1.1	Orderable Parts.....	3
2	MPC5676R Blocks .....	4
2.1	Block Diagram.....	4
3	Pin Assignments.....	6
3.1	416-ball TEPBGA Pin Assignments .....	6
3.2	516-ball TEPBGA Pin Assignments .....	7
3.3	Pin Muxing and Reset States .....	8
4	Electrical Characteristics .....	8
4.1	Maximum Ratings .....	8
4.2	Thermal Characteristics .....	9
4.2.1	General Notes for Specifications at Maximum Junction Temperature .....	11
4.3	EMI (Electromagnetic Interference) Characteristics .....	12
4.4	ESD Characteristics .....	13
4.5	PMC/POR/LVI Electrical Specifications .....	13
4.5.1	Regulator Example .....	16
4.6	Power Up/Down Sequencing .....	18
4.6.1	Power-Up .....	19
4.6.2	Power-Down .....	19
4.6.3	Power Sequencing and POR Dependent on $V_{DDA}$ .....	20
4.7	DC Electrical Specifications .....	20
4.7.1	I/O Pad Current Specifications .....	23
4.7.2	I/O Pad $V_{DD33}$ Current Specifications .....	24
4.7.3	LVDS Pad Specifications .....	25
4.8	Oscillator and FMPLL Electrical Characteristics .....	27
4.9	eQADC Electrical Characteristics .....	29
4.10	C90 Flash Memory Electrical Characteristics .....	31
4.11	AC Specifications .....	32
4.11.1	Clocking Modes .....	32
4.11.2	Pad AC Specifications .....	33
4.12	AC Timing .....	34
4.12.1	Generic Timing Diagrams.....	34
4.12.2	Reset and Configuration Pin Timing.....	35
4.12.3	IEEE 1149.1 Interface Timing.....	36
4.12.4	Nexus Timing .....	39
4.12.5	External Bus Interface (EBI) Timing.....	41
4.12.6	External Interrupt Timing (IRQ Pin) .....	46
4.12.7	eTPU Timing .....	46
4.12.8	eMIOS Timing .....	47
4.12.9	DSPI Timing .....	48
5	Package Information .....	54
5.1	416-Pin Package.....	54
5.2	516-Pin Package.....	56
6	Product Documentation.....	58
	Appendix A Signal Properties and Muxing .....	59
	Appendix B Revision History .....	109

# 1 Ordering Information

## 1.1 Orderable Parts

Figure 1 and Table 1 describe and list the orderable part numbers for the MPC5676R.



**Temperature Range**  
M = -40 °C to 125 °C

**Package Identifier**  
VU = 416 TEPBGA  
Pb-Free  
VY = 516 TEPBGA  
Pb-Free

**Operating Frequency**  
1 = 2 x 180 MHz

**Tape and Reel Status**  
R = Tape and reel  
(blank) = Trays

### Qualification Status

P = Pre qualification

M = Fully spec. qualified, general market flow

S = Fully spec. qualified, automotive flow

**Note:** Not all options are available on all devices. Refer to Table 1.

Figure 1. MPC5676R Orderable Part Number Description

Table 1. Orderable Part Numbers

NXP Part Number <sup>1</sup>	Package Description	Speed (MHz) <sup>2</sup>		Operating Temperature <sup>3</sup>	
		Nominal	Max <sup>4</sup> (f <sub>MAX</sub> )	Min (T <sub>L</sub> )	Max (T <sub>H</sub> )
SPC5676RDK2MVU1R	MPC5676R 416 package Lead-free (Pb-free)	180	184	-40 °C	125 °C
SPC5676RDK2MVY1R	MPC5676R 516 package Lead-free (Pb-free)	180	184	-40 °C	125 °C

<sup>1</sup> All packaged devices are PPC5676R, rather than MPC5676R or SPC5676R, until product qualifications are complete. The unpackaged device prefix is PCC, rather than SCC, until product qualification is complete.  
Not all configurations are available in the PPC parts.

<sup>2</sup> For the operating mode frequency of various blocks on the device, see Table 28.

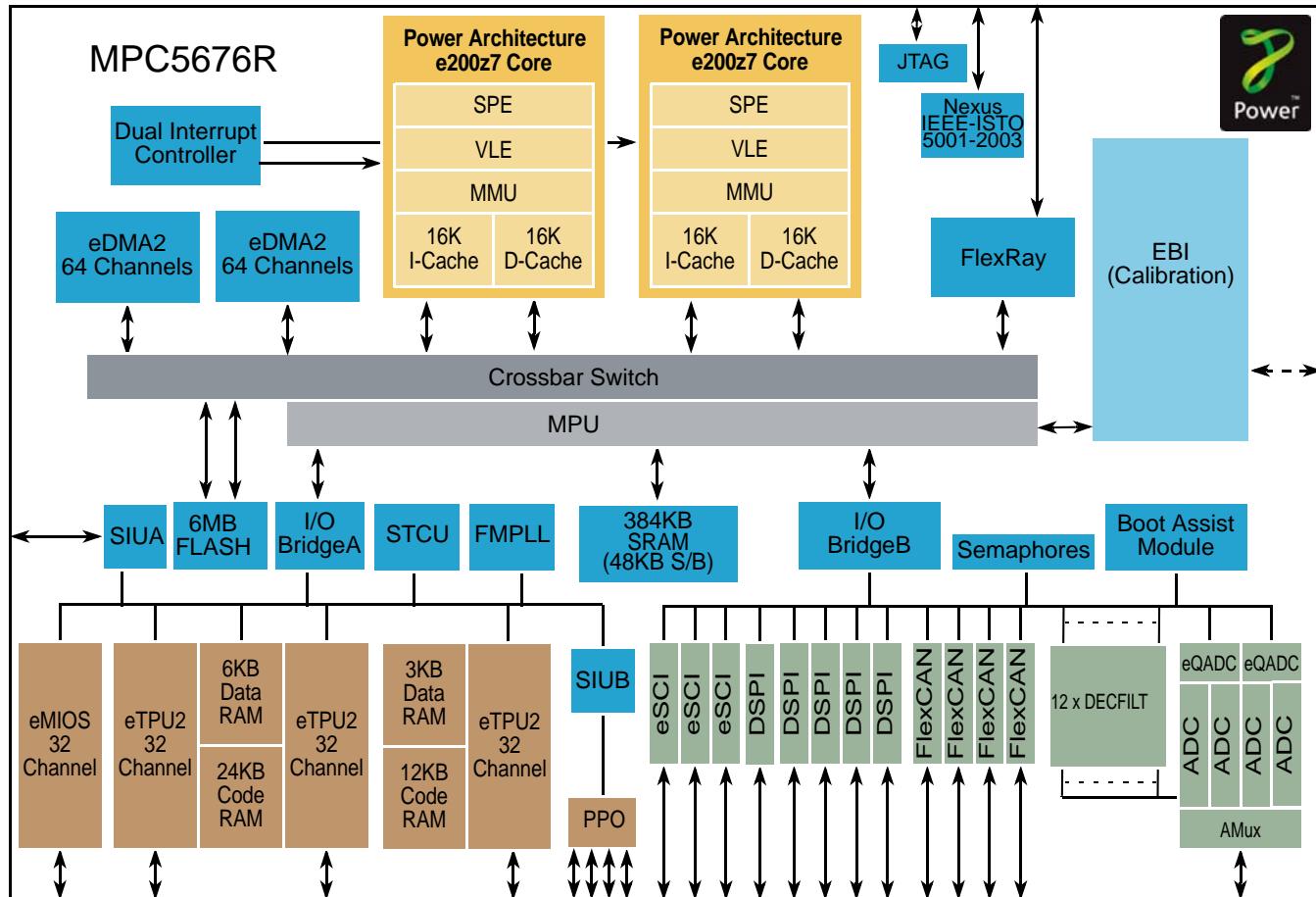
<sup>3</sup> The lowest ambient operating temperature is referenced by T<sub>L</sub>; the highest ambient operating temperature is referenced by T<sub>H</sub>.

<sup>4</sup> Speed is the nominal maximum frequency. Max speed is the maximum speed allowed including frequency modulation (FM). 180 MHz parts allow for 180 MHz system clock + 2% FM.

## 2 MPC5676R Blocks

### 2.1 Block Diagram

The following figure shows a top-level block diagram of the MPC5676R. The purpose of the block diagram is to show the general interconnection of functional modules through the crossbar switch and from the Dual Interrupt Controller, and provide an indication of the modules that connect to external pins. For clarity, the following modules are omitted from the diagram: PMU, SWT, STM, PIT, ECSV, DTS, and CRC.



#### LEGEND

ADC	- Analog to Digital Converter
AMux	- Analog Pin Multiplexer
D-Cache	- Data Cache
DECFILT	- Decimation Filter
DSPI	- Deserial/Serial Peripheral Interface
EBI	- External Bus Interface
eDMA2	- Enhanced Direct Memory Access controller version 2
eMIOS	- Enhanced Modular I/O System
eQADC	- Enhanced Queued Analog to Digital Converter
eSCI	- Enhanced Serial Communications Interface
eTPU2	- Enhanced Time Processing Unit version 2
FlexCAN	- Flexible Controller Area Network controller
FMPLL	- Frequency Modulated Phase Lock Loop clock generator
I-Cache	- Instruction Cache
IRC	- Internal RC Oscillator
JTAG	- Joint Test Action Group controller
MMU	- Memory Management Unit
MPU	- Memory Protection Unit
PPO	- Protected Port Output
S/B	- Stand-by
SIUA	- System Integration Unit A
SIUB	- System Integration Unit B
SPE	- Signal Processing Engine
SRAM	- Static RAM
STCU	- Self Test Control Unit
VLE	- Variable Length instruction Encoding

Figure 2. MPC5676R Block Diagram

## 3 Pin Assignments

### 3.1 416-ball TEPBGA Pin Assignments

Figure 3 shows the 416-ball TEPBGA pin assignments.

## **CAUTION**

This ball map is preliminary and subject to change. Do not use it for board design.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	
A	VSS	VDD	RSTOUT	ANA0	ANA4	ANA8	ANA11	ANA15	VDDA_A0	REF-BYPC1	VRL_A	VRH_A	AN28	AN32	AN36	VDDA_B0	REF-BYPC1	VRL_B	VRH_B	ANB7	ANB11	ANB14	ANB17	ANB21	ANB23	VSS	A
B	VDDEH1	VSS	VDD	TEST	ANA1	ANA5	ANA10	ANA14	VDDA_A1	VSSA_A1	REF-BYPC1	AN24	AN27	AN29	AN33	VDDA_B1	VSSA_B0	REF-BYPCB	ANB6	ANB8	ANB10	ANB15	ANB18	ANB22	VSS	TCRCLKC	B
C	ETPUA30	ETPUA31	VSS	VDD	ANA2	ANA6	ANA9	ANA13	ANA17	ANA19	ANA21	ANA23	AN26	AN30	AN34	AN37	AN38	ANB0	ANB4	ANB5	ANB12	ANB16	ANB19	VSS	ETPUC0	ETPUC1	C
D	ETPUA27	ETPUA28	ETPUA29	VSS	VDD	ANA3	ANA7	ANA12	ANA16	ANA18	ANA20	ANA22	AN25	AN31	AN35	AN39	ANB1	ANB2	ANB3	ANB9	ANB13	ANB20	VSS	VDDEH7	ETPUC2	ETPUC3	D
E	ETPUA23	ETPUA24	ETPUA25	ETPUA26																			VDDEH7	ETPUC4	ETPUC5	ETPUC6	E
F	ETPUA19	ETPUA20	ETPUA21	ETPUA22																			ETPUC7	ETPUC8	ETPUC9	ETPUC10	F
G	ETPUA15	ETPUA16	ETPUA17	ETPUA18																			ETPUC11	ETPUC12	ETPUC13	ETPUC14	G
H	ETPUA11	ETPUA12	ETPUA14	ETPUA13																			ETPUC15	ETPUC16	ETPUC17	ETPUC18	H
J	ETPUA7	ETPUA8	ETPUA9	ETPUA10																			ETPUC19	ETPUC20	ETPUC21	ETPUC22	J
K	ETPUA3	ETPUA4	ETPUA5	ETPUA6																			ETPUC23	ETPUC24	ETPUC25	ETPUC26	K
L	TCRCLKA	ETPUA0	ETPUA1	ETPUA2																			ETPUC27	ETPUC28	ETPUC29	ETPUC30	L
M	VDD33_1	TXDA	RXDA	VSTBY																			ETPUC31	ETPUB15	ETPUB14	VDDEH7	M
N	RXDB	BOOT-CFG1	WPKCFG	VDD																			VDDEH6	ETPUB11	ETPUB12	ETPUB13	N
P	TXDB	PLLCFG1	PLLCFG2	VDDEH1																			ETPUB7	ETPUB8	ETPUB9	ETPUB10	P
R	JCOMP	RESET	PLLCFG0	RDY																			ETPUB3	ETPUB4	ETPUB5	ETPUB6	R
T	VDDE2	MCK0	MSE01	EVTI																			TCRCLKB	ETPUB0	ETPUB1	ETPUB2	T
U	EVTO	MSE00	MDO0	MDO1																			ETPUB19	ETPUB18	ETPUB17	ETPUB16	U
V	MDO2	MDO3	MDO4	MDO5																			ETPUB26	ETPUB22	ETPUB21	ETPUB20	V
W	MDO6	MDO7	MDO8	VDDE2																			REGSEL	ETPUB25	ETPUB24	ETPUB23	W
Y	MDO9	MDO10	MDO11	MDO15																			ETPUB29	ETPUB28	ETPUB27	REGCTL	Y
AA	MDO12	MDO13	MDO14	VDD33_2																			VDD33_3	ETPUB30	VDDREG	VSSSYN	AA
AB	TDO	TCK	TMS	VDD																			VDD	ETPUB31	VSSFL	EXTAL	AB
AC	VDDE2	TDI	VDD	VSS	VDDE2	PCSA1	PCSA2	PCSB4	PCSB1	VDDEH3	VDDEH4	VDD	EMIOS8	EMIOS14	EMIOS18	EMIOS22	EMIOS27	EMIOS31	CNRXB	CNRXD	VDDEH5	PCSC1	VSS	VDD	VDDEH6	XTAL	AC
AD	ENGCLK	VDD	VSS	FR_A-TX	FR_B-TX	PCSA5	SOUTA	SCKA	PCSB0	PCSB3	EMIOS2	EMIOS5	EMIOS9	EMIOS15	EMIOS19	EMIOS23	EMIOS26	EMIOS30	CNTXB	CNTXD	SCKC	RXDC	PCSC3	VSS	VDD	VDDSYN	AD
AE	VDD	VSS	FR_A-RX	FR_B-RX	PCSA4	PCSA0	PCSA3	SCKB	SINB	EMIOS0	EMIOS3	EMIOS6	EMIOS10	EMIOS13	EMIOS17	EMIOS21	EMIOS25	EMIOS29	CNRXA	CNRXC	PCSC0	SINC	PCSC2	PCSC5	VSS	VDD	AE
AF	VSS	VDDE2	FR_A-TX_EN	FR_B-TX_EN	VDDEH3	PCSB5	SINA	PCSB2	SOUTB	EMIOS1	EMIOS4	EMIOS7	EMIOS11	EMIOS12	EMIOS16	EMIOS20	EMIOS24	EMIOS28	CNTXA	CNTXC	SOUTC	VDDEH4	TXDC	PCSC4	VDDEH5	VSS	AF

**Figure 3. MPC5676R 416-ball TEPBGA (full diagram)**

## Pin Assignments

### 3.2 516-ball TEPBGA Pin Assignments

Figure 4 shows the 516-ball TEPBGA pin assignments.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26			
A	VDD	RSTOUT	ANA0	ANA4	ANA9	ANA11	ANA15	VDDA_A0	REF-BYPC1	VRL_A	VRH_A	AN28	AN29	AN36	VDDA_B0	REF-BYPC1	VRL_B	VRH_B	ANB5	ANB9	ANB12	ANB18	ANB21	VSS		A			
B	VDDEH1	VSS	VDD	TEST	ANA1	ANA5	ANA10	ANA14	VDDA_A1	VSSA_A1	REF-BYPC1	AN24	AN27	AN30	AN32	VDDA_B1	VSSA_B1	REF-BYPC1	ANB4	ANB8	ANB10	ANB13	ANB19	ANB22	VSS	VSS	B		
C	ETPUA30	ETPUA31	VSS	VDD	ANA2	ANA6	ANA7	ANA13	ANA17	ANA19	ANA21	ANA22	AN25	AN31	AN34	AN39	AN37	ANB6	ANB7	ANB8	ANB11	ANB15	ANB20	VSS	ETPUC0	ETPUC1	C		
D	ETPUA27	ETPUA28	ETPUA29	VSS	VDD	ANA3	ANA8	ANA12	ANA16	ANA18	ANA20	ANA23	AN26	AN33	AN35	AN38	ANB1	ANB2	ANB3	ANB4	ANB16	ANB17	VSS	VDDEH7	ETPUC2	ETPUC3	D		
E	ETPUA23	ETPUA24	ETPUA25	ETPUA26	VSS	VDD	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDEH7	ETPUC4	ETPUC5	ETPUC6	E	
F	ETPUA19	ETPUA20	ETPUA21	ETPUA22	VSS	VDDE8		VDDE8		VDDE8	VDDE8		VSS	VSS		VDDE10	VDDE10		VDDE10		VDDE10		VDCLKC	ETPUC7	ETPUC8	ETPUC9	ETPUC10	F	
G	ETPUA11	ETPUA13	ETPUA15	ETPUA17	ETPUA18																							G	
H	ETPUA5	ETPUA7	ETPUA8	ETPUA3	ETPUA4	ETPUA14	ETPUA16																						H
J	ETPUA1	ETPUA2	ETPUA9	ETPUA4	ETPUA12																								J
K	TXDB	TXDA	RXDA	TCRCLKA	ETPUA6	ETPUA10																							K
L	PLLCFG1	PLLCFG2	BOOT-CFG1	BOOT-CFG0	RXDB	ETPUA0																							L
M	VDD33_1	D_BDIP	PLLCFG0	VSTBY	WKPCFG																								M
N	D_WE0	D_WE2	D_WE3	VDD	RESET	VDDE8																							N
P	D_ADD9	D_ADD10	D_ADD11	VDDEH1	D_WE1	VDD33_1																							P
R	D_ADD12	D_ADD13	D_ADD14	D_ADD15	D_ADD16																								R
T	VDDE2	D_ADD18	D_ADD19	D_ADD20	D_ADD17	D_CS3																							T
U	D_CS2	JCOMP	RDY	MCK0	MSE01	MSE00																							U
V	EVTI	EVTO	MDO0	MDO2	MDO3																								V
W	MDO4	MDO5	MDO6	VDDE2	MDO8	MDO1																						W	
Y	MDO7	MDO9	MDO10	MDO11	MDO12																								Y
AA	MDO13	MDO14	MDO15	VDD33_1	VDDE8	VSS			PCSA5		SOUTB	VDD33_4		VDDE9	VDD33_4		EMIOS23	EMIOS31		CNRXB		VSS	VDDE10	VDD33_3	ETPUB16	VDDREG	VSSYN	AA	
AB	TDO	TCK	TMS	VDD	VSS	VDDE9	VDDE9	SCKA	SINB	D_CS1	D_ADD21	D_ADD28	EMIOS1	EMIOS11	EMIOS17	EMIOS19	EMIOS29	VDDE9	VDDE9	VDDE9	VSS	VDD	ETPUB30	VSSFL	EXTAL	AB			
AC	VDDE2	TDI	VDD	VSS	VDDE2	PCSA1	SOUTA	SCKB	PCSB3	VDDEH3	VDDEH4	VDD	EMIOS0	EMIOS8	EMIOS13	EMIOS22	EMIOS24	EMIOS28	CNTXB	CNRXD	VDDEH5	PCSC1	VSS	VDD	VDDEH6	XTAL	AC		
AD	ENGCLK	VDD	VSS	FR_A_TX	FR_B_TX	PCSA0	PCSA3	PCSB2	D_CS0	D_ADD22	D_ADD25	D_ADD28	EMIOS2	EMIOS7	EMIOS12	EMIOS16	EMIOS18	EMIOS27	CNRXA	CNTXD	SCKC	RXDC	PCSC3	VSS	VDD	VDDSYN	AD		
AE	VDD	VSS	FR_A_RX	FR_B_RX	PCSA4	PCSB5	SINA	PCSB1	D_TS	D_ADD23	D_ADD26	D_ADD30	EMIOS3	EMIOS8	EMIOS10	EMIOS15	EMIOS21	EMIOS26	CNTXA	CNRXC	PCSC0	SINC	PCSC2	PCSC5	VSS	VDD	AE		
AF	VDDE2	FR_A_TX_EN	FR_B_TX_EN	VDDEH3	PCSA2	PCSB4	PCSB0	D_TA	D_ADD24	D_ADD27	D_CLKOUT	EMIOS4	EMIOS5	EMIOS9	EMIOS20	EMIOS14	EMIOS25	EMIOS30	CNTXC	SOUTC	VDDEH4	TXDC	PCSC4	VDDEH5			AF		

Figure 4. MPC5676R 516-ball TEPBGA (full diagram)

### 3.3 Pin Muxing and Reset States

See [Appendix A, Signal Properties and Muxing](#), for a listing and description of the pin functions and properties.

## 4 Electrical Characteristics

This section contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications for the MPC5676R.

The electrical specifications are preliminary and are from previous designs, design simulations, or initial evaluation. These specifications may not be fully tested or guaranteed at this early stage of the product life cycle, however for production silicon these specifications will be met. Finalized specifications will be published after complete characterization and device qualifications have been completed.

### 4.1 Maximum Ratings

**Table 2. Absolute Maximum Ratings<sup>1</sup>**

Spec	Characteristic	Symbol	Min	Max <sup>2</sup>	Unit
1	1.2 V Core Supply Voltage <sup>3</sup>	V <sub>DD</sub>	-0.3	1.65 <sup>4</sup>	V
2	SRAM Standby Voltage	V <sub>STBY</sub>	-0.3	5.5 <sup>5,6</sup>	V
3	Clock Synthesizer Voltage	V <sub>DDSYN</sub>	-0.3	4.5 <sup>6,7</sup>	V
4	I/O Supply Voltage (I/O buffers and predrivers)	V <sub>DD33</sub>	-0.3	4.5 <sup>6,7</sup>	V
5	Analog Supply Voltage (reference to V <sub>SSA</sub> <sup>8</sup> )	V <sub>DDA</sub> <sup>9</sup>	-0.3	5.5 <sup>5,6</sup>	V
6	I/O Supply Voltage (fast I/O pads)	V <sub>DDE</sub>	-0.3	4.5 <sup>6</sup>	V
7	I/O Supply Voltage (medium I/O pads)	V <sub>DDEH</sub>	-0.3	5.5 <sup>5,6</sup>	V
8	Voltage Regulator Input Supply Voltage	V <sub>DDREG</sub>	-0.3	5.5 <sup>5,6</sup>	V
9	Analog Reference High Voltage (reference to V <sub>RL</sub> <sup>10</sup> )	V <sub>RH</sub> <sup>11</sup>	-0.3	5.5 <sup>5,6</sup>	V
10	V <sub>SS</sub> to V <sub>SSA</sub> <sup>8</sup> Differential Voltage	V <sub>SS</sub> - V <sub>SSA</sub>	-0.1	0.1	V
11	V <sub>REF</sub> Differential Voltage	V <sub>RH</sub> - V <sub>RL</sub>	-0.3	5.5 <sup>5,6</sup>	V
12	V <sub>RL</sub> to V <sub>SSA</sub> Differential Voltage	V <sub>RL</sub> - V <sub>SSA</sub>	-0.3	0.3	V
13	V <sub>DD33</sub> to V <sub>DDSYN</sub> Differential Voltage	V <sub>DD33</sub> - V <sub>DDSYN</sub>	-0.1	0.1	V
14	V <sub>SSSYN</sub> to V <sub>SS</sub> Differential Voltage	V <sub>SSSYN</sub> - V <sub>SS</sub>	-0.1	0.1	V
15	Maximum Digital Input Current <sup>12</sup> (per pin, applies to all digital pins)	I <sub>MAXD</sub>	-3 <sup>13</sup>	3 <sup>13</sup>	mA
16	Maximum Analog Input Current <sup>14</sup> (per pin, applies to all analog pins)	I <sub>MAXA</sub>	-3 <sup>9,13</sup>	3 <sup>9,13</sup>	mA

**Electrical Characteristics****Table 2. Absolute Maximum Ratings<sup>1</sup> (continued)**

Spec	Characteristic	Symbol	Min	Max <sup>2</sup>	Unit
17	Maximum Operating Temperature Range <sup>15</sup> – Die Junction Temperature	T <sub>J</sub>	-40.0	150.0	°C
18	Storage Temperature Range	T <sub>stg</sub>	-55.0	150.0	°C
19	Maximum Solder Temperature <sup>16</sup> Pb-free package SnPb package	T <sub>sdr</sub>	— —	260.0 245.0	°C
20	Moisture Sensitivity Level <sup>17</sup>	MSL	—	3	—

<sup>1</sup> Functional operating conditions are given in the DC electrical specifications. Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the listed maxima may affect device reliability or cause permanent damage to the device.

<sup>2</sup> Absolute maximum voltages are currently maximum burn-in voltages. Absolute maximum specifications for device stress have not yet been determined.

<sup>3</sup> 1.2 V ±10% for proper operation. This parameter is specified at a maximum junction temperature of 150 °C.

<sup>4</sup> 2.0 V for 10 hours cumulative time, 1.2 V +10% for time remaining.

<sup>5</sup> 6.4 V for 10 hours cumulative time, 5.0 V +10% for time remaining.

<sup>6</sup> Voltage overshoots during a high-to-low or low-to-high transition must not exceed 10 seconds per instance.

<sup>7</sup> 4.5 V for 10 hours cumulative time, 3.3 V +10% for time remaining.

<sup>8</sup> MPC5676R has two analog power supply pins on the pinout: VDDA\_A and VDDA\_B.

<sup>9</sup> MPC5676R has two analog ground supply pins on the pinout: VSSA\_A and VSSA\_B.

<sup>10</sup> MPC5676R has two analog low reference voltage pins on the pinout: VRL\_A and VRL\_B.

<sup>11</sup> MPC5676R has two analog high reference voltage pins on the pinout: VRH\_A and VRH\_B.

<sup>12</sup> Total injection current for all pins must not exceed 25 mA at maximum operating voltage.

<sup>13</sup> Injection current of ±5 mA allowed for limited duration for analog (ADC) pads and digital 5 V pads. The maximum accumulated time at this current shall be 60 hours. This includes an assumption of a 5.25 V maximum analog or V<sub>DDEH</sub> supply when under this stress condition.

<sup>14</sup> Total injection current for all analog input pins must not exceed 15 mA.

<sup>15</sup> Lifetime operation at these specification limits is not guaranteed.

<sup>16</sup> Solder profile per CDF-AEC-Q100.

<sup>17</sup> Moisture sensitivity per JEDEC test method A112.

## 4.2 Thermal Characteristics

**Table 3. Thermal Characteristics, 416-pin TEPBGA Package<sup>1</sup>**

Characteristic	Symbol	Value	Unit
Junction to Ambient <sup>2,3</sup> Natural Convection (Single layer board)	R <sub>θJA</sub>	24	°C/W
Junction to Ambient <sup>2,4</sup> Natural Convection (Four layer board 2s2p)	R <sub>θJA</sub>	16	°C/W
Junction to Ambient (@200 ft./min., Single layer board)	R <sub>θJMA</sub>	18	°C/W

**Table 3. Thermal Characteristics, 416-pin TEPBGA Package<sup>1</sup> (continued)**

Characteristic	Symbol	Value	Unit
Junction to Ambient (@200 ft./min., Four layer board 2s2p)	$R_{\theta JMA}$	13	°C/W
Junction to Board <sup>5</sup>	$R_{\theta JB}$	8	°C/W
Junction to Case <sup>6</sup>	$R_{\theta JC}$	4	°C/W
Junction to Package Top <sup>7</sup> Natural Convection	$\Psi_{JT}$	3	°C/W

<sup>1</sup> Thermal characteristics are targets based on simulation that are subject to change per device characterization.

<sup>2</sup> Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.

<sup>3</sup> Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.

<sup>4</sup> Per JEDEC JESD51-6 with the board horizontal.

<sup>5</sup> Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

<sup>6</sup> Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature.

<sup>7</sup> Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

**Table 4. Thermal Characteristics, 516-pin TEPBGA Package<sup>1</sup>**

Characteristic	Symbol	Value	Unit
Junction to Ambient <sup>2,3</sup> Natural Convection (Single layer board)	$R_{\theta JA}$	24	°C/W
Junction to Ambient <sup>2,4</sup> Natural Convection (Four layer board 2s2p)	$R_{\theta JA}$	17	°C/W
Junction to Ambient (@200 ft./min., Single layer board)	$R_{\theta JMA}$	19	°C/W
Junction to Ambient (@200 ft./min., Four layer board 2s2p)	$R_{\theta JMA}$	14	°C/W
Junction to Board <sup>5</sup>	$R_{\theta JB}$	9	°C/W
Junction to Case <sup>6</sup>	$R_{\theta JC}$	5	°C/W
Junction to Package Top <sup>7</sup> Natural Convection	$\Psi_{JT}$	2	°C/W

<sup>1</sup> Thermal characteristics are targets based on simulation that are subject to change per device characterization.

<sup>2</sup> Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.

<sup>3</sup> Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.

<sup>4</sup> Per JEDEC JESD51-6 with the board horizontal.

<sup>5</sup> Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

<sup>6</sup> Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature.

**Electrical Characteristics**

- <sup>7</sup> Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

**4.2.1 General Notes for Specifications at Maximum Junction Temperature**

An estimation of the chip junction temperature,  $T_J$ , can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} * P_D) \quad Eqn. 1$$

where:

$T_A$  = ambient temperature for the package ( $^{\circ}\text{C}$ )

$R_{\theta JA}$  = junction to ambient thermal resistance ( $^{\circ}\text{C/W}$ )

$P_D$  = power dissipation in the package (W)

The junction to ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. Unfortunately, there are two values in common usage: the value determined on a single layer board and the value obtained on a board with two planes. For packages such as the TEPBGA, these values can be different by a factor of two. Which value is closer to the application depends on the power dissipated by other components on the board. The value obtained on a single layer board is appropriate for the tightly packed printed circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated.

When a heat sink is used, the thermal resistance is expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA} \quad Eqn. 2$$

where:

$R_{\theta JA}$  = junction to ambient thermal resistance ( $^{\circ}\text{C/W}$ )

$R_{\theta JC}$  = junction to case thermal resistance ( $^{\circ}\text{C/W}$ )

$R_{\theta CA}$  = case to ambient thermal resistance ( $^{\circ}\text{C/W}$ )

$R_{\theta JC}$  is device related and cannot be influenced by the user. The user controls the thermal environment to change the case to ambient thermal resistance,  $R_{\theta CA}$ . For instance, the user can change the size of the heat sink, the air flow around the device, the interface material, the mounting arrangement on printed circuit board, or change the thermal dissipation on the printed circuit board surrounding the device.

To determine the junction temperature of the device in the application when heat sinks are not used, the Thermal Characterization Parameter ( $\Psi_{JT}$ ) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} * P_D) \quad Eqn. 3$$

where:

$T_T$  = thermocouple temperature on top of the package ( $^{\circ}\text{C}$ )

$\Psi_{JT}$  = thermal characterization parameter ( $^{\circ}\text{C/W}$ )

$P_D$  = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm. of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

**References:**

Semiconductor Equipment and Materials International  
3081 Zanker Road  
San Jose, CA 95134  
(408) 943-6900

MIL-SPEC and EIA/JESD (JEDEC) specifications are available from Global Engineering Documents at 800-854-7179 or 303-397-7956.

JEDEC specifications are available on the WEB at <http://www.jedec.org>.

- C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47-54.
- G. Kromann, S. Shidore, and S. Addison, "Thermal Modeling of a PBGA for Air-Cooled Applications," Electronic Packaging and Production, pp. 53-58, March 1998.
- B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212-220.

## 4.3 EMI (Electromagnetic Interference) Characteristics

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions, go to [www.nxp.com](http://www.nxp.com) and perform a keyword search for "radiated emissions." The following tables list the values of the device's radiated emissions operating behaviors.

**Table 5. EMC Radiated Emissions Operating Behaviors: 416 BGA**

Symbol	Description	Conditions	f <sub>osc</sub> f <sub>SYS</sub>	Frequency band (MHz)	Level (max.)	Unit	Notes
V <sub>RE_TEM</sub>	Radiated emissions, electric field and magnetic field	V <sub>DD</sub> = 1.2 V V <sub>DDE</sub> = 3.3 V V <sub>DDEH</sub> = 5 V T <sub>A</sub> = 25 °C 416 BGA EBI off CLK off FM off	40 MHz crystal 180 MHz (f <sub>EBI_CAL</sub> = 46 MHz)	0.15–50	26	dB $\mu$ V	1
				50–150	30		
				150–500	34		
				500–1000	30		
				IEC and SAE level	I <sup>2</sup>	—	1, 3
V <sub>RE_TEM</sub>	Radiated emissions, electric field and magnetic field	V <sub>DD</sub> = 1.2 V V <sub>DDE</sub> = 3.3 V V <sub>DDEH</sub> = 5 V T <sub>A</sub> = 25 °C 416 BGA EBI off CLK off FM on <sup>4</sup>	40 MHz crystal 180 MHz (f <sub>EBI_CAL</sub> = 46 MHz)	0.15–50	24	dB $\mu$ V	1
				50–150	25		
				150–500	25		
				500–1000	21		
				IEC and SAE level	K <sup>5</sup>	—	1, 3

<sup>1</sup> Determined according to IEC Standard 61967-2, Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method, and SAE Standard J1752-3, Measurement of Radiated Emissions from Integrated Circuits—TEM/Wideband TEM (GTEM) Cell Method.

<sup>2</sup> I = 36 dB $\mu$ V

<sup>3</sup> Specified according to Annex D of IEC Standard 61967-2, Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method, and Appendix D of SAE Standard J1752-3, Measurement of Radiated Emissions from Integrated Circuits—TEM/Wideband TEM (GTEM) Cell Method.

<sup>4</sup> "FM on" = FM depth of ±2%

<sup>5</sup> K = 30 dB $\mu$ V

## 4.4 ESD Characteristics

**Table 6. ESD Ratings<sup>1,2</sup>**

Spec	Characteristic	Symbol	Value	Unit
1	ESD for Human Body Model (HBM)	$V_{HBM}$	2000	V
2	ESD for Charged Device Model (CDM)	$V_{CDM}$	750 (corners) 500 (other)	V

<sup>1</sup> All ESD testing is in conformity with CDF-AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits.

<sup>2</sup> A device will be defined as a failure if after exposure to ESD pulses the device no longer meets the device specification requirements. Complete DC parametric and functional testing shall be performed per applicable device specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

## 4.5 PMC/POR/LVI Electrical Specifications

**Table 7. PMC Operating conditions**

Spec	Name	Parameter	Condition	Min	Typ	Max	Unit
1	$V_{DDREG}$	Supply voltage VDDREG 5 V nominal <sup>1</sup>	LDO5V / SMPS5V mode	4.5	5	5.5	V
2	$V_{DDREG}$	Supply voltage VDDREG 3 V nominal <sup>1</sup>	LDO3V mode	3.0	3.3	3.6	V
3	$V_{DD33}$	Supply voltage VDDSYN / $V_{DD33}$ 3.3 V nominal <sup>2</sup>	LDO3V mode	3.0	3.3	3.6	V
4	$V_{DD}$	Supply voltage VDD 1.2 V nominal <sup>3</sup>	—	1.14	1.2	1.32	V

<sup>1</sup> Voltage should be higher than maximum  $V_{LVDREG}$  to avoid LVD event

<sup>2</sup> Applies to both  $V_{DD33}$  (flash supply) and VDDSYN (PLL supply) pads. Voltage should be higher than maximum  $V_{LVD33}$  to avoid LVD event

<sup>3</sup> Voltage should be higher than maximum  $V_{LVD12}$  to avoid LVD event

### NOTE

In the following table, “untrimmed” means “at reset” and “trimmed” means “after reset”.

**Table 8. PMC Electrical Specifications**

Spec	Name	Symbol	Condition	Min	Typ	Max	Unit
1	Nominal bandgap reference voltage	$V_{BG}$	—	0.59	0.620	0.65	V
1a	Bandgap reference voltage during power on reset	—	—	$V_{BG} - 5\%$	$V_{BG}$	$V_{BG} + 5\%$	V
1b	Bandgap reference voltage at nominal voltage / nominal temperature after power on reset	—	—	$V_{BG} - 2\%$	$V_{BG}$	$V_{BG} + 2\%$	V

**Table 8. PMC Electrical Specifications**

<b>Spec</b>	<b>Name</b>	<b>Symbol</b>	<b>Condition</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Unit</b>
1c	Bandgap reference voltage / temperature dependence after power on reset	—	—	—	300	—	ppm/C
1d	Bandgap reference voltage / voltage dependence ( $V_{DDREG}$ ) after power on reset	—	—	—	1500	—	
2	Nominal VRC regulated 1.2V output VDD <sup>1</sup>	$V_{DD12OUT}$	—	—	1.2	—	V
2a	VRC 1.2V output variation at reset (unloaded) <sup>2</sup>	—	At POR	$V_{DD12OUT} - 8\%$	$V_{DD12OUT}$	$V_{DD12OUT} + 10\%$	
2b	VRC 1.2V output variation after reset(REGCTL load max. 20mA, VDD load max. 1A)	—	After POR	$V_{DD12OUT} - 5\%$	$V_{DD12OUT}$	$V_{DD12OUT} + 10\%$	
2c	Trimming step Vdd1p2	$V_{STEPV12}$	—	—	10	—	mV
3	POR rising VDD 1.2V	$V_{PORC}$	—	-	0.7	—	V
3a	POR VDD 1.2V variation	—	—	$V_{PORC} - 30\%$	$V_{PORC}$	$V_{PORC} + 30\%$	
3b	POR 1.2V hysteresis	—	—	—	75	—	mV
4	Nominal rising LVD 1.2V <sup>3</sup>	$V_{LVD12}$	—	—	1.100	—	V
4a	LVD 1.2V variation before band gap trim <sup>4</sup>	—	At POR	$V_{LVD12} - 6\%$	$V_{LVD12}$	$V_{LVD12} + 6\%$	
4b	LVD 1.2V variation after band gap trim <sup>4</sup>	—	After POR	$V_{LVD12} - 3\%$	$V_{LVD12}$	$V_{LVD12} + 3\%$	
4c	LVD 1.2V Hysteresis	—	—	15	20	25	mV
4d	Trimming step LVD 1.2V	$V_{LVDSTEP12}$	—	—	10	—	mV
5	VRC 1.2V max DC output current	$I_{REGCTL}$	—	—	—	20	mA
6	Voltage regulator 1.2V current consumption VDDREG	—	—	—	3	—	mA
7	Nominal Vreg 3.3V output <sup>5</sup>	$V_{DD33OUT}$	—	—	3.3	—	V
7a	Vreg 3.3V output variation at reset (unloaded) <sup>6</sup>	—	At POR	$V_{DD33OUT} - 6\%$	$V_{DD33OUT}$	$V_{DD33OUT} + 10\%$	
7b	Vreg 3.3V output variation after reset (max. load 60mA)	—	After POR	$V_{DD33OUT} - 5\%$	$V_{DD33OUT}$	$V_{DD33OUT} + 10\%$	
7c	Trimming step VDDSYN	$V_{STEPV33}$	—	—	30	—	mV
8	Nominal rising LVD 3.3V <sup>7</sup>	$V_{LVD33}$	—	—	2.950	—	V
8a	LVD 3.3V variation before band gap trim <sup>6</sup>	—	At POR	$V_{LVD33} - 5\%$	$V_{LVD33}$	$V_{LVD33} + 5\%$	
8b	LVD 3.3V variation after bad gap trim <sup>6</sup>	—	After POR	$V_{LVD33} - 3\%$	$V_{LVD33}$	$V_{LVD33} + 3\%$	

## Electrical Characteristics

Table 8. PMC Electrical Specifications

Spec	Name	Symbol	Condition	Min	Typ	Max	Unit
8c	LVD 3.3V Hysteresis	—	—	—	30	—	mV
8d	Trimming step LVD 3.3V	$V_{LVDSTEP33}$	—	—	30	—	mV
9	Vreg 3.3V minimum peak DC output current supplied by regulator without causing $V_{LVD33}^8$	$I_{DD33}$	—	60	—	—	mA
10	Voltage regulator 3.3V current consumption VDDREG <sup>9</sup>	—	—	—	2	—	mA
11	POR rising on VDDREG	$V_{PORREG}$	—	—	2.00	—	V
11a	POR VDDREG variation	—	—	$V_{PORREG} - 30\%$	$V_{PORREG}$	$V_{PORREG} + 30\%$	
11b	POR VDDREG hysteresis	—	—	—	250	—	mV
12	Nominal rising LVD VDDREG	$V_{LVDREG}$	LDO3V / LDO5V mode	—	2.950	—	V
12a	LVD VDDREG variation at reset <sup>10</sup>	—	At POR	$V_{LVDREG} - 5\%$	$V_{LVDREG}$	$V_{LVDREG} + 5\%$	
12b	LVD VDDREG variation after reset <sup>10</sup>	—	After POR	$V_{LVDREG} - 3\%$	$V_{LVDREG}$	$V_{LVDREG} + 3\%$	
12c	LVD VDDREG Hysteresis	—	LDO3V / LDO5V mode	—	30	—	mV
12d	Trimming step LVD VDDREG	$V_{LVDSTEPREG}$	LDO3V / LDO5V mode	—	30	—	mV
13	Nominal rising LVD VDDREG	$V_{LVDREG}$	SMPS5V mode	—	4.360	—	V
13a	LVD VDDREG variation at reset <sup>10</sup>	—	At POR	$V_{LVDREG} - 5\%$	$V_{LVDREG}$	$V_{LVDREG} + 5\%$	
13b	LVD VDDREG variation after reset <sup>10</sup>	—	After POR	$V_{LVDREG} - 3\%$	$V_{LVDREG}$	$V_{LVDREG} + 3\%$	
14	SMPS regulator output resistance <sup>11</sup>	—	—	—	15	25	Ohm
15	SMPS regulator clock frequency	—	After POR	1.0	1.5	—	MHz
16	SMPS regulator overshoot at start-up <sup>12</sup>	—	GBD/GBC <sup>13</sup>	—	1.32	1.4	V
17	SMPS maximum output current, as required by SoC <sup>14</sup>	—	—	—	1.0	—	A
18	Voltage variation on current step (20% to 80% of maximum current with 4 usec constant time) <sup>14</sup>	—	GBD/GBC <sup>13</sup>	—	—	0.1	V

- <sup>1</sup> Nominal internal regulator output voltage is 1.27V
- <sup>2</sup> Voltage should be higher than maximum VLVD12 to avoid LVD event
- <sup>3</sup> ~VDD12OUT \*0.87
- <sup>4</sup> Rising VDD
- <sup>5</sup> Nominal internal regulator output voltage is 3.4V
- <sup>6</sup> Rising VDDSYN
- <sup>7</sup> ~VDD33OUT \*0.872
- <sup>8</sup> VDDSYN
- <sup>9</sup> Except IDD33
- <sup>10</sup> Rising VDDREG
- <sup>11</sup> Pull up to VDDREG when high, pull down to VSSREG when low.
- <sup>12</sup> Depends on external device, can be as high as 1.6V for short time (<100 usec each start-up)
- <sup>13</sup> GBD — Guaranteed By Design; GBC — Guaranteed by Characterization
- <sup>14</sup> Proper external devices required

## 4.5.1 Regulator Example

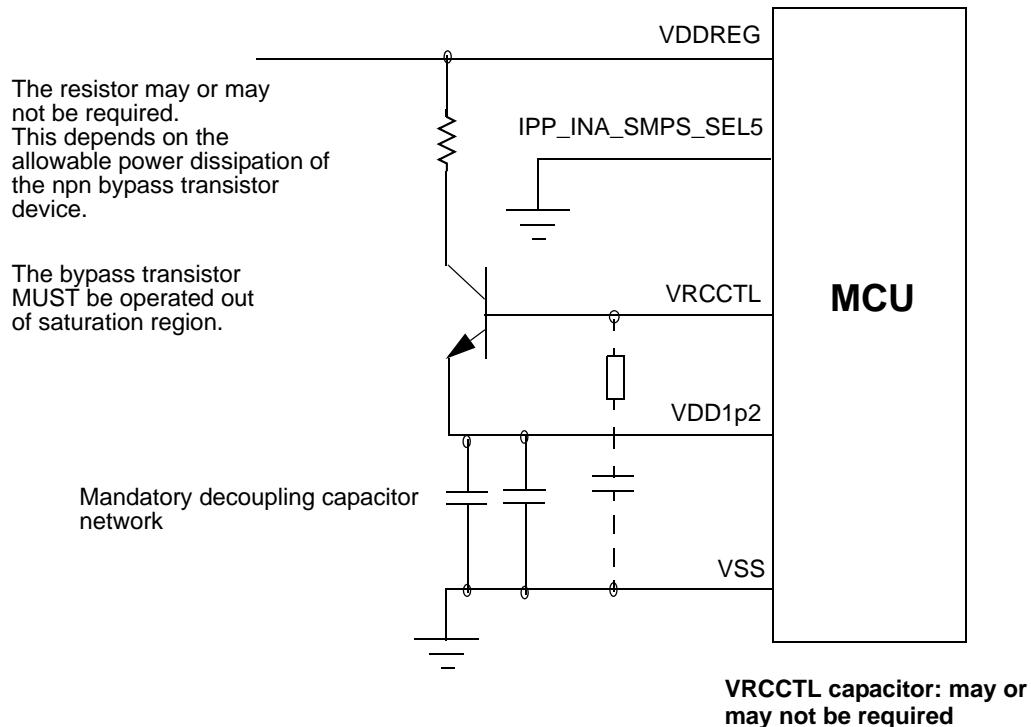
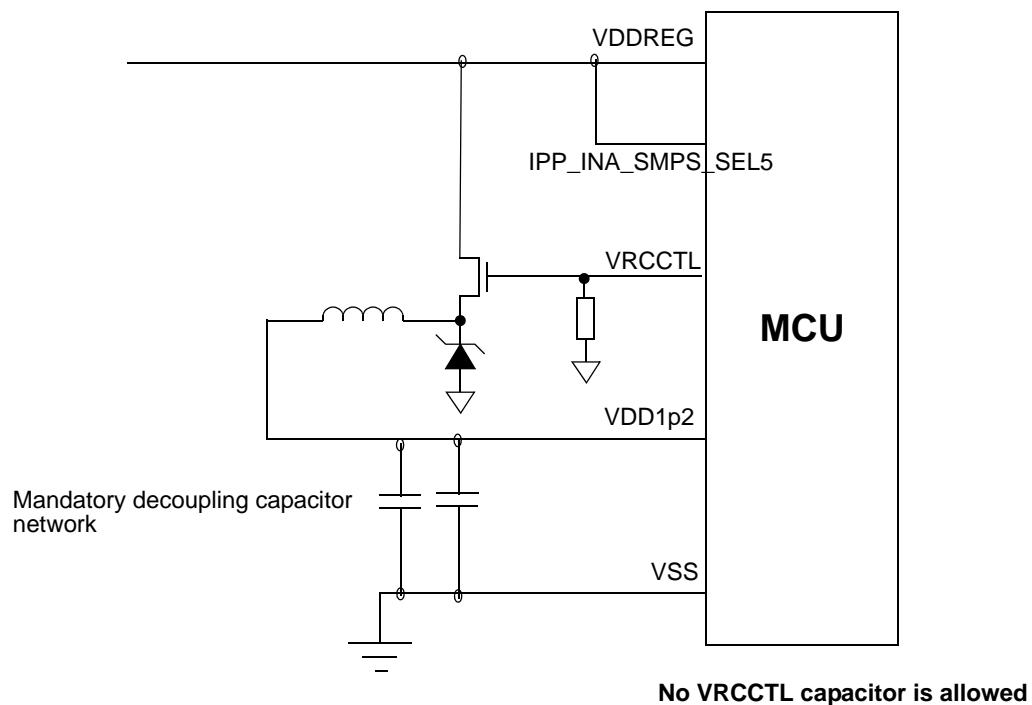


Figure 5. VRC 1.2 V LDO configuration with external bipolar



**Figure 6. VRC 1.2V buck SMPS LDO configuration with external MOS - Schottky diode**

**Table 9. VRC LDO recommended external devices**

Part Name	Part Type	Nominal	Description
NJD2873 Beta (Bf)	NPN		ON Semiconductor TM From 60 to 550
Vbe			From 0.4 V to 1.0 V
Vce	Capacitor	6 x 4.7 $\mu$ F - 20 V	From 0.2 V to 0.6 V depends on package / power Ceramic low ESR—One for each VDD pin
	Capacitor	6 x 0.1 $\mu$ F - 20 V	Ceramic —One capacitor for each VDD pin
	Capacitor	20 $\mu$ F	Supply decoupling cap (close to bipolar collector)
	Capacitor	2.2 $\mu$ F	Snubber cap, required with NJD2873 (on bipolar base)
	Resistor	12 $\Omega$	Optional ESR for snubber cap

**Table 10. VRC SMPS recommended external devices**

Part Name	Part Type	Nominal	Description
IR7353	HS nMOS + Schottky		Low threshold n-MOS/Low Vf Schottky diode
SS8P3L	Schottky		Low Vf Schottky diode
Vf			From 0.4V to 0.6 V
SI3460 or equivalent	nMOS		Low threshold n-MOS
Vth			Less than 2 V
Ids			More than 1.5 A
Vds			More than 12 V
Rdson			Less than 100 Ohms
Cg			Less than 5 nF
Turn on / off delay			Less than 50 ns
Rise time			Less than 90 ns
LQH66SN2R2M03	inductor	2.2 uH—3.2 A	muRata TM shielded coil, preferred $f_{max} > 40$ MHz
C3225X7R1E106M	capacitor	22 uF — 25 V	TDK high capacitance ceramic SMD (on VDD close to coil)
C3225X7R1E225K	capacitor	2 to 6 x 2.2 uF — 25 V	TDK ceramic SMD (on VDD close to MCU)
	capacitor	6 x 0.1 uF — 20 V	Ceramic -One capacitor for each VDD pin
C3225X7R1E106M	capacitor	22 uF — 25 V	Supply decoupling cap—close to n-MOS drain
	resistor	20 K	Pull down for power n—MOS gate

## 4.6 Power Up/Down Sequencing

There is no power sequencing required among power sources during power up and power down in order to operate within specification as long as the following two rules are met:

- When VDDREG is tied to a nominal 3.3V supply, VDD33 and VDDSYN must be both shorted to VDDREG.
- When VDDREG is tied to a 5V supply, VDD33 and VDDSYN must be tied together and shall be powered by the internal 3.3V regulator.

The recommended power supply behavior is as follows: Use 25 V/millisecond or slower rise time for all supplies. Power up each  $V_{DDE}/V_{DDEH}$  first and then power up  $V_{DD}$ . For power down, drop  $V_{DD}$  to 0 V first, and then drop all  $V_{DDE}/V_{DDEH}$  supplies. There is no limit on the fall time for the power supplies.

Although there are no power up/down sequencing requirements to prevent issues like latch-up, excessive current spikes, etc., the state of the I/O pins during power up/down varies according to [Table 11](#) and [Table 12](#).

**Table 11. Power Sequence Pin States for MH and AE pads**

<b>VDD</b>	<b>VDD33</b>	<b>VDDE</b>	<b>MH Pad</b>	<b>MH+LVDS Pads<sup>1</sup></b>	<b>AE/up-down Pads</b>
High	High	High	Normal operation	Normal operation	Normal operation
—	Low	High	Pin is tri-stated (output buffer, input buffer, and weak pulls disabled)	Outputs driven high	Pull-ups enabled, pull-downs disabled
Low	High	Low	Output low, pin unpowered	Outputs disabled	Output low, pin unpowered
Low	High	High	Pin is tri-stated (output buffer, input buffer, and weak pulls disabled)	Outputs disabled	Pull-ups enabled, pull-downs disabled

<sup>1</sup> MH+LVDS pads are output-only.

**Table 12. Power Sequence Pin States for F and FS pads**

<b>VDD</b>	<b>VDD33</b>	<b>VDDE</b>	<b>F and FS pads</b>
low	low	high	Outputs drive high
low	high	—	Outputs Disabled
high	low	low	Outputs Disabled
high	low	high	Outputs drive high
high	high	low	Normal operation - except no drive current and input buffer output is unknown. <sup>1</sup>
high	high	high	Normal Operation

<sup>1</sup> The pad pre-drive circuitry will function normally but since VDDE is unpowered the outputs will not drive high even though the output pmos can be enabled.

## 4.6.1 Power-Up

If  $V_{DDE}/V_{DDEH}$  is powered up first, then a threshold detector tristates all drivers connected to  $V_{DDE}/V_{DDEH}$ . There is no limit to how long after  $V_{DDE}/V_{DDEH}$  powers up before  $V_{DD}$  must power up. If there are multiple  $V_{DDE}/V_{DDEH}$  supplies, they can be powered up in any order. For each  $V_{DDE}/V_{DDEH}$  supply not powered up, the drivers in that  $V_{DDE}/V_{DDEH}$  segment exhibit the characteristics described in the next paragraph.

If  $V_{DD}$  is powered up first, then all pads are loaded through the drain diodes to  $V_{DDE}/V_{DDEH}$ . This presents a heavy load that pulls the pad down to a diode above  $V_{SS}$ . Current injected by external devices connected to the pads must meet the current injection specification. There is no limit to how long after  $V_{DD}$  powers up before  $V_{DDE}/V_{DDEH}$  must power up.

The rise times on the power supplies are to be no faster than 25 V/millisecond.

## 4.6.2 Power-Down

If  $V_{DD}$  is powered down first, then all drivers are tristated. There is no limit to how long after  $V_{DD}$  powers down before  $V_{DDE}/V_{DDEH}$  must power down.

If  $V_{DDE}/V_{DDEH}$  is powered down first, then all pads are loaded through the drain diodes to  $V_{DDE}/V_{DDEH}$ . This presents a heavy load that pulls the pad down to a diode above  $V_{SS}$ . Current injected by external devices connected to the pads must meet the current injection specification. There is no limit to how long after  $V_{DDE}/V_{DDEH}$  powers down before  $V_{DD}$  must power down.

There are no limits on the fall times for the power supplies.

### 4.6.3 Power Sequencing and POR Dependent on V<sub>DDA</sub>

During power up or down, V<sub>DDA</sub> can lag other supplies (of magnitude greater than V<sub>DDEH</sub>/2) within 1 V to prevent any forward-biasing of device diodes that causes leakage current and/or POR. If the voltage difference between V<sub>DDA</sub> and V<sub>DDEH</sub> is more than 1 V, the following will result:

- Triggers POR (ADC monitors on V<sub>DDEH1</sub> segment which powers the RESET pin) if the leakage current path created, when V<sub>DDA</sub> is sufficiently low, causes sufficient voltage drop on V<sub>DDEH1</sub> node monitored crosses low-voltage detect level.
- If V<sub>DDA</sub> is between 0–2 V, powering all the other segments (especially V<sub>DDEH1</sub>) will not be sufficient to get the part out of reset.
- Each V<sub>DDEH</sub> will have a leakage current to V<sub>DDA</sub> of a magnitude of ((V<sub>DDEH</sub> – V<sub>DDA</sub> – 1 V(diode drop)/200 KOhms) up to (V<sub>DDEH</sub>/2 = V<sub>DDA</sub> + 1 V). .
- Each V<sub>DD</sub> has the same behavior; however, the leakage will be small even though there is no current limiting resistor since V<sub>DD</sub> = 1.32 V max.

### 4.7 DC Electrical Specifications

Table 13. DC Electrical Specifications<sup>1</sup>

Spec	Characteristic	Symbol	Min	Max	Unit
1	Core Supply Voltage (External Regulation)	V <sub>DD</sub>	1.14	1.32 <sup>2, 3</sup>	V
1a	Core Supply Voltage (Internal Regulation) <sup>4</sup>	V <sub>DD</sub>	1.08	1.32	V
2	I/O Supply Voltage (fast I/O pads)	V <sub>DDE</sub>	3.0	3.6 <sup>2</sup>	V
3	I/O Supply Voltage (medium I/O pads)	V <sub>DDEH</sub>	3.0	5.25 <sup>2</sup>	V
4	3.3 V I/O Buffer Voltage	V <sub>DD33</sub>	3.0	3.6 <sup>2</sup>	V
5	Analog Supply Voltage	V <sub>DDA</sub>	4.75	5.25 <sup>2</sup>	V
6a	SRAM Standby Voltage low range	V <sub>STBY_LOW</sub>	0.95 <sup>5</sup>	1.2	V
6b	SRAM Standby Voltage high range	V <sub>STBY_HIGH</sub>	2	6	V
7	Voltage Regulator Control Input Voltage <sup>6</sup>	V <sub>DDREG</sub>	2.7 <sup>7</sup>	5.5 <sup>2</sup>	V
8	Clock Synthesizer Operating Voltage <sup>8</sup>	V <sub>DDSYN</sub>	3.0	3.6 <sup>2</sup>	V
9	Fast I/O Input High Voltage Hysteresis enabled Hysteresis disabled	V <sub>IH_F</sub>	0.65 × V <sub>DDE</sub> 0.55 × V <sub>DDE</sub>	V <sub>DDE</sub> + 0.3	V
10	Fast I/O Input Low Voltage Hysteresis enabled Hysteresis disabled	V <sub>IL_F</sub>	V <sub>SS</sub> – 0.3	0.35 × V <sub>DDE</sub> 0.40 × V <sub>DDE</sub>	V
11	Medium I/O Input High Voltage Hysteresis enabled Hysteresis disabled	V <sub>IH_S</sub>	0.65 × V <sub>DDEH</sub> 0.55 × V <sub>DDEH</sub>	V <sub>DDEH</sub> + 0.3	V

## Electrical Characteristics

Table 13. DC Electrical Specifications<sup>1</sup> (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
12	Medium I/O Input Low Voltage Hysteresis enabled Hysteresis disabled	V <sub>IL_S</sub>	V <sub>SS</sub> – 0.3	0.35 × V <sub>DDEH</sub> 0.40 × V <sub>DDEH</sub>	V
13	Fast I/O Input Hysteresis	V <sub>HYS_F</sub>	0.1 × V <sub>DDE</sub>	—	V
14	Medium I/O Input Hysteresis	V <sub>HYS_S</sub>	0.1 × V <sub>DDEH</sub>	—	V
15	Analog Input Voltage	V <sub>INDC</sub>	V <sub>SSA</sub> – 0.1	V <sub>DDA</sub> + 0.1	V
16	Fast I/O Output High Voltage <sup>9</sup>	V <sub>OH_F</sub>	0.8 × V <sub>DDE</sub>	—	V
17	Medium I/O Output High Voltage <sup>10</sup>	V <sub>OH_S</sub>	0.8 × V <sub>DDEH</sub>	—	V
18	Fast I/O Output Low Voltage <sup>9</sup>	V <sub>OL_F</sub>	—	0.2 × V <sub>DDE</sub>	V
19	Medium I/O Output Low Voltage	V <sub>OL_S</sub>	—	0.2 × V <sub>DDEH</sub> <sup>1</sup> 0.15 × V <sub>DDEH</sub> <sup>11</sup>	V
20	Load Capacitance (Fast I/O) <sup>12</sup> DSC(PCR[8:9]) = 0b00 DSC(PCR[8:9]) = 0b01 DSC(PCR[8:9]) = 0b10 DSC(PCR[8:9]) = 0b11	C <sub>L</sub>	— — — —	10 20 30 50	pF pF pF pF
21	Input Capacitance (Digital Pins)	C <sub>IN</sub>	—	7	pF
22	Input Capacitance (Analog Pins)	C <sub>IN_A</sub>	—	10	pF
23	Input Capacitance (Digital and Analog Pins <sup>13</sup> )	C <sub>IN_M</sub>	—	12	pF
24	Operating Current 1.2 V Supplies @ f <sub>sys</sub> = 180 MHz V <sub>DD</sub> (including V <sub>DDF</sub> current) @ 1.32 V V <sub>STBY</sub> <sup>14</sup> @ 1.2 V and 85°C V <sub>STBY</sub> <sup>15</sup> @ 6.0 V and 85°C V <sub>DDF</sub> <sup>15</sup> (P/E) V <sub>DDF</sub> <sup>15</sup> (Read) V <sub>DDF</sub> <sup>15</sup> (RWW) V <sub>DDF</sub> <sup>15</sup> (Standby) V <sub>DDF</sub> <sup>15</sup> (Disabled)	I <sub>DD</sub> I <sub>DDSTBY</sub> I <sub>DDSTBY6</sub> I <sub>DDFPE</sub> I <sub>DDFREAD</sub> I <sub>DDFRWW</sub> I <sub>DDpTANDBY</sub> I <sub>DDFDISABLED</sub>	— — — — — — — —	1.0 <sup>16</sup> 0.10 0.15 36 <sup>17</sup> 50 <sup>17</sup> 90 <sup>17</sup> 0.20 <sup>17</sup> 0.10 <sup>17</sup>	A mA mA mA mA mA mA mA
25	Operating Current 3.3 V Supplies @ f <sub>sys</sub> = 180 MHz V <sub>DD33</sub> <sup>18</sup> V <sub>DDSYN</sub> <sup>19</sup> (P/E) V <sub>FLASH</sub> <sup>19</sup> (Read) V <sub>FLASH</sub> <sup>19</sup> (RWW) V <sub>FLASH</sub> <sup>19</sup> (Standby) V <sub>FLASH</sub> <sup>19</sup> (Disabled)	I <sub>DD33</sub> I <sub>DDSYN</sub> I <sub>DDFLASHPE</sub> I <sub>DDFLASHREADS</sub> I <sub>DDFLASHRWW</sub> I <sub>DDFLASHSTANDBY</sub> I <sub>DDFLASHDISABLED</sub>	— — — — — — —	note <sup>18</sup> 7 <sup>20</sup> 32 <sup>21</sup> 6.4 <sup>21</sup> 40 <sup>21</sup> 3.4 <sup>21</sup> 0.10 <sup>21</sup>	mA mA mA mA mA mA mA
26	Operating Current 5.0 V Supplies @ f <sub>sys</sub> = 180 MHz V <sub>DDA</sub> Analog Reference Supply Current (Transient) V <sub>DDREG</sub>	I <sub>DDA</sub> I <sub>REF</sub> I <sub>REG</sub>	— — —	50 <sup>22</sup> 1.0 22	mA mA mA

Table 13. DC Electrical Specifications<sup>1</sup> (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
27	Operating Current $V_{DDE}/V_{DDEH}$ <sup>23</sup> Supplies $V_{DDE2}$ $V_{DDEH1}$ $V_{DDEH3}$ $V_{DDEH4}$ $V_{DDEH5}$ $V_{DDEH6}$ $V_{DDEH7}$	$I_{DD2}$ $I_{DD1}$ $I_{DD3}$ $I_{DD4}$ $I_{DD5}$ $I_{DD6}$ $I_{DD7}$	— — — — — — —	note <sup>23</sup>	mA mA mA mA mA mA mA
28	Fast I/O Weak Pull Up/Down Current <sup>24</sup> 3.0 V–3.6 V	$I_{ACT\_F}$	42	158	$\mu A$
29	Medium I/O Weak Pull Up/Down Current <sup>25</sup> 3.0 V–3.6 V 4.5 V–5.5 V	$I_{ACT\_S}$	15 35	95 200	$\mu A$ $\mu A$
30	I/O Input Leakage Current <sup>26</sup>	$I_{INACT\_D}$	-2.5	2.5	$\mu A$
31	DC Injection Current (per pin)	$I_{IC}$	-1.0	1.0	mA
32	Analog Input Current, Channel Off <sup>27</sup> , AN[0:7], AN38, AN39 Analog Input Current, Channel Off, all other analog inputs AN[x] = -/+ 150nA	$I_{INACT\_A}$	-250 -150	250 150	nA nA
33	$V_{SS}$ Differential Voltage	$V_{SS} - V_{SSA}$	-100	100	mV
34	Analog Reference Low Voltage	$V_{RL}$	$V_{SSA}$	$V_{SSA} + 100$	mV
35	$V_{RL}$ Differential Voltage	$V_{RL} - V_{SSA}$	-100	100	mV
36	Analog Reference High Voltage	$V_{RH}$	$V_{DDA} - 100$	$V_{DDA}$	mV
37	$V_{REF}$ Differential Voltage	$V_{RH} - V_{RL}$	4.75	5.25	V
38	$V_{SSSYN}$ to $V_{SS}$ Differential Voltage	$V_{SSSYN} - V_{SS}$	-100	100	mV
39	Operating Temperature Range—Ambient (Packaged)	$T_A$ ( $T_L$ to $T_H$ )	-40.0	125.0	°C
40	Slew rate on power supply pins	—	—	25	V/ms
41	Weak Pull-Up/Down Resistance <sup>28,29</sup> 200 kΩ Option	$R_{PUPD200K}$	130	280	kΩ
42	Weak Pull-Up/Down Resistance <sup>28,29</sup> 100 kΩ Option	$R_{PUPD100K}$	65	140	kΩ
43	Weak Pull-Up/Down Resistance <sup>28</sup> (5 kΩ Option) 5 V ± 10% supply 3.3 V ± 10% supply	$R_{PUPD5K}$	1.4 1.7	5.2 7.7	kΩ
44	Pull-Up/Down Resistance Matching Ratios (100K/200K) (Pull-up and pull-down resistances both enabled and settings are equal)	$R_{PUPDMATCH}$	-2.5	2.5	%

<sup>1</sup> These specifications are design targets and subject to change per device characterization.<sup>2</sup> Voltage overshoots during a high-to-low or low-to-high transition must not exceed 10 seconds per instance.<sup>3</sup> 2.0 V for 10 hours cumulative time, 1.2 V +10% for time remaining.

## Electrical Characteristics

- <sup>4</sup> Assumed with DC load.
- <sup>5</sup>  $V_{STBY}$  below 0.95 V the RAM will not retain states, but will be operational.  $V_{STBY}$  can be 0 V when bypass standby mode.
- <sup>6</sup> Regulator is functional with derated performance, with supply voltage down to 4.0 V for system with  $V_{DDREG} = 4.5$  V (min).
- <sup>7</sup> 2.7 V minimum operating voltage allowed during vehicle crank for system with  $V_{DDREG} = 3.0$  V (min). Normal operating voltage should be either  $V_{DDREG} = 3.0$  V (min) or 4.5 V (min) depending on the user regulation voltage system selected.
- <sup>8</sup> Required to be supplied when 3.3 V regulator is disabled. See [Section 4.5, “PMC/POR/LVI Electrical Specifications.”](#)
- <sup>9</sup>  $I_{OH\_F} = \{12, 20, 30, 40\}$  mA and  $I_{OL\_F} = \{24, 40, 50, 65\}$  mA for {00, 01, 10, 11} drive mode with  $V_{DDE} = 3.0$  V.
- <sup>10</sup>  $I_{OH\_S} = \{11.6\}$  mA and  $I_{OL\_S} = \{17.7\}$  mA for {medium} I/O with  $V_{DDEH} = 4.5$  V;  
 $I_{OH\_S} = \{5.4\}$  mA and  $I_{OL\_S} = \{8.1\}$  mA for {medium} I/O with  $V_{DDEH} = 3.0$  V
- <sup>11</sup>  $I_{OL\_S} = 2$  mA
- <sup>12</sup> Applies to D\_CLKOUT, external bus pins, and Nexus pins.
- <sup>13</sup> Applies to the FCK, SDI, SDO, and SDS\_B pins.
- <sup>14</sup>  $V_{STBY}$  current specified at 1.0 V at a junction temperature of 85 °C.  $V_{STBY}$  current is 700 µA maximum at a junction temperature of 150 °C.
- <sup>15</sup> VDD pin is shorted to  $V_{DD}$  on the package substrate.
- <sup>16</sup> Preliminary. Specification pending typical and/or high-use Runidd pattern simulation as well as final silicon characterization. 1.0 A based on transistor count estimate at Worst Case (wcs) process and temperature condition.
- <sup>17</sup> Typical values from the simulation.
- <sup>18</sup> Power requirements for the  $V_{DD33}$  supply depend on the frequency of operation and load of all I/O pins, and the voltages on the I/O segments. See [Section 4.7.2, “I/O Pad  \$V\_{DD33}\$  Current Specifications,”](#) for information on both fast (F, FS) and medium (MH) pads. Also refer to [Table 15](#) for values to calculate power dissipation for specific operation.
- <sup>19</sup> VFLSH pin is shorted to  $V_{DD33}$  on the package substrate.
- <sup>20</sup> This value is a target that is subject to change.
- <sup>21</sup> Typical values from the simulation.
- <sup>22</sup> These value allows a 5 V 20 mA reference to supply ADC + REF.
- <sup>23</sup> Power requirements for each I/O segment depend on the frequency of operation and load of the I/O pins on a particular I/O segment, and the voltage of the I/O segment. See [Section 4.7.1, “I/O Pad Current Specifications,”](#) for information on I/O pad power. Also refer to [Table 14](#) for values to calculate power dissipation for specific operation. The total power consumption of an I/O segment is the sum of the individual power consumptions for each pin on the segment.
- <sup>24</sup> Absolute value of current, measured at  $V_{IL}$  and  $V_{IH}$ .
- <sup>25</sup> Absolute value of current, measured at  $V_{IL}$  and  $V_{IH}$ .
- <sup>26</sup> Weak pull up/down inactive. Measured at  $V_{DDE} = 3.6$  V and  $V_{DDEH} = 5.25$  V. Applies to pad types F and MH.
- <sup>27</sup> Maximum leakage occurs at maximum operating temperature. Leakage current decreases by approximately one-half for each 8 to 12 °C, in the ambient temperature range of 50 to 125 °C. Applies to pad types AE and AE/up-down.
- <sup>28</sup> This programmable option applies only to eQADC differential input channels and is used for biasing and sensor diagnostics.
- <sup>29</sup> When the pull-up and pull-down of the same nominal 200 kΩ or 100 kΩ value are both enabled, assuming no interference from external devices, the resulting pad voltage will be  $0.5 * V_{DDEH} \pm 2.5\%$ .

### 4.7.1 I/O Pad Current Specifications

The power consumption of an I/O segment is dependent on the usage of the pins on a particular segment. The power consumption is the sum of all output pin currents for a particular segment. The output pin current can be calculated from [Table 14](#) based on the voltage, frequency, and load on the pin. Use linear scaling to calculate pin currents for voltage, frequency, and load parameters that fall outside the values given in [Table 14](#).

The AC timing of these pads are described in the [Section 4.11.2, “Pad AC Specifications.”](#)

**Table 14.  $V_{DDE}/V_{DDEH}$  I/O Pad Average DC Current<sup>1</sup>**

Spec	Pad Type	Symbol	Frequency (MHz)	Load <sup>2</sup> (pF)	Voltage (V)	Drive/Slew Rate Select	Current (mA)
1	Medium	$I_{DRV\_MH}$	50	50	5.25	11	16.0
2			20	50	5.25	01	6.3
3			3.0	50	5.25	00	1.1
4			2.0	200	5.25	00	2.4
5	Fast	$I_{DRV\_FC}$	66	10	3.6	00	6.5
6			66	20	3.6	01	9.4
7			66	30	3.6	10	10.8
8			66	50	3.6	11	33.3
9			66	10	1.98	00	2.0
10			66	20	1.98	01	3.0
11			66	30	1.98	10	4.4
12			66	50	1.98	11	15.1
13	Fast w/ Slew Control	$I_{DRV\_FSR}$	66	50	3.6	11	12.0
14			50	50	3.6	10	6.2
15			33.33	50	3.6	01	4.0
16			20	50	3.6	00	2.4
17			20	200	3.6	00	8.9

<sup>1</sup> These are average IDDE numbers for worst case PVT from simulation. Currents apply to output pins only.

<sup>2</sup> All loads are lumped.

## 4.7.2 I/O Pad $V_{DD33}$ Current Specifications

The power consumption of the  $V_{DD33}$  supply is dependent on the usage of the pins on all I/O segments. The power consumption is the sum of all input and output pin  $V_{DD33}$  currents for all I/O segments. The  $V_{DD33}$  current draw on fast speed pads can be calculated from [Table 15](#) dependent on the voltage, frequency, and load on all F type pins. The  $V_{DD33}$  current draw on medium pads can be calculated from [Table 15](#) dependent on voltage and independent on the frequency and load on all MH type pins. Use linear scaling to calculate pin currents for voltage, frequency, and load parameters that fall outside the values given in [Table 15](#).

The AC timing of these pads are described in the [Section 4.11.2, “Pad AC Specifications.”](#)

## Electrical Characteristics

Table 15. V<sub>DD33</sub> Pad Average DC Current<sup>1</sup>

Spec	Pad Type	Symbol	Frequency (MHz)	Load <sup>2</sup> (pF)	V <sub>DD33</sub> (V)	V <sub>DDE</sub> (V)	Drive/Slew Rate Select	Current (mA)
1	Medium	I <sub>33_MH</sub>	—	—	3.6	5.5	—	0.0007
2	Fast	I <sub>33_FC</sub>	66	10	3.6	3.6	00	0.92
3			66	20	3.6	3.6	01	1.14
4			66	30	3.6	3.6	10	1.50
5			66	50	3.6	3.6	11	2.19
6			66	10	3.6	1.98	00	0.70
7			66	20	3.6	1.98	01	0.90
8			66	30	3.6	1.98	10	1.08
9			66	50	3.6	1.98	11	1.52
10	Fast w/ Slew Control	I <sub>33_FSR</sub>	66	50	3.6	3.6	11	0.74
11			50	50	3.6	3.6	10	0.52
12			33.33	50	3.6	3.6	01	0.36
13			20	50	3.6	3.6	00	0.19
14			20	200	3.6	3.6	00	0.19

<sup>1</sup> These are average IDD33 for worst case PVT from simulation. Currents apply to output pins only for the fast pads and to input pins only for the medium pads.

<sup>2</sup> All loads are lumped.

### 4.7.3 LVDS Pad Specifications

LVDS pads are implemented to support the MSC (Microsecond Channel) protocol, which is an enhanced feature of the DSPI module.

Table 16. DSPI LVDS Pad Specification <sup>1, 2</sup>  
(V<sub>DD33</sub> = 3.0 V to 3.6 V, V<sub>DDEH</sub> = 4.75 V to 5.25 V, T<sub>A</sub> = T<sub>L</sub> to T<sub>H</sub>)

Spec	Characteristic	Symbol	Min	Typical	Max	Unit
<b>Data Rate</b>						
1	Data Frequency	f <sub>LVDSCLK</sub>	—	—	40	MHz
<b>Driver Specs</b>						
2	Differential Output Voltage SRC=0b00 or 0b11 SRC=0b01 SRC=0b10	V <sub>OD</sub>	215 170 260	—	400 320 480	mV
3	Common Mode Voltage (LVDS), V <sub>OS</sub>	V <sub>OS</sub>	1.075	1.2	1.325	V
4	Rise/Fall Time	t <sub>R</sub> or t <sub>F</sub>	—	—	2.5	ns
5	Delay, Z to Normal (High/Low)	t <sub>DZ</sub>	—	—	100	ns

**Table 16. DSPI LVDS Pad Specification<sup>1, 2</sup> (continued)**  
 $(V_{DD33} = 3.0 \text{ V to } 3.6 \text{ V}, V_{DDEH} = 4.75 \text{ V to } 5.25 \text{ V}, T_A = T_L \text{ to } T_H)$

6	Differential Skew between Positive and Negative LVDS Pair $ t_{phla} - t_{plhb} $ or $ t_{plhb} - t_{phla} $	$t_{Skew}$	—	—	0.5	ns
<b>Termination</b>						
7	Termination Resistance <sup>3</sup>	$R_{Load}$	95	100	105	ohm
8	Load	—	—	—	32	pF

<sup>1</sup> These are typical values that are estimated from simulation.

<sup>2</sup> These specifications are subject to change per device characterization.

<sup>3</sup> The termination resistance spec is not meant to specify the receiver termination requirements. They are there to establish the measurement criteria for the specs in this table. As per the TIA/EIA-644A standard, the LVDS receiver termination resistance can vary from 90 to 132  $\Omega$ .

## 4.8 Oscillator and FMPLL Electrical Characteristics

**Table 17. FMPLL Electrical Specifications<sup>1</sup>**

$(V_{DDSYN} = 3.0 \text{ V to } 3.6 \text{ V}, V_{SS} = V_{SSSYN} = 0 \text{ V}, T_A = T_L \text{ to } T_H)$

Spec	Characteristic	Symbol	Min	Max	Unit
1	PLL Reference Frequency Range <sup>2</sup> (Normal Mode) Crystal Reference (PLLCFG2 = 0b0) Crystal Reference (PLLCFG2 = 0b1) External Reference (PLLCFG2 = 0b0) External Reference(PLLCFG2 = 0b1)	$f_{ref\_crystal}$ $f_{ref\_crystal}$ $f_{ref\_ext}$ $f_{ref\_ext}$	8 40 8 40	20 40 <sup>3</sup> 20 40	MHz
2	PLL Frequency <sup>4</sup> Enhanced Mode	$f_{PLL}$	$f_{vco(\min)} \div 64$	$f_{\max}$	MHz
3	Loss of Reference Frequency <sup>5</sup>	$f_{LOR}$	100	1000	kHz
4	Self Clocked Mode Frequency <sup>6</sup>	$f_{SCM}$	4	16	MHz
5	PLL Lock Time <sup>7</sup>	$t_{LPLL}$	—	<750	$\mu\text{s}$
6	Duty Cycle of Reference <sup>8, 9</sup>	$t_{DC}$	40	60	%
7	Frequency un-LOCK Range	$f_{UL}$	-4.0	4.0	$\% f_{sys}$
8	Frequency LOCK Range	$f_{LCK}$	-2.0	2.0	$\% f_{sys}$
9	D_CLKOUT Period Jitter <sup>10, 11</sup> Measured at $f_{SYS}$ Max Cycle-to-cycle Jitter	$C_{jitter}$	-5	5	$\% f_{clockout}$
10	Peak-to-Peak Frequency Modulation Range Limit <sup>12,13</sup> ( $f_{sys}$ Max must not be exceeded)	$C_{mod}$	0	4	$\% f_{sys}$
11	FM Depth Tolerance <sup>14</sup>	$C_{mod\_err}$	-0.25	0.25	$\% f_{sys}$
12	VCO Frequency	$f_{VCO}$	192	600	MHz
13	Modulation Rate Limits <sup>15</sup>	$f_{mod}$	0.400	1	MHz
14	Predivider Operating Frequency	$f_{prediv}$	4	10	MHz

## Electrical Characteristics

- <sup>1</sup> All values given are initial design targets and subject to change.
- <sup>2</sup> Crystal and External reference frequency limits depend on device relying on PLL to lock prior to release of reset, default PREDIV/EPREDIV, MFD/EMFD default settings, and VCO frequency range. Absolute minimum loop frequency is 4 MHz.
- <sup>3</sup> Upper tolerance of less than 1% is allowed on 40MHz crystal.
- <sup>4</sup> All internal registers retain data at 0 Hz.
- <sup>5</sup> “Loss of Reference Frequency” is the reference frequency detected internally, which transitions the PLL into self clocked mode.
- <sup>6</sup> Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls below  $f_{LOR}$ . This frequency is measured at D\_CLKOUT with the divider set to divide-by-2 of the system clock. NOTE: in SCM, the PLL is running open loop at a centercode 0x4. The MFD has no effect and the RFD is bypassed.
- <sup>7</sup> This specification applies to the period required for the PLL to re-lock after changing the MFD frequency control bits in the synthesizer control register (SYNCR). From power up with crystal oscillator reference, lock time will be additive with crystal startup time.
- <sup>8</sup> For FlexRay operation, duty cycle requirements are higher.
- <sup>9</sup> Duty cycle can be 20–80% when PLL is used with a pre-divider greater than 1.
- <sup>10</sup> Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum  $f_{sys}$ . Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via  $V_{DDSYN}$  and  $V_{SSSYN}$  and variation in crystal oscillator frequency increase the Cjitter percentage for a given interval. D\_CLKOUT divider set to divide-by-2.
- <sup>11</sup> Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of  $C_{jitter} + C_{mod}$ .
- <sup>12</sup> Modulation depth selected must not result in  $f_{PLL}$  value greater than the  $f_{PLL}$  maximum specified value.
- <sup>13</sup> Maximum and minimum variation from programmed modulation depth is pending characterization. Depth settings available in control register are: 1%, 2%, 3%, and 4% peak-to-peak.
- <sup>14</sup> Depth tolerance is the programmed modulation depth  $\pm 0.25\%$  of  $F_{sys}$ . Initial design target pending silicon evaluation.
- <sup>15</sup> Modulation rates less than 400 kHz will result in exceedingly long FM calibration durations. Modulation rates greater than 1 MHz will result in reduced calibration accuracy.

**Table 18. Oscillator Electrical Specifications<sup>1</sup>**

( $V_{DDSYN} = 3.0 \text{ V to } 3.6 \text{ V}$ ,  $V_{SS} = V_{SSSYN} = 0 \text{ V}$ ,  $T_A = T_L \text{ to } T_H$ )

Spec	Characteristic	Symbol	Min	Max	Unit
1	Crystal Mode Differential Amplitude <sup>2</sup> (Min differential voltage between EXTAL and XTAL)	$V_{crystal\_diff\_amp}$	$ V_{extal} - V_{xtal}  > 0.4 \text{ V}$	—	V
2	Crystal Mode: Internal Differential Amplifier Noise Rejection	$V_{crystal\_diff\_amp\_nr}$	—	$ V_{extal} - V_{xtal}  < 0.2 \text{ V}$	V
3	EXTAL Input High Voltage Bypass mode, External Reference	$V_{IHEXT}$	$((V_{DD33}/2) + 0.4 \text{ V})$	—	V
4	EXTAL Input Low Voltage Bypass mode, External Reference	$V_{ILEXT}$	—	$(V_{DD33}/2) - 0.4 \text{ V}$	V
5	XTAL Current <sup>3</sup>	$I_{XTAL}$	1	3	mA
6	Total On-chip stray capacitance on XTAL	$C_{S\_XTAL}$	—	1.5	pF

**Table 18. Oscillator Electrical Specifications<sup>1</sup> (continued)**  
 $(V_{DDSYN} = 3.0 \text{ V to } 3.6 \text{ V}, V_{SS} = V_{SSSYN} = 0 \text{ V}, T_A = T_L \text{ to } T_H)$

Spec	Characteristic	Symbol	Min	Max	Unit
7	Total On-chip stray capacitance on EXTAL	$C_{S\_EXTAL}$	—	1.5	pF
8	Crystal manufacturer's recommended capacitive load	$C_L$	See crystal spec	See crystal spec	pF
9	Discrete load capacitance to be connected to EXTAL	$C_{L\_EXTAL}$	—	$(2 \times C_L - C_{S\_EXTAL})^{\frac{1}{4}}$	pF
10	Discrete load capacitance to be connected to XTAL	$C_{L\_XTAL}$	—	$(2 \times C_L - C_{S\_XTAL})^{\frac{1}{4}}$	pF

<sup>1</sup> All values given are initial design targets and subject to change.

<sup>2</sup> This parameter is meant for those who do not use quartz crystals or resonators, but instead use CAN oscillators in crystal mode. In that case,  $V_{extal} - V_{xtal} \geq 400 \text{ mV}$  criterion has to be met for oscillator's comparator to produce output clock.

<sup>3</sup>  $I_{xtal}$  is the oscillator bias current out of the XTAL pin with both EXTAL and XTAL pins grounded.

<sup>4</sup>  $C_{PCB\_EXTAL}$  and  $C_{PCB\_XTAL}$  are the measured PCB stray capacitances on EXTAL and XTAL, respectively.

## 4.9 eQADC Electrical Characteristics

**Table 19. eQADC Conversion Specifications (Operating)**

Spec	Characteristic	Symbol	Min	Max	Unit
1	ADC Clock (ADCLK) Frequency	$f_{ADCLK}$	2	16	MHz
2	Conversion Cycles	CC	$2 + 13$	$128 + 14$	ADCLK cycles
3	Stop Mode Recovery Time <sup>1</sup>	$T_{SR}$	10	—	$\mu\text{s}$
4	Resolution <sup>2</sup>	—	1.25	—	mV
5	INL: 8 MHz ADC Clock <sup>3</sup>	INL8	$-4^4$	$4^4$	LSB <sup>5</sup>
6	INL: 16 MHz ADC Clock <sup>3</sup>	INL16	$-8^4$	$8^4$	LSB
7	DNL: 8 MHz ADC Clock <sup>3</sup>	DNL8	$-3^4$	$3^4$	LSB
8	DNL: 16 MHz ADC Clock <sup>3</sup>	DNL16	$-3^4$	$3^4$	LSB
9	Offset Error without Calibration	OFFNC	$0^4$	$100^4$	LSB
10	Offset Error with Calibration	OFFWC	$-4^4$	$4^4$	LSB
11	Full Scale Gain Error without Calibration	GAINNC	$-120^4$	$0^4$	LSB
12	Full Scale Gain Error with Calibration	GAINWC	$-4^{4,6}$	$4^{4,6}$	LSB
13	Disruptive Input Injection Current <sup>7, 8, 9, 10</sup>	$I_{INJ}$	-1	1	mA
14	Incremental Error due to injection current <sup>11, 12</sup>	$E_{INJ}$	—	$\pm 4^4$	Counts
15	TUE value at 8 MHz <sup>13, 14</sup> (with calibration)	TUE8	—	$\pm 4^{4,6}$	Counts

## Electrical Characteristics

Table 19. eQADC Conversion Specifications (Operating) (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
16	TUE value at 16 MHz <sup>13, 14</sup> (with calibration)	TUE16	—	±8	Counts
17	Variable gain amplifier accuracy (gain=1) <sup>15</sup> INL, 8 MHz ADC INL, 16 MHz ADC DNL, 8 MHz ADC DNL, 16 MHz ADC	GAINVGA1	-4 -8 -3 <sup>16</sup> -3 <sup>16</sup>	4 8 3 <sup>16</sup> 3 <sup>16</sup>	Counts <sup>17</sup>
18	Variable gain amplifier accuracy (gain=2) <sup>15</sup> INL, 8 MHz ADC INL, 16 MHz ADC DNL, 8 MHz ADC DNL, 16 MHz ADC	GAINVGA2	-5 -8 -3 -3	5 8 3 3	Counts
19	Variable gain amplifier accuracy (gain=4) <sup>15</sup> INL, 8 MHz ADC INL, 16 MHz ADC DNL, 8 MHz ADC DNL, 16 MHz ADC	GAINVGA4	-7 -8 -4 -4	7 8 4 4	Counts

<sup>1</sup> Stop mode recovery time is the time from the setting of either of the enable bits in the ADC Control Register to the time that the ADC is ready to perform conversions. Delay from power up to full accuracy = 8 ms.

<sup>2</sup> At  $V_{RH} - V_{RL} = 5.12$  V, one count = 1.25 mV without using pregain.

<sup>3</sup> INL and DNL are tested from  $V_{RL} + 50$  LSB to  $V_{RH} - 50$  LSB.

<sup>4</sup> New design target. Actual specification will change following characterization. Margin for manufacturing has not been fully included.

<sup>5</sup> At  $V_{RH} - V_{RL} = 5.12$  V, one LSB = 1.25 mV.

<sup>6</sup> The value is valid at 8 MHz, it is ±8 counts at 16 MHz.

<sup>7</sup> Below disruptive current conditions, the channel being stressed has conversion values of \$3FF for analog inputs greater than  $V_{RH}$  and \$000 for values less than  $V_{RL}$ . Other channels are not affected by non-disruptive conditions.

<sup>8</sup> Exceeding limit may cause conversion error on stressed channels and on unstressed channels. Transitions within the limit do not affect device reliability or cause permanent damage.

<sup>9</sup> Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values using  $V_{POSCLAMP} = V_{DDA} + 0.5$  V and  $V_{NEGCLAMP} = -0.3$  V, then use the larger of the calculated values.

<sup>10</sup> Condition applies to two adjacent pins at injection limits.

<sup>11</sup> Performance expected with production silicon.

<sup>12</sup> All channels have same  $10\text{ k}\Omega < R_s < 100\text{ k}\Omega$ . Channel under test has  $R_s = 10\text{ k}\Omega$ ,  $I_{INJ} = I_{INJMAX}, I_{INJMIN}$ .

<sup>13</sup> The TUE specification is always less than the sum of the INL, DNL, offset, and gain errors due to cancelling errors.

<sup>14</sup> TUE does not apply to differential conversions.

<sup>15</sup> Variable gain is controlled by setting the PRE\_GAIN bits in the ADC\_ACR1-8 registers to select a gain factor of ×1, ×2, or ×4. Settings are for differential input only. Tested at ×1 gain. Values for other settings are guaranteed by as indicated.

<sup>16</sup> Guaranteed 10-bit mono tonicity.

<sup>17</sup> At  $V_{RH} - V_{RL} = 5.12$  V, one LSB = 1.25 mV.

## 4.9.1 ADC Internal Resource Measurements

**Table 20. Power Management Control (PMC) Specification**

Spec	Characteristic	Symbol	Min	Typical	Max	Unit
<b>PMC Normal Mode</b>						
1	Bandgap 0.62 V ADC0 channel 145	$V_{ADC145}$	0.59	0.62	0.65	V
2	Bandgap 1.2 V ADC0 channel 146	$V_{ADC146}$	1.10	1.22	1.34	V
3	Vreg1p2 Feedback ADC0 channel 147	$V_{ADC147}$	$V_{DD}/2.147$	$V_{DD} / 2.045$	$V_{DD}/1.943$	V
4	LVD 1.2 V ADC0 channel 180	$V_{ADC180}$	$V_{DD}/1.863$	$V_{DD} / 1.774$	$V_{DD}/1.685$	V
5	Vreg3p3 Feedback ADC0 channel 181	$V_{ADC181}$	Vreg3p3 / 5.733—	Vreg3p3 / 5.460	Vreg3p3 / 5.187	V
6	LVD 3.3 V ADC0 channel 182	$V_{ADC182}$	Vreg3p3 / 4.996	Vreg3p3 / 4.758	Vreg3p3 / 4.520	V
7	LVD 5.0 V ADC0 channel 183 — LDO mode — SMPS mode	$V_{ADC183}$	$V_{DDREG} / 4.996$ $V_{DDREG} / 7.384$	$V_{DDREG} / 4.758$ $V_{DDREG}/7.032$	$V_{DDREG} / 4.520$ $V_{DDREG} / 6.680$	V

**Table 21. Standby RAM Regulator Electrical Specifications**

Spec	Characteristic	Symbol	Min	Typ	Max	Unit
<b>Normal Mode</b>						
1	Standby Regulator Output ADC1 channel 194	$V_{ADC194}$	—	1.2	—	V
2	Standby Source Bias ADC1 channel 195	$V_{ADC195}$	150	—	360	mV

**Table 22. ADC Band Gap Reference / LVI Electrical Specifications**

Spec	Characteristic	Symbol	Min	Typ	Max	Unit
1	4.75 LVD (from $V_{DDA}$ ) ADC1 channel 196	$V_{ADC196}$	—	4.75	—	V
2	ADC Bandgap ADC0 channel 45 ADC1 channel 45	$V_{ADC45}$	—	1.220	—	V

## Electrical Characteristics

**Table 23. Temperature Sensor Electrical Specifications**

Spec	Characteristic	Symbol	Min	Typ	Max	Unit
1	Slope –40 °C to 100 °C $\pm 1.0$ °C 100 °C to 150 °C $\pm 1.6$ °C ADC0 channel 128 ADC1 channel 128	$V_{SADC128}$ <sup>1</sup>	—	5.8	—	mV/ °C
2	Accuracy –40 °C to 150 °C ADC0 channel 128 ADC1 channel 128	—	-20	—	+20	°C

<sup>1</sup> Slope is the measured voltage change per °C.

**4.10 C90 Flash Memory Electrical Characteristics****Table 24. Flash Program and Erase Specifications (Pending Si characterization)**

Spec	Characteristic	Symbol	Typ <sup>1</sup>	Initial Max <sup>2</sup>	Lifetime Max <sup>3</sup>	Unit
1	Double Word (64 bits) Program Time <sup>4</sup>	$t_{dwprogram}$	38	—	500	μs
2	Page (128 bits) Program Time <sup>4</sup>	$t_{pprogram}$	45	160	500	μs
3	16 KB Block Pre-program and Erase Time	$t_{16kpperase}$	270	1000	5000	ms
4	48 KB Block Pre-program and Erase Time	$t_{48kpperase}$	625	1500	5000	ms
5	64 KB Block Pre-program and Erase Time	$t_{64kpperase}$	800	1800	5000	ms
6	128 KB Block Pre-program and Erase Time	$t_{128kpperase}$	1500	2600	7500	ms
7	256 KB Block Pre-program and Erase Time	$t_{256kpperase}$	3000	5200	15000	ms

<sup>1</sup> Typical program and erase times represent the median performance and assume nominal supply values and operation at 25 °C. These values are characterized, but not tested.

<sup>2</sup> Initial Max program and erase times provide guidance for time-out limits used in the factory and apply for < 100 program/erase cycles, nominal supply values and operation at 25 °C. These values are verified at production test.

<sup>3</sup> Lifetime Max program and erase times apply across the voltage, temperature, and cycling range of product life. These values are characterized, but not tested.

<sup>4</sup> Program times are actual hardware programming times and do not include software overhead.

**NOTE**

The low, mid, and high address blocks of the flash arrays are erased (all bits set to 1) before leaving the factory.

**Table 25. Flash Memory AC Timing Specifications<sup>1</sup>**

Symbol	Parameter	Value			Unit
		Min	Typ	Max	
T <sub>RES</sub>	Time from clearing the MCR-ESUS or PSUS bit with EHV = 1 until DONE goes low	—	—	100	ns
T <sub>DONE</sub>	Time from 0 to 1 transition on the MCR-EHV bit initiating a program/erase until the MCR-DONE bit is cleared	—	—	5	ns
T <sub>PSRT</sub>	Time between program suspend resume and the next program suspend request. <sup>2</sup>	100	—	—	μ s
T <sub>ESRT</sub>	Time between erase suspend resume and the next erase suspend request. <sup>3</sup>	10	—	—	ms

<sup>1</sup> This parameter is guaranteed by characterization before qualification rather than 100% tested.

<sup>2</sup> Repeated suspends at a high frequency may result in the operation timing out, and the flash module will respond by completing the operation with a fail code (MCR[PEG] = 0), or the operation not able to finish (MCR[DONE] = 1 during Program operation). The minimum time between suspends to ensure this does not occur is T<sub>PSRT</sub>.

<sup>3</sup> If Erase suspend rate is less than T<sub>ESRT</sub>, an increase of slope voltage ramp occurs during erase pulse. This improves erase time but reduces cycling figure due to overstress.

**Table 26. Flash EEPROM Module Life**

Spec	Characteristic	Symbol	Min	Typical <sup>1</sup>	Unit
1	Number of Program/Erase cycles per block for 16 KB and 64 KB blocks over the operating temperature range (T <sub>J</sub> )	P/E	100,000	—	cycles
2	Number of Program/Erase cycles per block for 128 KB and 256 KB blocks over the operating temperature range (T <sub>J</sub> )	P/E	1,000	100,000	cycles
3	Minimum Data Retention at 85 °C ambient temperature <sup>2</sup> Blocks with 0–1,000 P/E cycles Blocks with 1,001–10,000 P/E cycles Blocks with 10,001–100,000 P/E cycles	Retention	20 10 1 – 5	—	years

<sup>1</sup> Typical endurance is evaluated at 25 °C. Product qualification is performed to the minimum specification. For additional information on the NXP definition of Typical Endurance, please refer to Engineering Bulletin EB619, *Typical Endurance for Nonvolatile Memory*.

<sup>2</sup> Ambient temperature averaged over duration of application, not to exceed product operating temperature range.

**Table 27. BIUCR1/BIUCR3 Settings**

Spec	Maximum Frequency (MHz)		APC = RWSC	WWSC	DPFEN <sup>1</sup>	IPFEN <sup>1</sup>	PFLIM <sup>2</sup>	BFEN <sup>3</sup>
	Core f <sub>sys</sub>	Platform f <sub>platf</sub>						
1	180 MHz	90 MHz	0b010	0b01	0b0 0b1	0b0 0b1	0b00 0b01 0b1x	0b0 0b1
Default setting after reset:		0b111	0b11	0b00	0b00	0b00	0b0	0b0

<sup>1</sup> For maximum flash performance, set to 0b1.<sup>2</sup> For maximum flash performance, set to 0b10.<sup>3</sup> For maximum flash performance, set to 0b1.

## 4.11 AC Specifications

### 4.11.1 Clocking Modes

There are two main modes of operating frequency settings:

- Double 2:1 (Core:Platform) Mode—the core is running at the system frequency setting while the platform and eTPU are running at half the core frequency (system frequency divided by 2).
- eTPU Mode—the core and eTPU are running at the system frequency setting while the platform is running at half the core frequency (system frequency divided by 2).

Table 28 shows the operating frequencies of various blocks depending on the device's clocking mode configuration settings.

**Table 28. MPC5676R Block Operating Frequency<sup>1, 2</sup>**

Spec	Blocks	Symbol	Double Mode Freq (MHz)	eTPU Mode Freq (MHz)
1	Cores	f <sub>sys</sub> (t <sub>cycsys</sub> = 1/f <sub>sys</sub> )	f <sub>sys</sub> = 180	f <sub>sys</sub> = 180
2	Platform	f <sub>platf</sub> (t <sub>cyc</sub> = 1/f <sub>platf</sub> )	f <sub>sys</sub> / 2	f <sub>sys</sub> / 2
3	eTPU	f <sub>eTPU</sub>	f <sub>sys</sub> / 2	f <sub>sys</sub>
4	EBI	f <sub>ebi</sub>	f <sub>sys</sub> / 4	f <sub>sys</sub> / 4

<sup>1</sup> The values in the table are specified at V<sub>DD</sub> = 1.02 V to 1.32 V, V<sub>DDE</sub> = 3.0 V to 3.6 V, V<sub>DDEH</sub> = 4.5 V to 5.5 V, V<sub>DD33</sub> and V<sub>DDSYN</sub> = 3.0 V to 3.6 V, T<sub>A</sub> = T<sub>L</sub> to T<sub>H</sub>.

<sup>2</sup> Up to the maximum frequency rating of the device (refer to Table 1). The f<sub>sys</sub> speed is the nominal maximum frequency.

## 4.11.2 Pad AC Specifications

**Table 29. Pad AC Specifications ( $V_{DDEH} = 5.0$  V,  $V_{DDE} = 3.3$  V)<sup>1</sup>**

Spec	Pad	SRC/DSC	Out Delay <sup>2,4</sup> $L \rightarrow H/H \rightarrow L$ (ns)	Rise/Fall <sup>3,4</sup> (ns)	Load Drive (pF)
1	Medium <sup>5</sup>	00	152/165	70/74	50
2			205/220	96/96	200
3		01	28/34	12/15	50
4			52/59	28/31	200
5		11	12/12	5.3/5.9	50
6			32/32	22/22	200
7	Fast <sup>6</sup>	00	2.5	1.2	10
8		01			20
9		10			30
10		11			50
11	Fast with Slew Rate	00	40/40	16/16	50
12			50/50	21/21	200
13		01	13/13	5/5	50
14			19/19	8/8	200
15		10	8/8	2.4/2.4	50
16			12/12	5/5	200
17		11	5/5	1.1/1/1	50
18			8/8	2.6	200
19	Pull Up/Down (3.6 V max)	—	—	7500	50
20	Pull Up/Down (5.25 V max)	—	6000	5000/5000	50

<sup>1</sup> These are worst case values that are estimated from simulation and not tested. The values in the table are simulated at  $V_{DD} = 1.02$  V to 1.32 V,  $V_{DDE} = 3.0$  V to 3.6 V,  $V_{DDEH} = 4.75$  V to 5.25 V,  $V_{DD33}$  and  $V_{DDSYN} = 3.0$  V to 3.6 V,  $T_A = T_L$  to  $T_H$ .

<sup>2</sup> This parameter is supplied for reference and is not guaranteed by design and not tested.

<sup>3</sup> This parameter is guaranteed by characterization before qualification rather than 100% tested.

<sup>4</sup> Delay and rise/fall are measured to 20% or 80% of the respective signal.

<sup>5</sup> Out delay is shown in [Figure 7](#). Add a maximum of one system clock to the output delay for delay with respect to system clock.

<sup>6</sup> Out delay is shown in [Figure 7](#). Add a maximum of one system clock to the output delay for delay with respect to system clock.

**Table 30. Derated Pad AC Specifications ( $V_{DDEH} = 3.3$  V)<sup>1</sup>**

Spec	Pad	SRC/DSC	Out Delay <sup>2,3</sup> $L \rightarrow H/H \rightarrow L$ (ns)	Rise/Fall <sup>4,3</sup> (ns)	Load Drive (pF)
1	Medium <sup>5</sup>	00	200/210	86/86	50
2			270/285	120/120	200
3		01	37/45	15.5/19	50
4			69/82	38/43	200
5		11	18/17	7.6/8.5	50
6			46/49	30/34	200

## Electrical Characteristics

- <sup>1</sup> These are worst case values that are estimated from simulation and not tested. The values in the table are simulated at  $V_{DD} = 1.08$  V to 1.32 V,  $V_{DDE} = 3.0$  V to 3.6 V,  $V_{DDEH} = 3.0$  V to 3.6 V,  $V_{DD33}$  and  $V_{DDSYN} = 3.0$  V to 3.6 V,  $T_A = T_L$  to  $T_H$ .
- <sup>2</sup> This parameter is supplied for reference and is not guaranteed by design and not tested.
- <sup>3</sup> Delay and rise/fall are measured to 20% or 80% of the respective signal.
- <sup>4</sup> This parameter is guaranteed by characterization before qualification rather than 100% tested.
- <sup>5</sup> Out delay is shown in [Figure 7](#). Add a maximum of one system clock to the output delay for delay with respect to system clock.

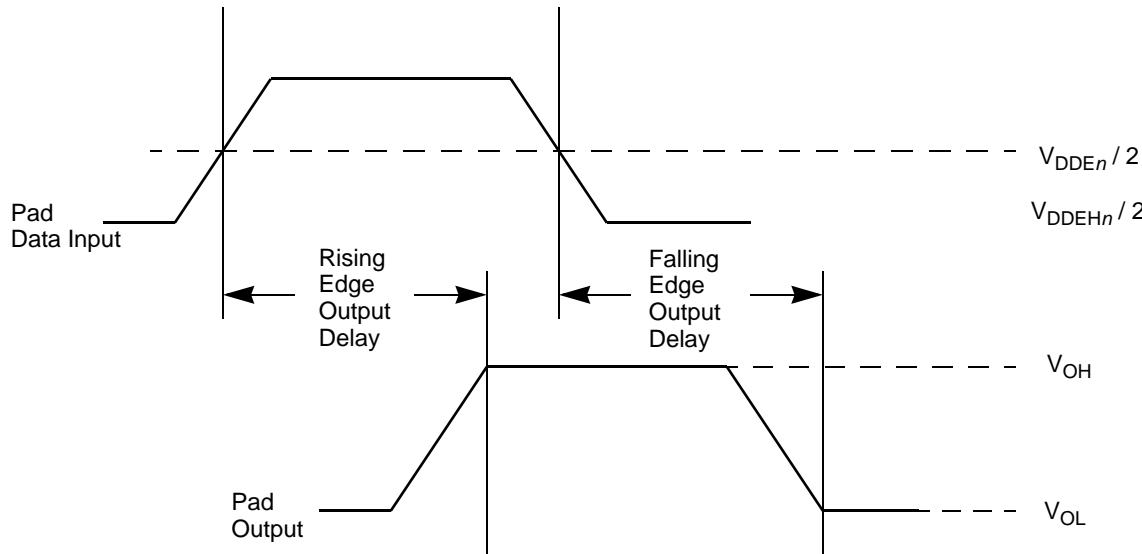


Figure 7. Pad Output Delay

## 4.12 AC Timing

### 4.12.1 Generic Timing Diagrams

The generic timing diagrams in [Figure 8](#) and [Figure 9](#) apply to all I/O pins with pad types F and MH. See [Table 39](#) for the pad type for each pin.

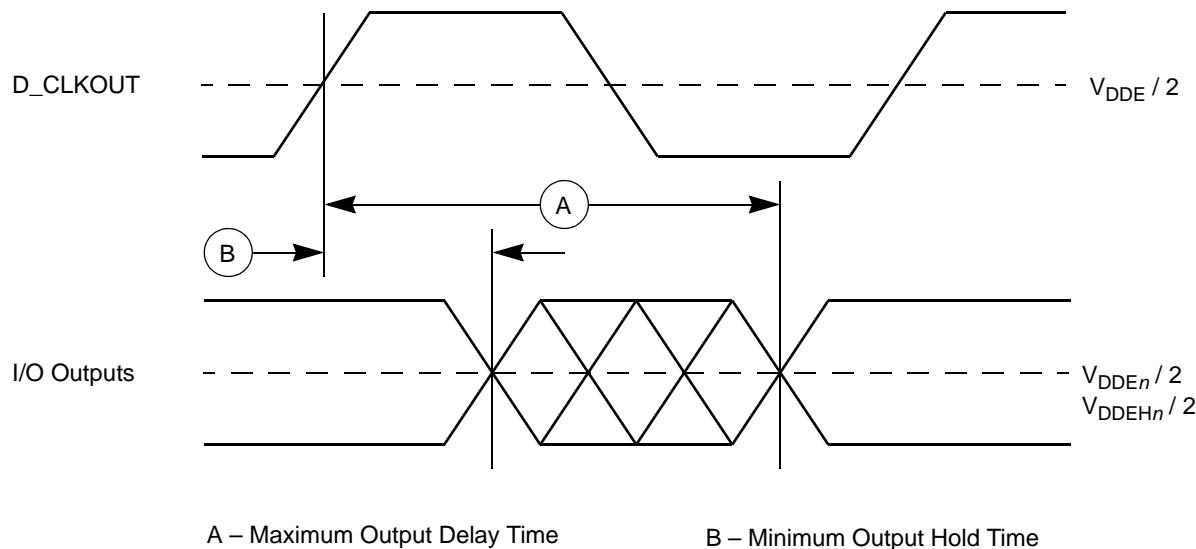


Figure 8. Generic Output Delay/Hold Timing

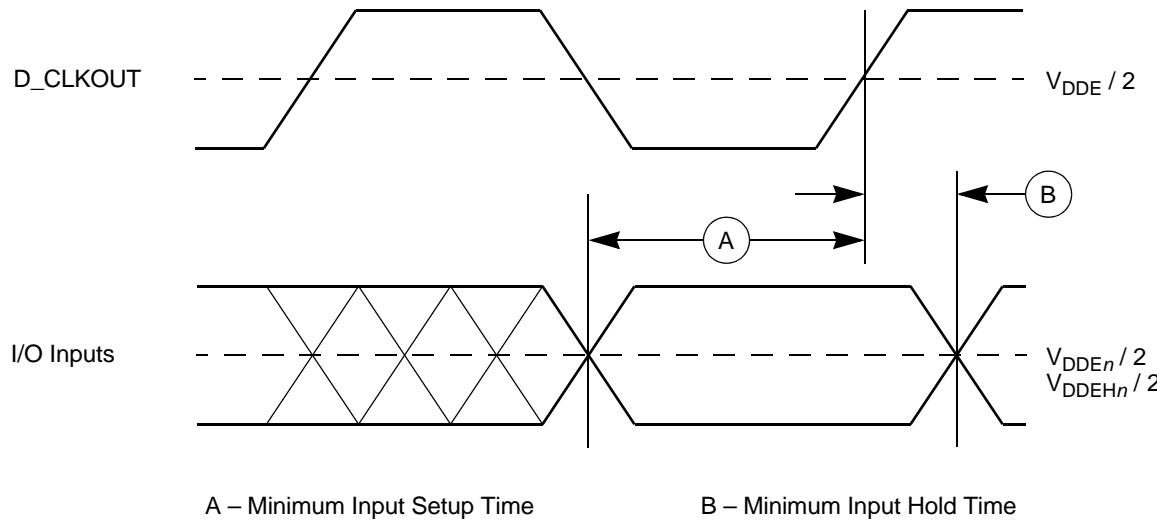


Figure 9. Generic Input Setup/Hold Timing

#### 4.12.2 Reset and Configuration Pin Timing

Table 31. Reset and Configuration Pin Timing<sup>1</sup>

Spec	Characteristic	Symbol	Min	Max	Unit
1	RESET Pulse Width	$t_{RPW}$	10	—	$t_{cyc}^2$
2	RESET Glitch Detect Pulse Width	$t_{GPW}$	2	—	$t_{cyc}^2$
3	PLLCFG, BOOTCFG, WKPCFG Setup Time to RSTOUT Valid	$t_{RCSU}$	10	—	$t_{cyc}^2$
4	PLLCFG, BOOTCFG, WKPCFG Hold Time to RSTOUT Valid	$t_{RCH}$	0	—	$t_{cyc}^2$

<sup>1</sup> Reset timing specified at:  $V_{DDEH} = 3.0 \text{ V to } 5.25 \text{ V}$ ,  $V_{DD} = 1.08 \text{ V to } 1.32 \text{ V}$ ,  $T_A = T_L$  to  $T_H$ .

## Electrical Characteristics

<sup>2</sup> See Notes on  $t_{cyc}$  on Table 28.

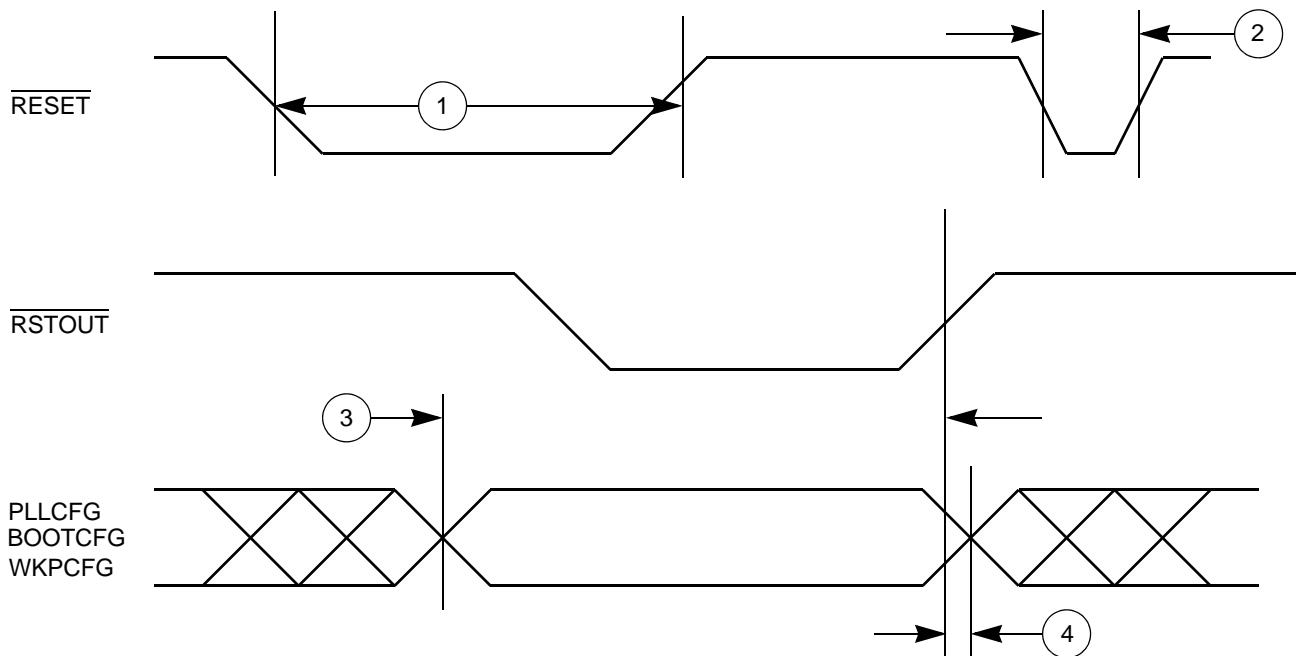


Figure 10. Reset and Configuration Pin Timing

#### 4.12.3 IEEE 1149.1 Interface Timing

Table 32. JTAG Pin AC Electrical Characteristics<sup>1</sup>

Spec	Characteristic	Symbol	Min	Max	Unit
1	TCK Cycle Time	$t_{JCYC}$	100	—	ns
2	TCK Clock Pulse Width (Measured at $V_{DDE} / 2$ )	$t_{JDC}$	40	60	ns
3	TCK Rise and Fall Times (40%–70%)	$t_{TCKRISE}$	—	3	ns
4	TMS, TDI Data Setup Time	$t_{TMSS}, t_{TDIS}$	5	—	ns
5	TMS, TDI Data Hold Time	$t_{TMSH}, t_{TDIH}$	25	—	ns
6	TCK Low to TDO Data Valid	$t_{TDOV}$	—	10	ns
7	TCK Low to TDO Data Invalid	$t_{TDOI}$	0	—	ns
8	TCK Low to TDO High Impedance	$t_{TDOHZ}$	—	20	ns
9	JCOMP Assertion Time	$t_{JCMPPW}$	100	—	ns
10	JCOMP Setup Time to TCK Low	$t_{JCMPS}$	40	—	ns
11	TCK Falling Edge to Output Valid	$t_{BSDV}$	—	50	ns

Table 32. JTAG Pin AC Electrical Characteristics<sup>1</sup> (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
12	TCK Falling Edge to Output Valid out of High Impedance	$t_{BSDVZ}$	—	50	ns
13	TCK Falling Edge to Output High Impedance	$t_{BSDHZ}$	—	50	ns
14	Boundary Scan Input Valid to TCK Rising Edge	$t_{BSDST}$	50	—	ns
15	TCK Rising Edge to Boundary Scan Input Invalid	$t_{BSDHT}$	50	—	ns

<sup>1</sup> JTAG timing specified at  $V_{DD} = 1.08$  V to 1.32 V,  $V_{DDE} = 3.0$  V to 3.6 V,  $V_{DD33}$  and  $V_{DDSYN} = 3.0$  V to 3.6 V,  $T_A = T_L$  to  $T_H$ , and  $C_L = 30$  pF with DSC = 0b10, SRC = 0b00. These specifications apply to JTAG boundary scan only. See [Table 33](#) for functional specifications.

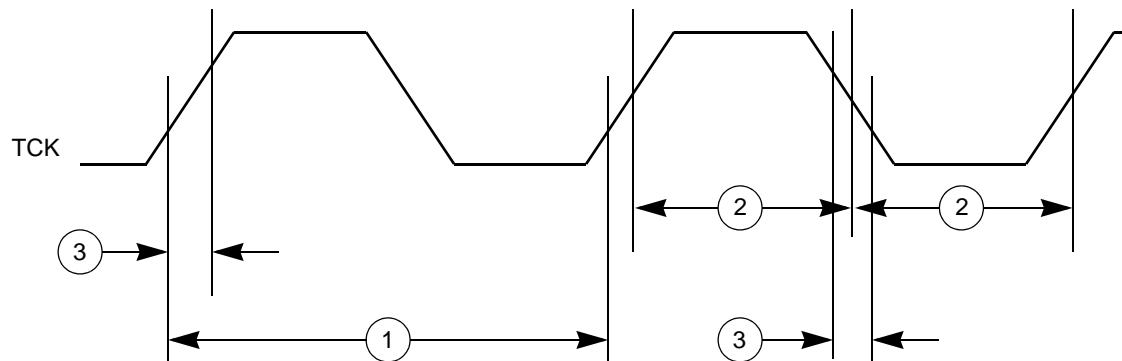


Figure 11. JTAG Test Clock Input Timing

## Electrical Characteristics

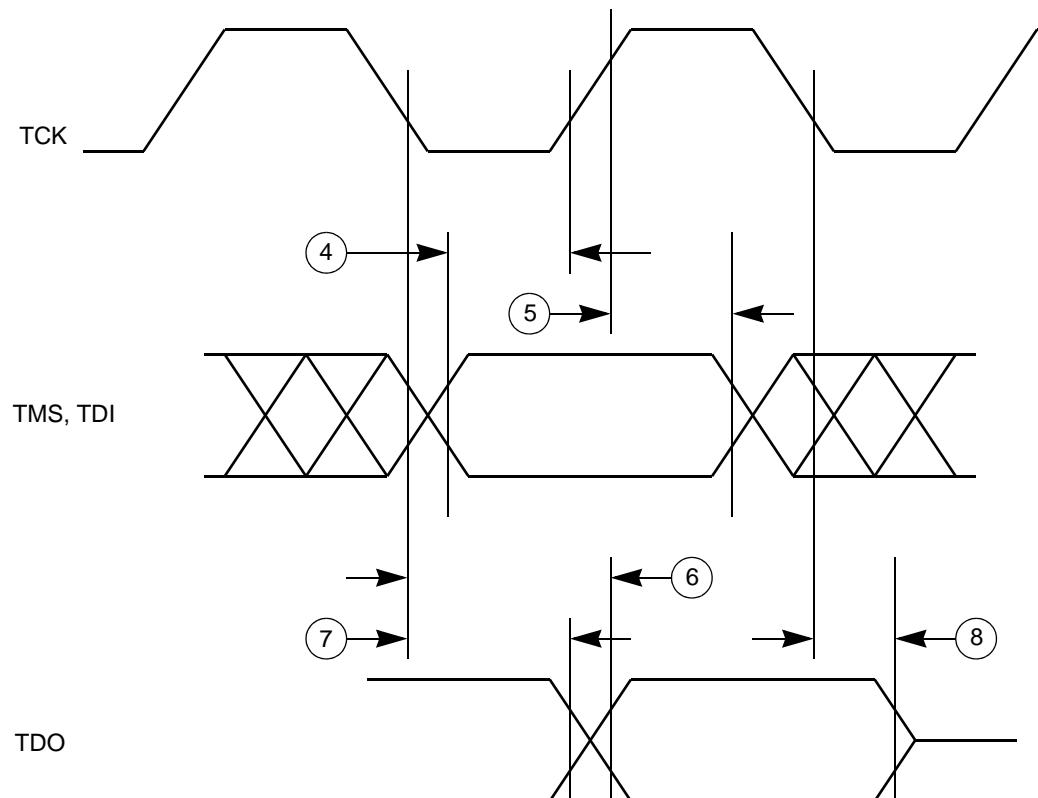


Figure 12. JTAG Test Access Port Timing

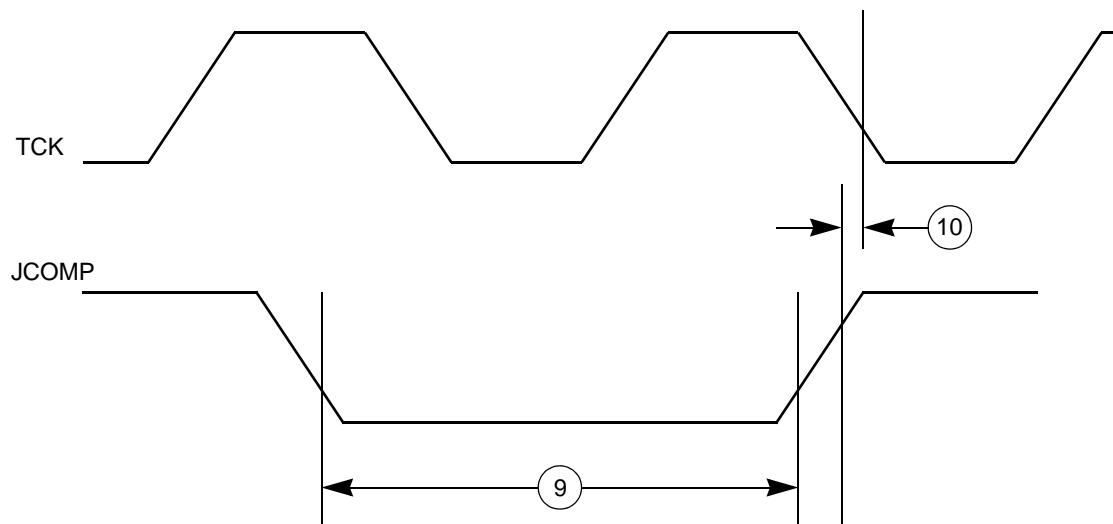


Figure 13. JTAG JCOMP Timing

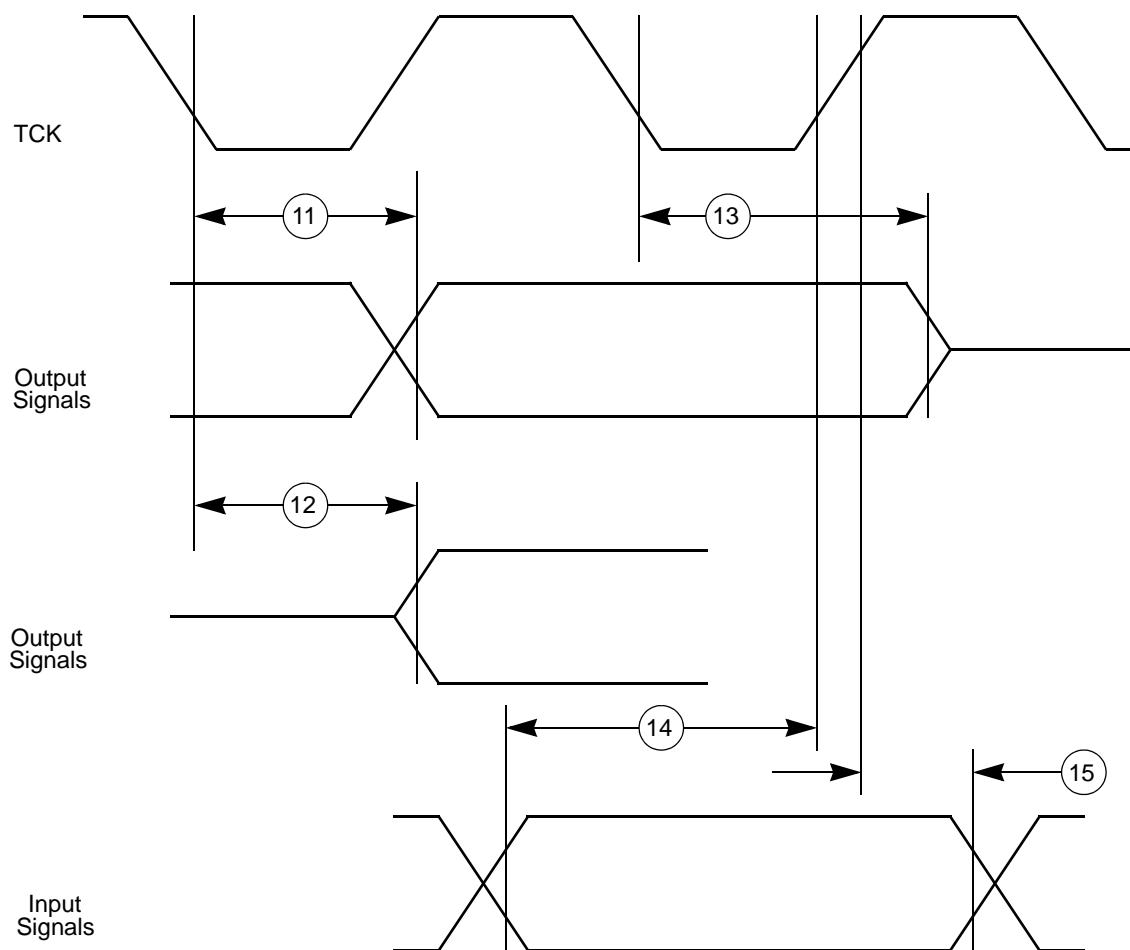


Figure 14. JTAG Boundary Scan Timing

#### 4.12.4 Nexus Timing

Table 33. Nexus Debug Port Timing<sup>1</sup>

Spec	Characteristic	Symbol	Min	Max	Unit
1	MCKO Cycle Time	$t_{MCYC}$	$2^2$	8	$t_{CYC}$
2	MCKO Duty Cycle	$t_{MDC}$	40	60	%
3	MCKO Low to MDO Data Valid <sup>3</sup>	$t_{MDOV}$	-0.1	0.2	$t_{MCYC}$
4	MCKO Low to MSEO Data Valid <sup>3</sup>	$t_{MSEOV}$	-0.1	0.2	$t_{MCYC}$
5	MCKO Low to EVTO Data Valid <sup>3</sup>	$t_{EVTOV}$	-0.1	0.2	$t_{MCYC}$
6	EVTI Pulse Width	$t_{EVТИPW}$	4.0	—	$t_{TCYC}$
7	EVTO Pulse Width	$t_{EVTOPW}$	1	—	$t_{MCYC}$
8	TCK Cycle Time	$t_{TCYC}$	$4^4$	—	$t_{CYC}$
9	TCK Duty Cycle	$t_{TDC}$	40	60	%
10	TDI, TMS Data Setup Time	$t_{NTDIS}, t_{NTMSS}$	8	—	ns

## Electrical Characteristics

Table 33. Nexus Debug Port Timing<sup>1</sup> (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
11	TDI, TMS Data Hold Time	$t_{NTDIH}, t_{NTMSH}$	5	—	ns
12	TCK Low to TDO Data Valid	$t_{NTDOV}$	0	10	ns
13	RDY Valid to MCKO <sup>5</sup>	—	—	—	—
14	TDO hold time after TCLK low	$t_{NTDOH}$	1	—	ns

<sup>1</sup> All Nexus timing relative to MCKO is measured from 50% of MCKO and 50% of the respective signal. Nexus timing specified at  $V_{DD} = 1.08$  V to 1.32 V,  $V_{DDE} = 3.0$  V to 3.6 V,  $V_{DD33}$  and  $V_{DDSYN} = 3.0$  V to 3.6 V,  $T_A = T_L$  to  $T_H$ , and  $C_L = 30$  pF with DSC = 0b10.

<sup>2</sup> The Nexus AUX port runs up to 82 MHz (pending characterization). Set NPC\_PCR[MCKO\_DIV] to correct division depending on the system frequency, not to exceed maximum Nexus AUX port frequency.

<sup>3</sup> MDO, MSEO, and EVTO data is held valid until next MCKO low cycle.

<sup>4</sup> Lower frequency is required to be fully compliant to standard.

<sup>5</sup> The RDY pin timing is asynchronous to MCKO. The timing is guaranteed by design to function correctly.

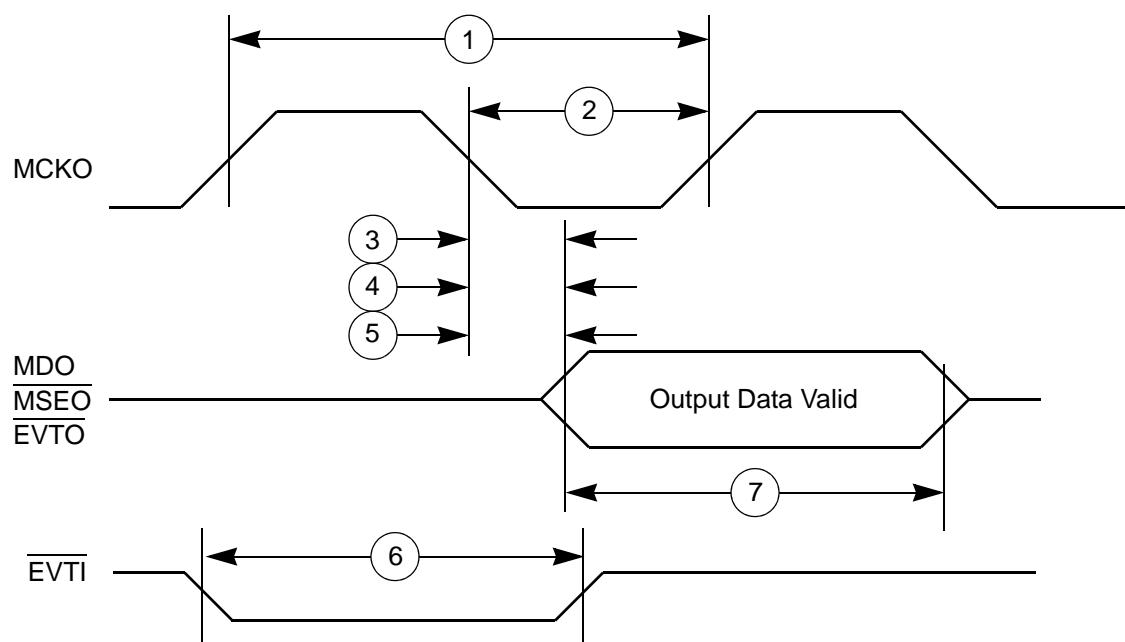


Figure 15. Nexus Timings

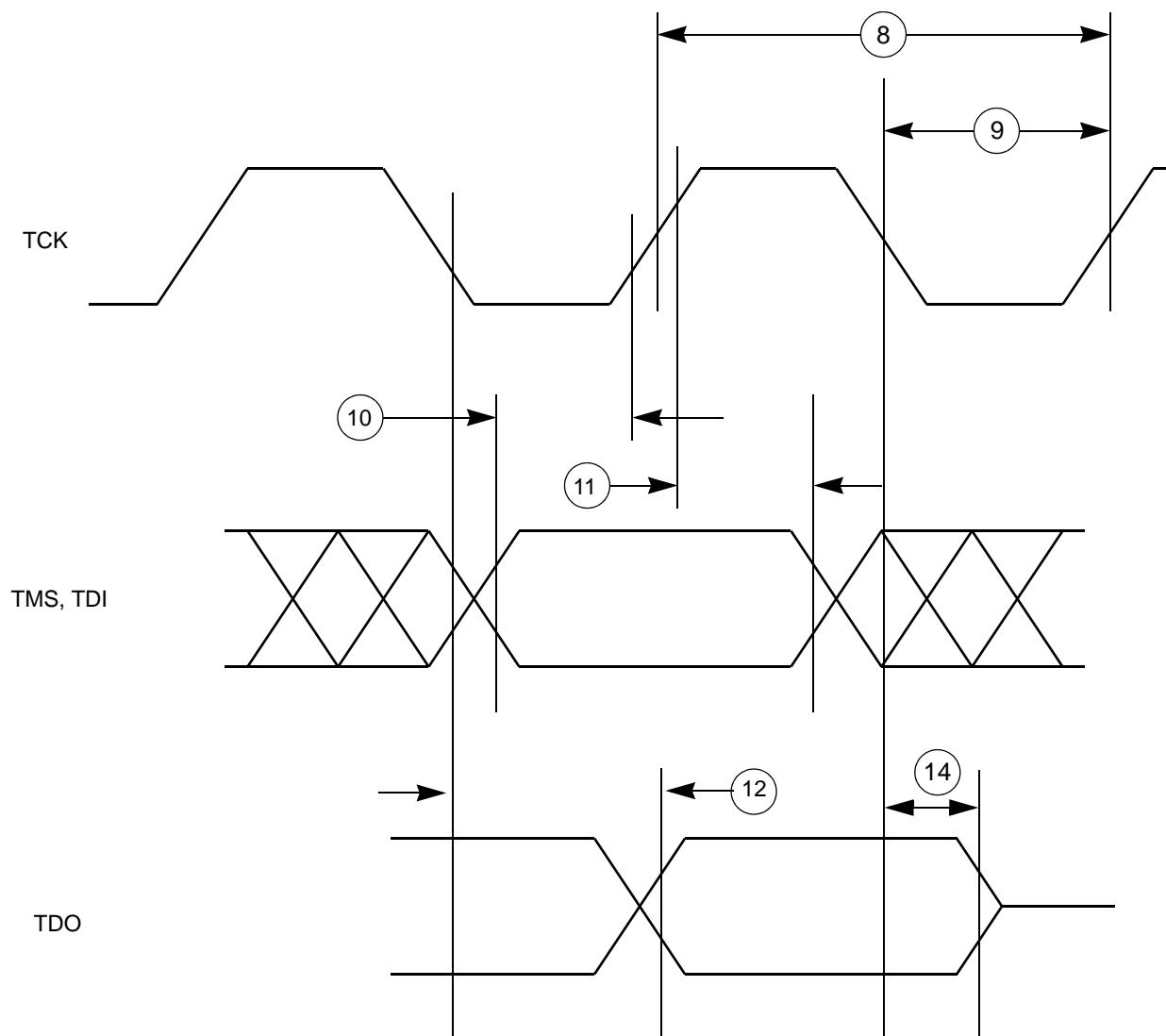


Figure 16. Nexus TCK, TDI, TMS, TDO Timing

#### 4.12.5 External Bus Interface (EBI) Timing

Table 34. Bus Operation Timing<sup>1</sup>

Spec	Characteristic	Symbol	66 MHz (Ext. Bus Freq) <sup>2 3</sup>		Unit	Notes
			Min	Max		
1	D_CLKOUT Period	$t_C$	15.2	—	ns	Signals are measured at 50% $V_{DDE}$ .

## Electrical Characteristics

Table 34. Bus Operation Timing<sup>1</sup> (continued)

Spec	Characteristic	Symbol	66 MHz (Ext. Bus Freq) <sup>2 3</sup>		Unit	Notes
			Min	Max		
2	D_CLKOUT Duty Cycle	t <sub>CDC</sub>	45%	55%	t <sub>C</sub>	
3	D_CLKOUT Rise Time	t <sub>CRT</sub>	—	— <sup>4</sup>	ns	
4	D_CLKOUT Fall Time	t <sub>CFT</sub>	—	— <sup>4</sup>	ns	
5	D_CLKOUT Posedge to Output Signal Invalid or High Z (Hold Time)  D_ADD[9:30] D_BDIP D_CS[0:3] D_DAT[0:15] D_OE <u>D_RD_WR</u> D_TA D_TS <u>D_WE[0:3]/D_BE[0:3]</u>	t <sub>COH</sub>	1.0/1.5	—	ns	Hold time selectable via SIU_ECCR[EBTS] bit: EBTS = 0: 1.0 ns EBTS = 1: 1.5 ns
6	D_CLKOUT Posedge to Output Signal Valid (Output Delay)  D_ADD[9:30] D_BDIP D_CS[0:3] D_DAT[0:15] D_OE <u>D_RD_WR</u> D_TA D_TS <u>D_WE[0:3]/D_BE[0:3]</u>	t <sub>COV</sub>	—	8.5/9.0	ns	Output valid time selectable via SIU_ECCR[EBTS] bit: EBTS = 0: 8.5 ns EBTS = 1: 9.0 ns
7	Input Signal Valid to D_CLKOUT Posedge (Setup Time)  D_ADD[9:30] <u>D_DAT[0:15]</u> <u>D_RD_WR</u> D_TA D_TS	t <sub>CIS</sub>	5.0/4.5	—	ns	Input setup time selectable via SIU_ECCR[EBTS] bit: EBTS = 0; 5.0ns EBTS = 1; 4.5ns
8	D_CLKOUT Posedge to Input Signal Invalid (Hold Time)  D_ADD[9:30] <u>D_DAT[0:15]</u> <u>D_RD_WR</u> D_TA D_TS	t <sub>CIH</sub>	1.0	—	ns	
9	D_ALE Pulse Width	t <sub>APW</sub>	6.5	—	ns	The timing is for Asynchronous external memory system.
10	D_ALE Negated to Address Invalid	t <sub>AAI</sub>	2.0/1.0 <sup>5</sup>	—	ns	The timing is for Asynchronous external memory system. ALE is measured at 50% of VDDE.

- <sup>1</sup> EBI timing specified at  $V_{DD} = 1.08\text{ V}$  to  $1.32\text{ V}$ ,  $V_{DDE} = 3.0\text{ V}$  to  $3.6\text{ V}$ ,  $V_{DD33}$  and  $V_{DDSYN} = 3.0\text{ V}$  to  $3.6\text{ V}$ ,  $T_A = T_L$  to  $T_H$ , and  $C_L = 30\text{ pF}$  with DSC = 0b10.
- <sup>2</sup> Speed is the nominal maximum frequency. Max speed is the maximum speed allowed including frequency modulation (FM).
- <sup>3</sup> Depending on the internal bus speed, set the SIU\_ECCR[EBDF] bits correctly not to exceed maximum external bus frequency. The maximum external bus frequency is 66 MHz.
- <sup>4</sup> Refer to Fast pad timing in [Table 29](#) and [Table 30](#).
- <sup>5</sup> ALE hold time spec is temperature dependant. 1.0ns spec applies for temperature range -40 to 0 C. 2.0ns spec applies to temperatures > 0 C. This spec has no dependency on SIU\_ECCR[EBTS] bit.

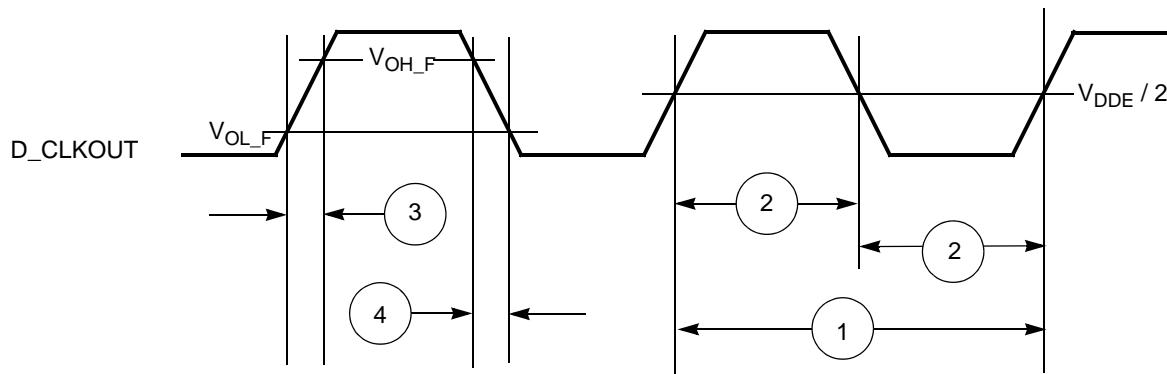


Figure 17. D\_CLKOUT Timing

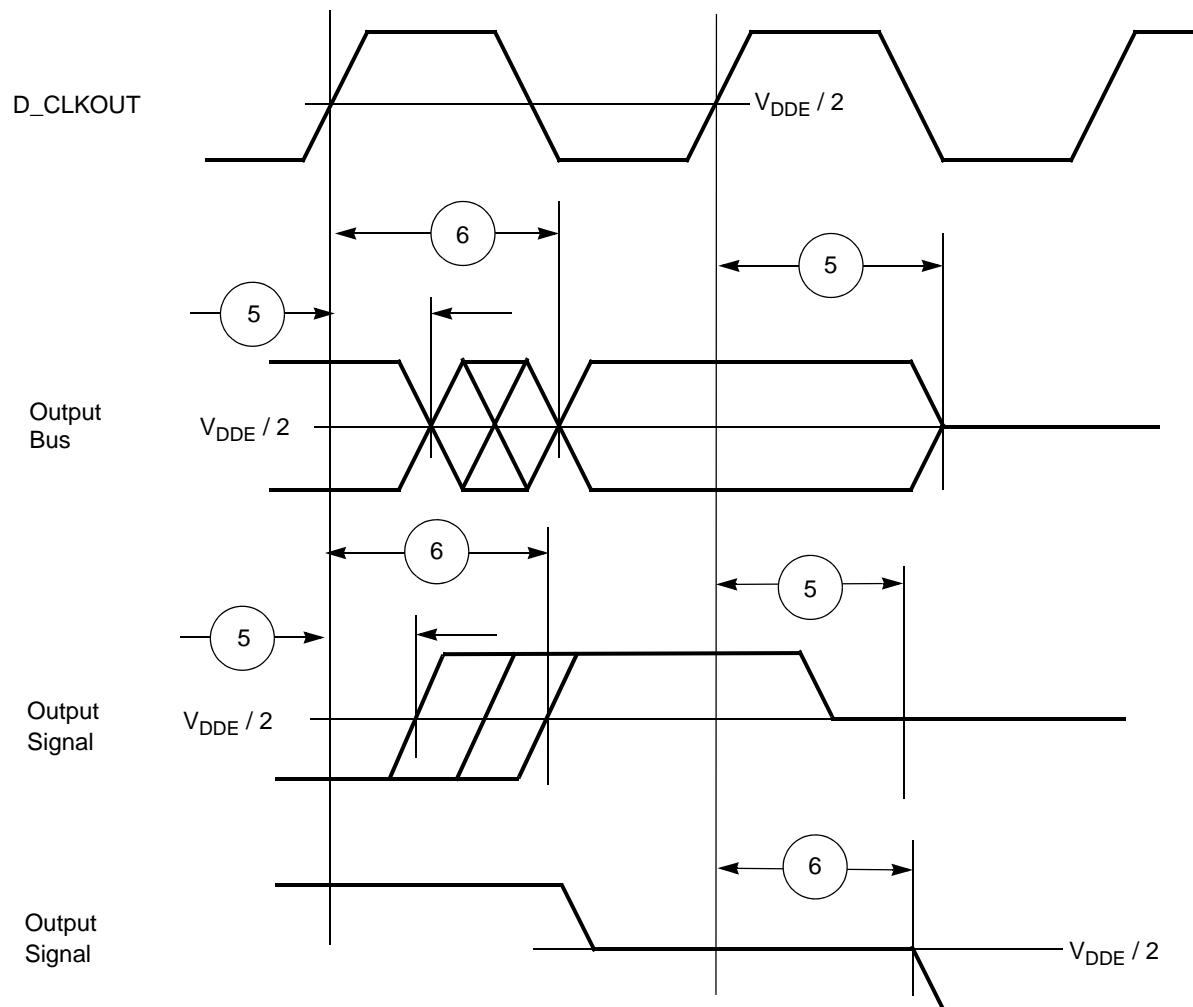


Figure 18. Synchronous Output Timing

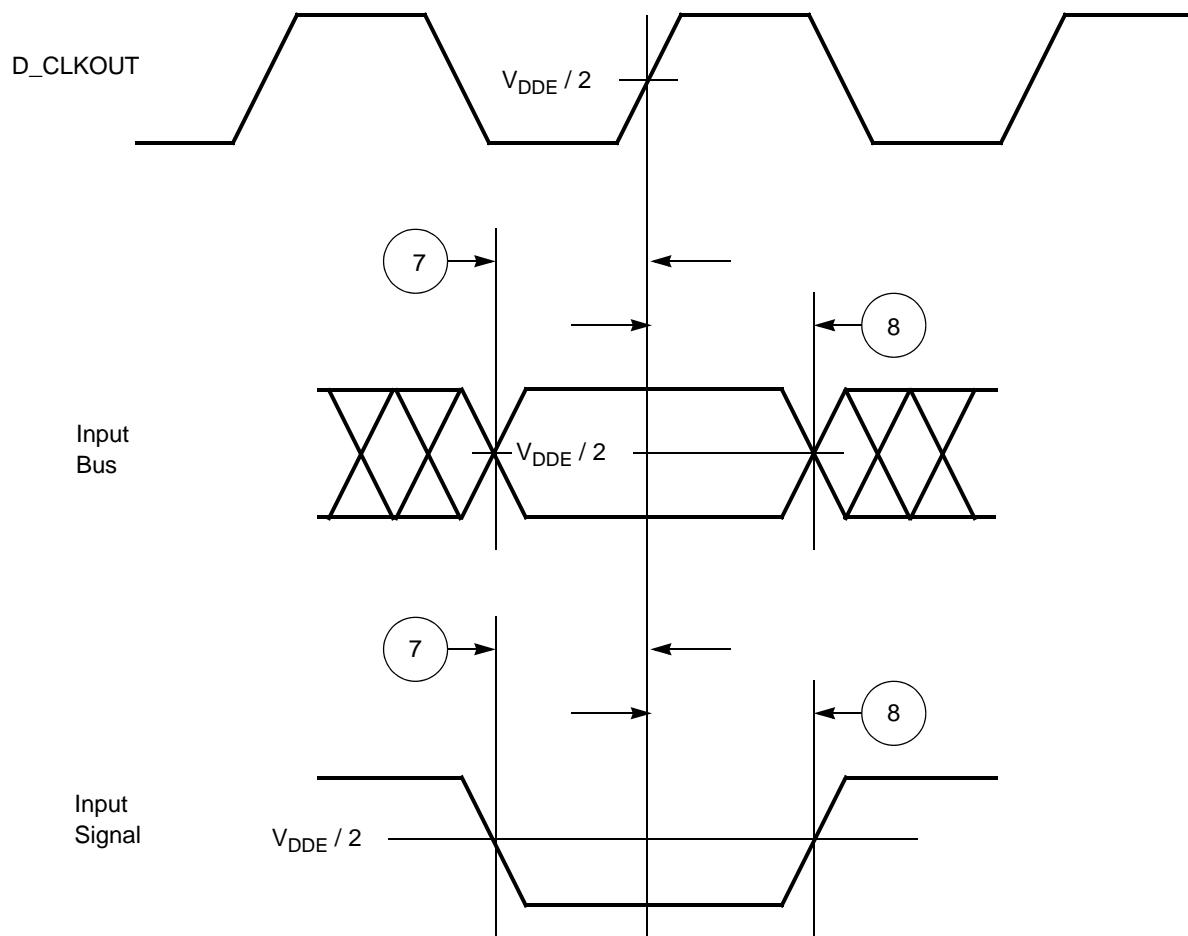


Figure 19. Synchronous Input Timing

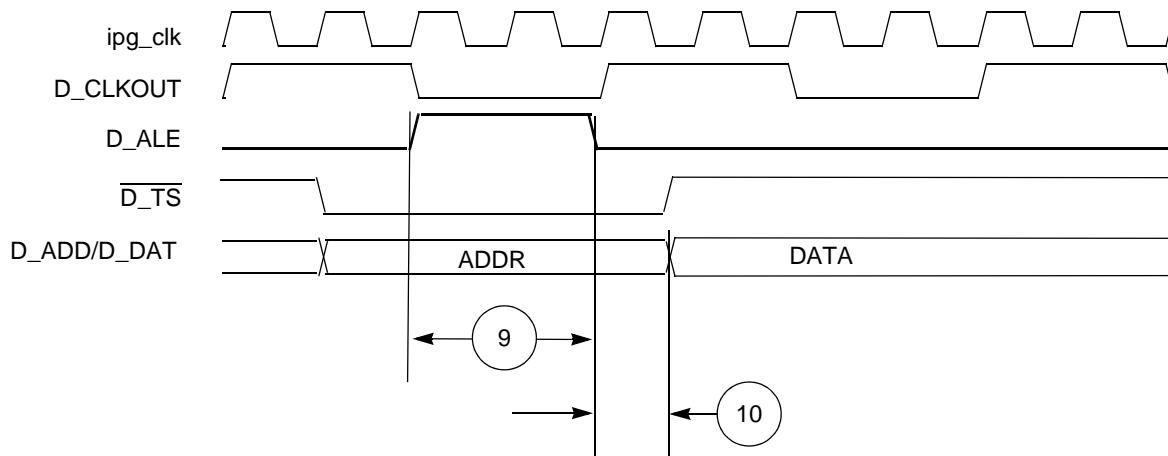


Figure 20. ALE Signal Timing

## 4.12.6 External Interrupt Timing (IRQ Pin)

Table 35. External Interrupt Timing<sup>1</sup>

Spec	Characteristic	Symbol	Min	Max	Unit
1	IRQ Pulse Width Low	$t_{IPWL}$	3	—	$t_{cyc}^2$
2	IRQ Pulse Width High	$t_{IPWH}$	3	—	$t_{cyc}^2$
3	IRQ Edge to Edge Time <sup>3</sup>	$t_{ICYC}$	6	—	$t_{cyc}^2$

<sup>1</sup> IRQ timing specified at  $V_{DD} = 1.08\text{ V}$  to  $1.32\text{ V}$ ,  $V_{DDEH} = 3.0\text{ V}$  to  $5.5\text{ V}$ ,  $V_{DD33}$  and  $V_{DDSYN} = 3.0\text{ V}$  to  $3.6\text{ V}$ ,  $T_A = T_L$  to  $T_H$ .

<sup>2</sup> See Notes on  $t_{cyc}$  Table 28.

<sup>3</sup> Applies when IRQ pins are configured for rising edge or falling edge events, but not both.

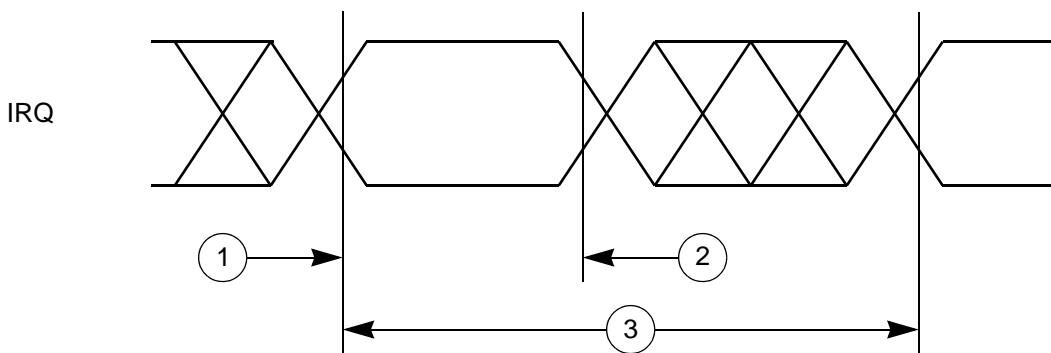


Figure 21. External Interrupt Timing

## 4.12.7 eTPU Timing

Table 36. eTPU Timing<sup>1</sup>

Spec	Characteristic	Symbol	Min	Max	Unit
1	eTPU Input Channel Pulse Width	$t_{ICPW}$	4	—	$t_{cyc}^2$
2	eTPU Output Channel Pulse Width	$t_{OCPW}$	1 <sup>3</sup>	—	$t_{cyc}^2$

<sup>1</sup> eTPU timing specified at  $V_{DD} = 1.08\text{ V}$  to  $1.32\text{ V}$ ,  $V_{DDEH} = 3.0\text{ V}$  to  $5.5\text{ V}$ ,  $V_{DD33}$  and  $V_{DDSYN} = 3.0\text{ V}$  to  $3.6\text{ V}$ ,  $T_A = T_L$  to  $T_H$ , and  $C_L = 200\text{ pF}$  with SRC = 0b00.

<sup>2</sup> See Notes on  $t_{cyc}$  Table 28.

<sup>3</sup> This specification does not include the rise and fall times. When calculating the minimum eTPU pulse width, include the rise and fall times defined in the slew rate control fields (SRC) of the pad configuration registers (PCR).

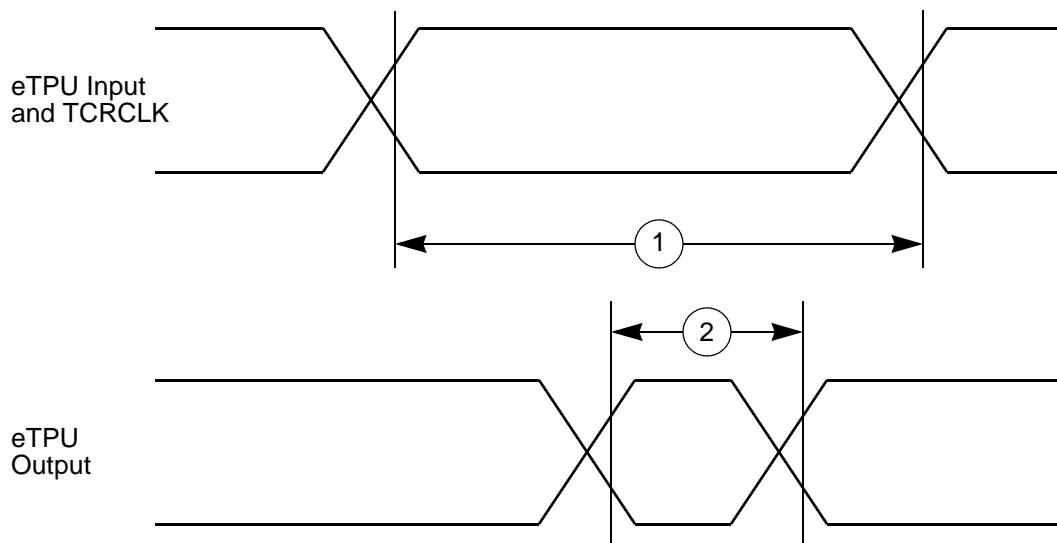


Figure 22. eTPU Timing

#### 4.12.8 eMIOS Timing

Table 37. eMIOS Timing<sup>1</sup>

Spec	Characteristic	Symbol	Min	Max	Unit
1	eMIOS Input Pulse Width	$t_{MIPW}$	4	—	$t_{cyc}^2$
2	eMIOS Output Pulse Width	$t_{MOPW}$	1 <sup>3</sup>	—	$t_{cyc}^2$

<sup>1</sup> eMIOS timing specified at  $V_{DD} = 1.08\text{ V}$  to  $1.32\text{ V}$ ,  $V_{DDEH} = 3.0\text{ V}$  to  $5.5\text{ V}$ ,  $V_{DD33}$  and  $V_{DDSYN} = 3.0\text{ V}$  to  $3.6\text{ V}$ ,  $T_A = T_L$  to  $T_H$ , and  $C_L = 50\text{ pF}$  with SRC = 0b00.

<sup>2</sup> See Notes on  $t_{cyc}$  on Table 28.

<sup>3</sup> This specification does not include the rise and fall times. When calculating the minimum eMIOS pulse width, include the rise and fall times defined in the slew rate control fields (SRC) of the pad configuration registers (PCR).

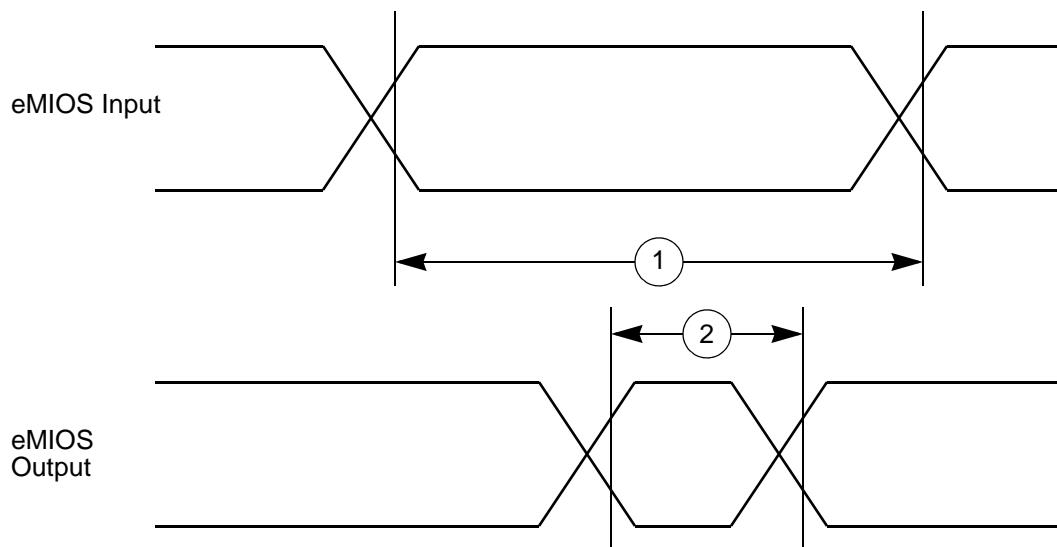


Figure 23. eMOS Timing

#### 4.12.9 DSPI Timing

Table 38. DSPI Timing<sup>1,2</sup>

Spec	Characteristic	Symbol	Peripheral Bus Freq: 92 MHz		Unit
			Min	Max	
1	DSPI Cycle Time <sup>3, 4</sup> Master (MTFE = 0) Slave (MTFE = 0) Master (MTFE = 1) Slave (MTFE = 1)	t <sub>SCK</sub>	23.8	1800	ns
2	PCS to SCK Delay <sup>5</sup>	t <sub>CSC</sub>	12	—	ns
3	After SCK Delay <sup>6</sup>	t <sub>ASC</sub>	12	—	ns
4	SCK Duty Cycle	t <sub>SDC</sub>	0.4 * t <sub>SCK</sub>	0.6 * t <sub>SCK</sub>	ns
5	Slave Access Time (SS active to SOUT valid)	t <sub>A</sub>	—	25	ns
6	Slave SOUT Disable Time (SS inactive to SOUT High-Z or invalid)	t <sub>DIS</sub>	—	25	ns
7	PCSx to PCSS time	t <sub>PCSC</sub>	4	—	ns
8	PCSS to PCSx time	t <sub>PASC</sub>	5	—	ns

Table 38. DSPI Timing<sup>1,2</sup> (continued)

Spec	Characteristic	Symbol	Peripheral Bus Freq: 92 MHz		Unit
			Min	Max	
9	Data Setup Time for Inputs Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) <sup>7</sup> Master (MTFE = 1, CPHA = 1)	t <sub>SUI</sub>	27	—	ns
			10	—	ns
			7	—	ns
			27	—	ns
10	Data Hold Time for Inputs Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) <sup>7</sup> Master (MTFE = 1, CPHA = 1)	t <sub>HI</sub>	-3	—	ns
			7	—	ns
			12	—	ns
			-3	—	ns
11	Data Valid (after SCK edge) Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) Master (MTFE = 1, CPHA = 1) Master (LVDS)	t <sub>SUO</sub>	—	10	ns
			—	30	ns
			—	20	ns
			—	10	ns
			—	5	ns
			—	—	—
12	Data Hold Time for Outputs Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) Master (MTFE = 1, CPHA = 1) Master (LVDS)	t <sub>HO</sub>	-6	—	ns
			2.5	—	ns
			3	—	ns
			-7	—	ns
			-5	—	ns
			—	—	—

<sup>1</sup> DSPI timing specified at V<sub>DD</sub> = 1.08 V to 1.32 V, V<sub>DDEH</sub> = 3.0 V to 5.5 V, V<sub>DD33</sub> and V<sub>DDSYN</sub> = 3.0 V to 3.6 V, and T<sub>A</sub> = T<sub>L</sub> to T<sub>H</sub>

<sup>2</sup> Speed is the nominal maximum frequency of platform clock (f<sub>platf</sub>). Max speed is the maximum speed allowed including frequency modulation (FM).

<sup>3</sup> The minimum DSPI Cycle Time restricts the baud rate selection for given system clock rate. These numbers are calculated based on two devices communicating over a DSPI link.

<sup>4</sup> The actual minimum SCK cycle time is limited by pad performance.

<sup>5</sup> The maximum value is programmable in DSPI\_CTAR<sub>n</sub>[PSSCK] and DSPI\_CTAR<sub>n</sub>[CSSCK].

<sup>6</sup> The maximum value is programmable in DSPI\_CTAR<sub>n</sub>[PASC] and DSPI\_CTAR<sub>n</sub>[ASC].

<sup>7</sup> This number is calculated assuming the SMPL\_PT bit-field in DSPI\_MCR is set to 0b10.

The DSPI in this device can be configured to serialize data to an external device that implements the Microsecond Bus protocol. DSPI pins support 5 V logic levels or Low Voltage Differential Signalling (LVDS) for data and clock signals to improve high speed operation.

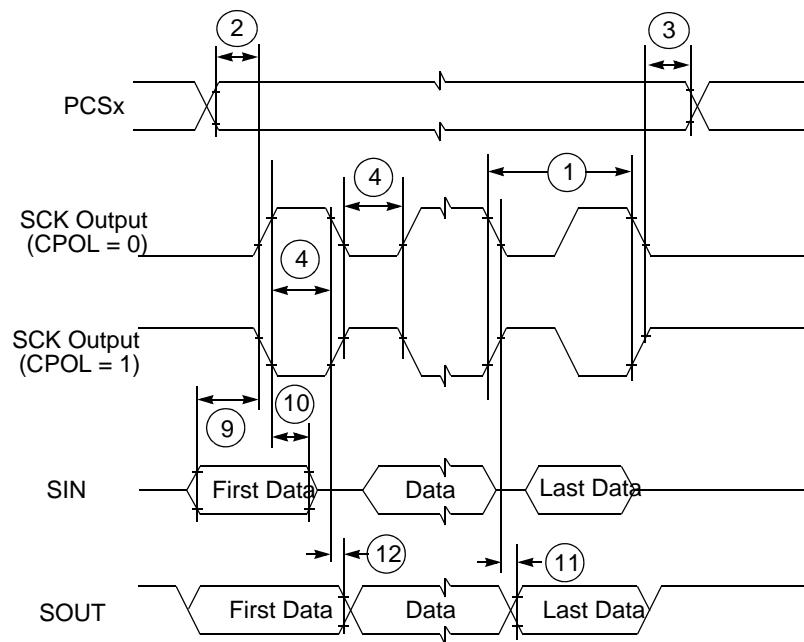


Figure 24. DSPI Classic SPI Timing — Master, CPHA = 0

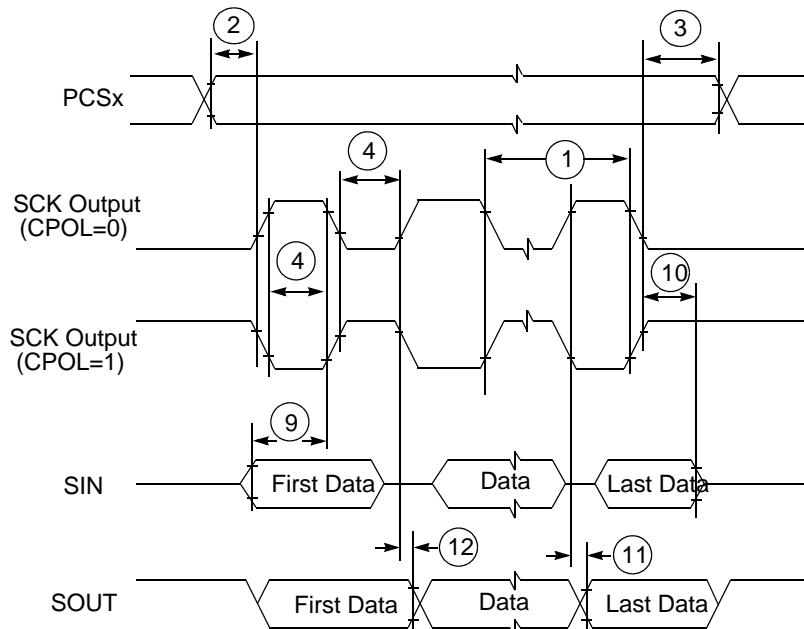


Figure 25. DSPI Classic SPI Timing — Master, CPHA = 1

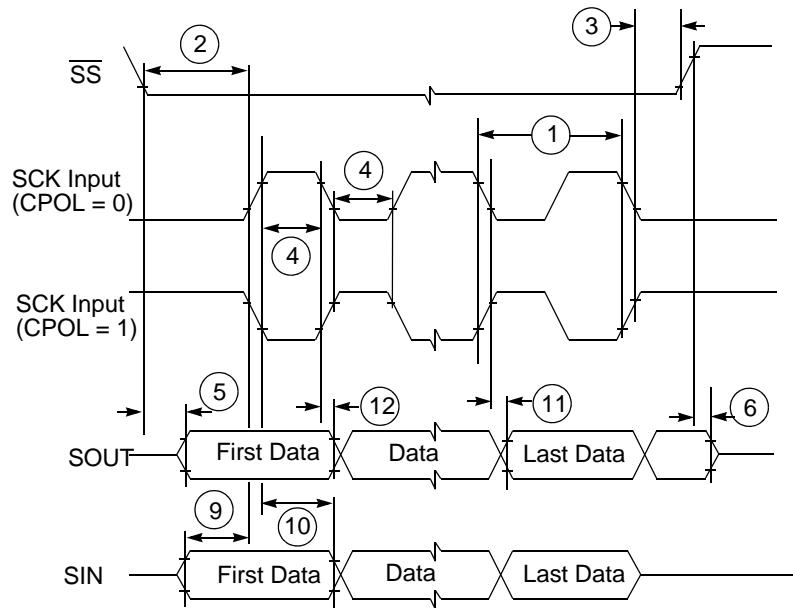


Figure 26. DSPI Classic SPI Timing — Slave, CPHA = 0

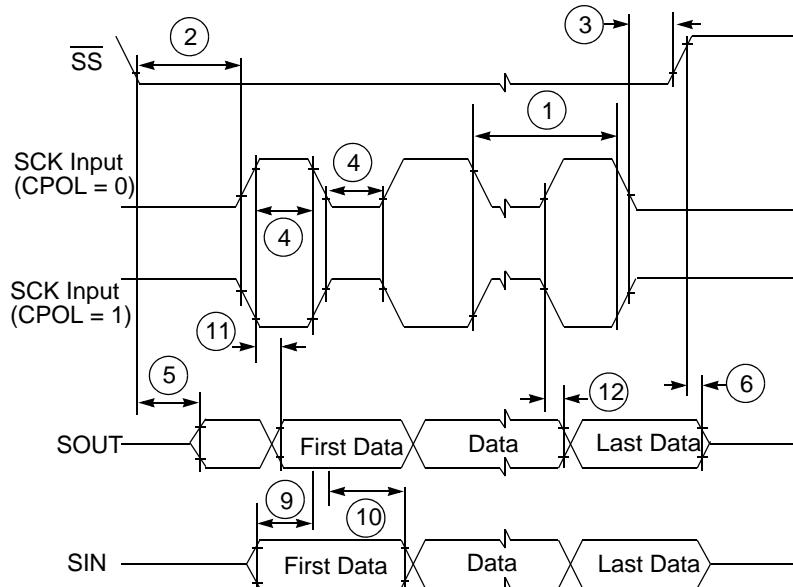


Figure 27. DSPI Classic SPI Timing — Slave, CPHA = 1

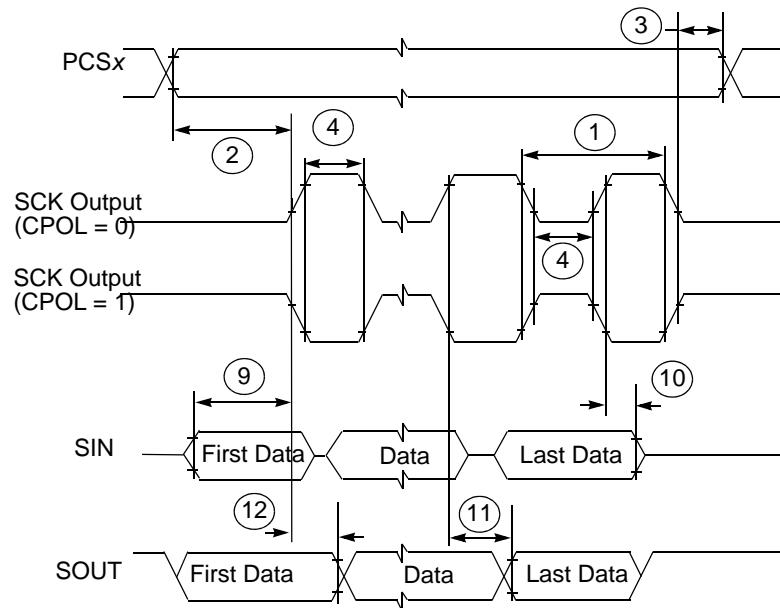


Figure 28. DSPI Modified Transfer Format Timing — Master, CPHA = 0

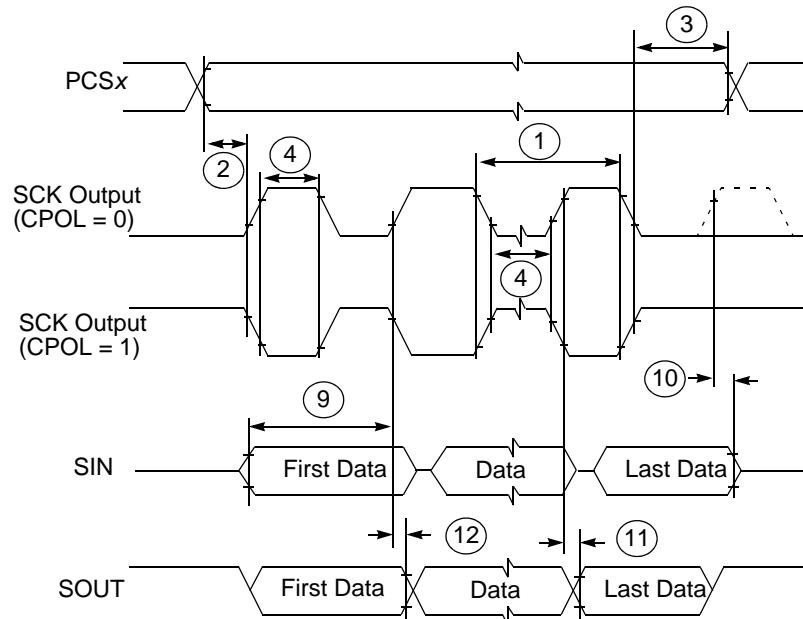


Figure 29. DSPI Modified Transfer Format Timing — Master, CPHA = 1

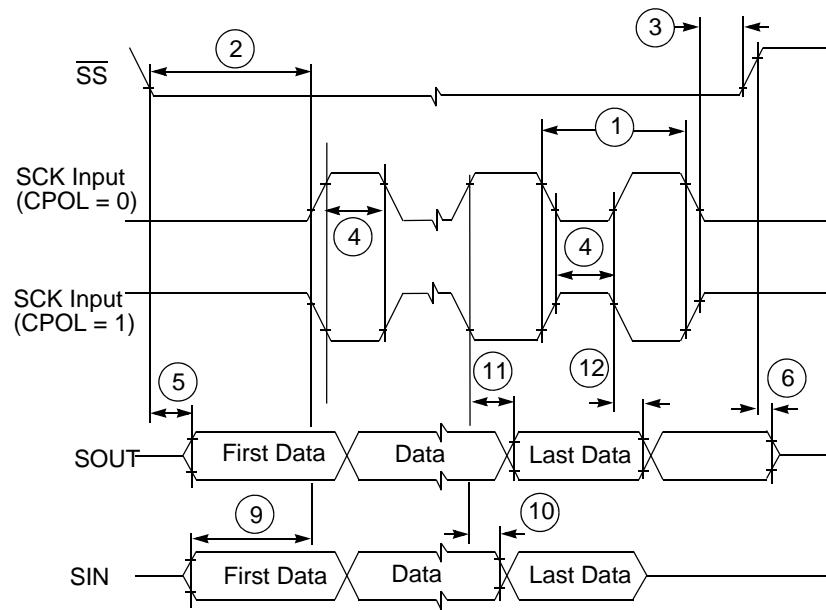


Figure 30. DSPI Modified Transfer Format Timing — Slave, CPHA = 0

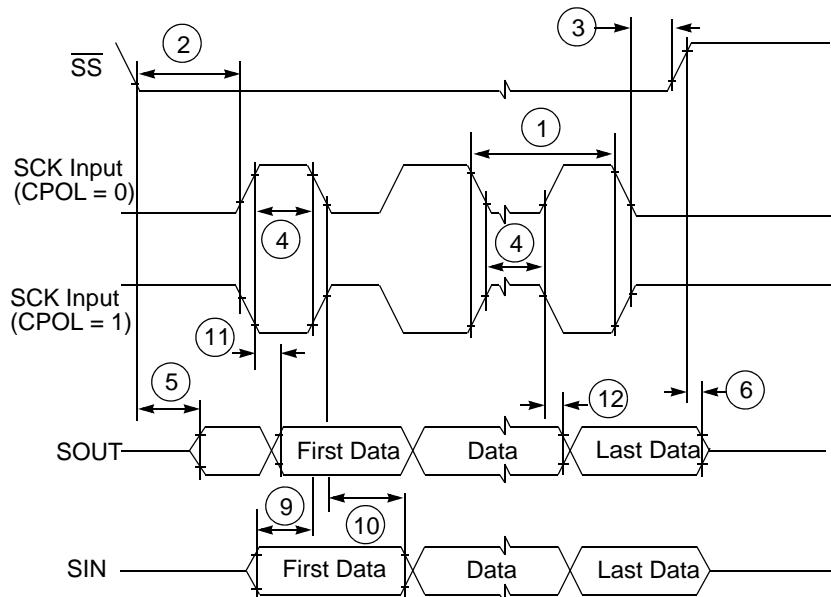


Figure 31. DSPI Modified Transfer Format Timing — Slave, CPHA = 1

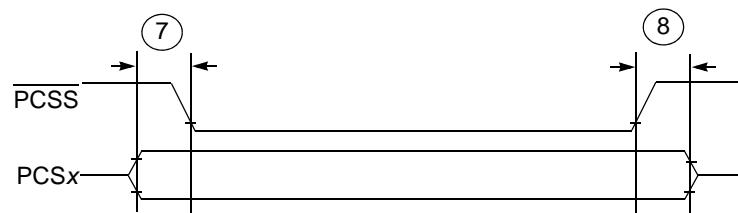


Figure 32. DSPI PCS Strobe ( $\overline{\text{PCSS}}$ ) Timing

## 5 Package Information

### 5.1 416-Pin Package

The package drawings of the 416-pin TEPBGA package are shown in [Figure 33](#) and [Figure 34](#).

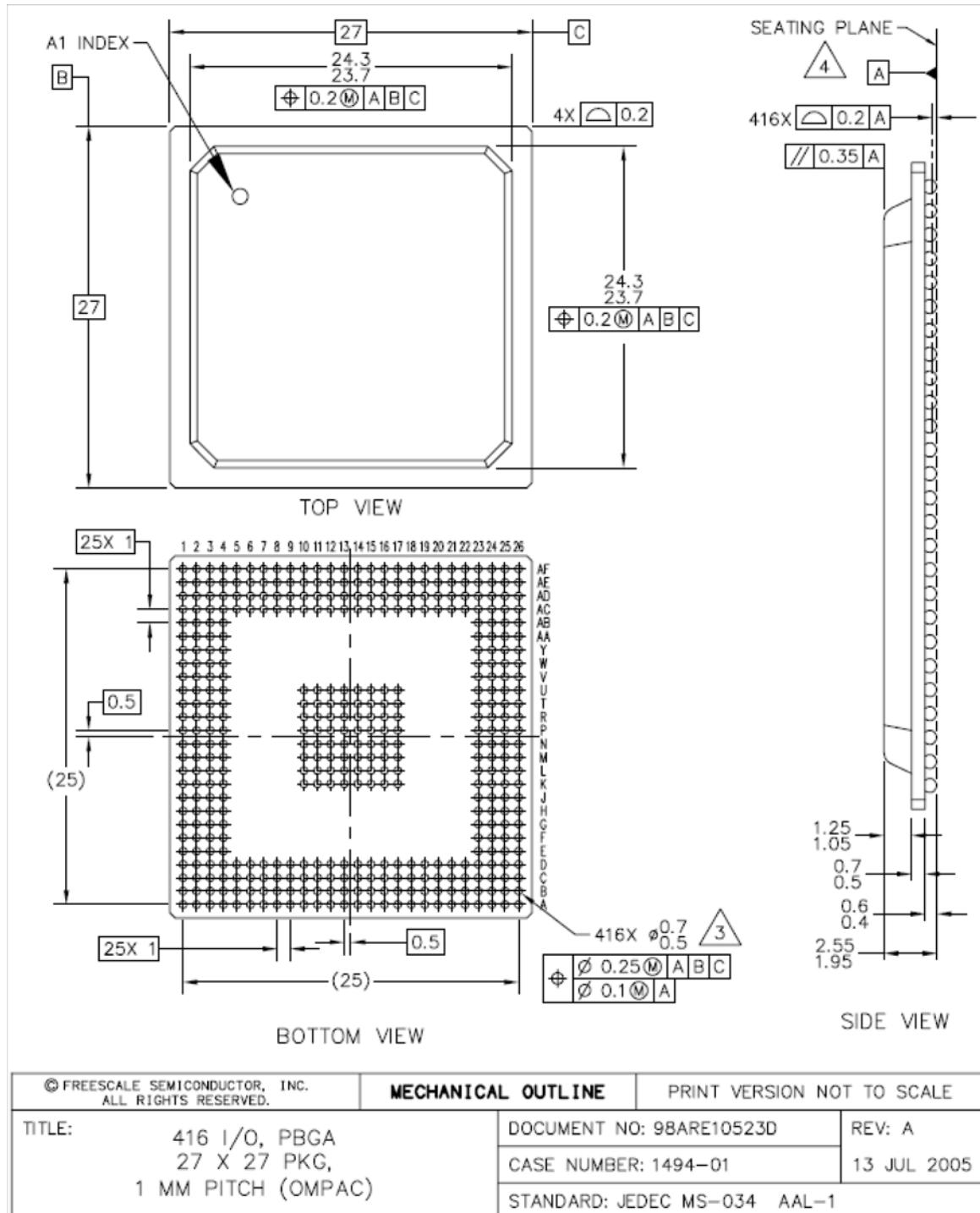


Figure 33. 416 TEPBGA Package (1 of 2)

## Package Information

## NOTES:

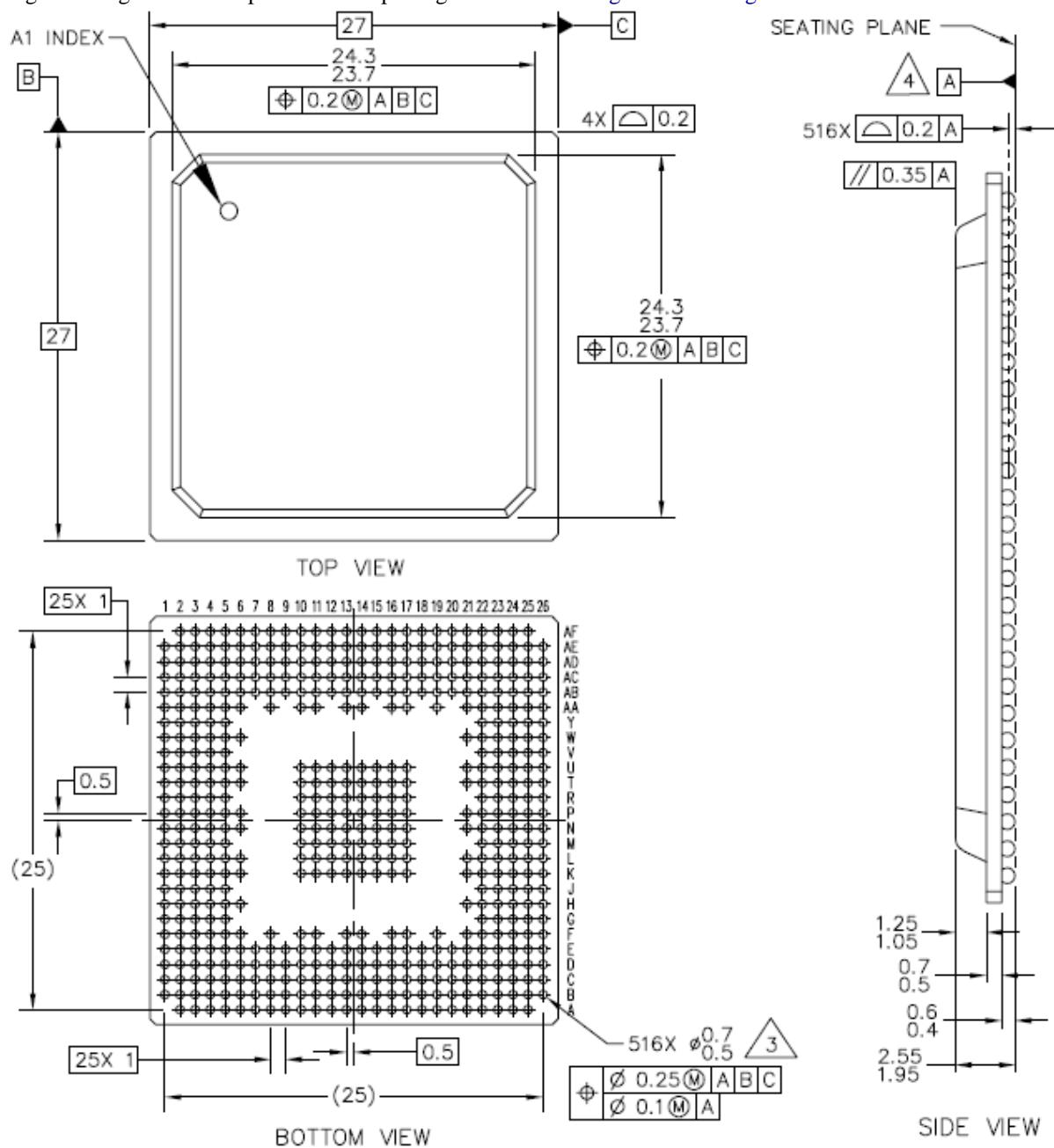
1. ALL DIMENSIONS IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.

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TITLE: 416 I/O, PBGA 27 X 27 PKG, 1 MM PITCH (OMPAC)	DOCUMENT NO: 98ARE10523D CASE NUMBER: 1494-01 STANDARD: JEDEC MS-034 AAL-1	REV: A 13 JUL 2005

Figure 34. 416 TEPBGA Package (2 of 2)

## 5.2 516-Pin Package

The package drawings of the 516-pin TEPBGA package are shown in [Figure 35](#) and [Figure 36](#).



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TITLE:	516 I/O, PBGA 27 X 27 PKG, 1 MM PITCH (OMPAC)	DOCUMENT NO: 98ARS10503D	REV: B	
		CASE NUMBER: 1164A-01		09 AUG 2005
		STANDARD: JEDEC MS-034 AAL-1		

**Figure 35. 516 TEPBGA Package (1 of 2)**

## Package Information

## NOTES:

1. ALL DIMENSIONS IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
5. PACKAGE CODES: 5193 & 5198.

© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED.	<b>MECHANICAL OUTLINE</b>	PRINT VERSION NOT TO SCALE	
TITLE:  516 I/O, PBGA 27 X 27 PKG, 1 MM PITCH (OMPAC)	DOCUMENT NO: 98ARS10503D	REV: B	
	CASE NUMBER: 1164A-01	09 AUG 2005	
	STANDARD: JEDEC MS-034 AAL-1		

Figure 36. 516 TEPBGA Package (2 of 2)

## 6 Product Documentation

This data sheet is labeled as a particular type: Product Preview, Advance Information, or Technical Data. Definitions of these types are available at: <http://www.nxp.com>.

The following documents are required for a complete description of the device and are necessary to design properly with the parts:

- *MPC5676R RM Microprocessor Reference Manual* (document number MPC5676RRM)

## Appendix A Signal Properties and Muxing

The following table shows the signals properties for each pin on the MPC5676R. For each port pin that has an associated SIU\_PCRn register to control its pin properties, the supported functions column lists the functions associated with the programming of the SIU\_PCRn[PA] bit in the order: Primary function (P), Function 2 (F2), Function 3 (F3), and GPIO (G). See [Figure 37](#).

Table 2. Signal Properties and Muxing Summary						
GPIO/ PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/ F/ G	Function <sup>3</sup>	Function Summary	I/O	Pad Type
113	TCRCLKA_IRQ7_GPIO113	P	TCRCLKA	eTPU A TCR clock	I	5V M
		A1	IRQ7	External interrupt request	I	
		A2	—	—	—	
		G	GPIO113	GPIO	I/O	

**Primary Functions** are listed First →

**Secondary Functions** are alternate functions →

**GPIO Functions** are listed Last →

Function not implemented on this device

**Figure 37. Supported Functions Example**

**Table 39. Signal Properties and Muxing Summary**

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
121	ETPUA7_ETPUA19_GPIO121	P	ETPUA7	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	J1	H2
		A1	ETPUA19	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO121	GPIO	I/O						
122	ETPUA8_ETPUA20_GPIO122	P	ETPUA8	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	J2	H3
		A1	ETPUA20	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO122	GPIO	I/O						
123	ETPUA9_ETPUA21_GPIO123	P	ETPUA9	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	J3	J3
		A1	ETPUA21	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO123	GPIO	I/O						
124	ETPUA10_ETPUA22_GPIO124	P	ETPUA10	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	J4	K6
		A1	ETPUA22	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO124	GPIO	I/O						
125	ETPUA11_ETPUA23_GPIO125	P	ETPUA11	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	H1	G1
		A1	ETPUA23	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO125	GPIO	I/O						
126	ETPUA12_PCSB1_GPIO126	P	ETPUA12	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	H2	J5
		A1	PCSB1	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO126	GPIO	I/O						

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
127	ETPUA13_PCSB3_GPIO127	P	ETPUA13	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	H4	G2
		A1	PCSB3	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO127	GPIO	I/O						
128	ETPUA14_PCSB4_GPIO128	P	ETPUA14	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	H3	H5
		A1	PCSB4	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO128	GPIO	I/O						
129	ETPUA15_PCSB5_GPIO129	P	ETPUA15	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	G1	G3
		A1	PCSB5	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO129	GPIO	I/O						
130	ETPUA16_PCSD1_GPIO130	P	ETPUA16	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	G2	H6
		A1	PCSD1	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO130	GPIO	I/O						
131	ETPUA17_PCSD2_GPIO131	P	ETPUA17	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	G3	G4
		A1	PCSD2	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO131	GPIO	I/O						
132	ETPUA18_PCSD3_GPIO132	P	ETPUA18	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	G4	G5
		A1	PCSD3	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO132	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
139	ETPUA25_IRQ13_GPIO139	P	ETPUA25	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	E3	E3
		A1	IRQ13	External interrupt request	I						
		A2	—	—	—						
		G	GPIO139	GPIO	I/O						
140	ETPUA26_IRQ14_GPIO140	P	ETPUA26	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	E4	E4
		A1	IRQ14	External interrupt request	I						
		A2	—	—	—						
		G	GPIO140	GPIO	I/O						
141	ETPUA27_IRQ15_GPIO141	P	ETPUA27	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	D1	D1
		A1	IRQ15	External interrupt request	I						
		A2	—	—	—						
		G	GPIO141	GPIO	I/O						
142	ETPUA28_PCSC1_GPIO142	P	ETPUA28	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	D2	D2
		A1	PCSC1	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO142	GPIO	I/O						
143	ETPUA29_PCSC2_GPIO143	P	ETPUA29	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	D3	D3
		A1	PCSC2	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO143	GPIO	I/O						
144	ETPUA30_PCSC3_GPIO144	P	ETPUA30	eTPU A channel	I/O	MH	V <sub>DDEH1</sub>	—/WKPCFG	—/WKPCFG	C1	C1
		A1	PCSC3	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO144	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
151	ETPUB4_ETPUB20_GPIO151	P	ETPUB4	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	R24	U24
		A1	ETPUB20	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO151	GPIO	I/O						
152	ETPUB5_ETPUB21_GPIO152	P	ETPUB5	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	R25	U25
		A1	ETPUB21	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO152	GPIO	I/O						
153	ETPUB6_ETPUB22_GPIO153	P	ETPUB6	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	R26	U26
		A1	ETPUB22	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO153	GPIO	I/O						
154	ETPUB7_ETPUB23_GPIO154	P	ETPUB7	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	P23	T23
		A1	ETPUB23	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO154	GPIO	I/O						
155	ETPUB8_ETPUB24_GPIO155	P	ETPUB8	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	P24	T24
		A1	ETPUB24	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO155	GPIO	I/O						
156	ETPUB9_ETPUB25_GPIO156	P	ETPUB9	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	P25	R22
		A1	ETPUB25	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO156	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
163	ETPUB16_PCSA1_GPIO163	P	ETPUB16	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	U26	V24
		A1	PCSA1	DSPI A peripheral chip select	O						
		A2	—	—	—						
		G	GPIO163	GPIO	I/O						
164	ETPUB17_PCSA2_GPIO164	P	ETPUB17	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	U25	T21
		A1	PCSA2	DSPI A peripheral chip select	O						
		A2	—	—	—						
		G	GPIO164	GPIO	I/O						
165	ETPUB18_PCSA3_GPIO165	P	ETPUB18	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	U24	W26
		A1	PCSA3	DSPI A peripheral chip select	O						
		A2	—	—	—						
		G	GPIO165	GPIO	I/O						
166	ETPUB19_PCSA4_GPIO166	P	ETPUB19	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	U23	W25
		A1	PCSA4	DSPI A peripheral chip select	O						
		A2	—	—	—						
		G	GPIO166	GPIO	I/O						
167	ETPUB20_GPIO167	P	ETPUB20	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	V26	W24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO167	GPIO	I/O						
168	ETPUB21_GPIO168	P	ETPUB21	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	V25	V22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO168	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
175	ETPUB28_GPIO175	P	ETPUB28	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	Y24	AA24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO175	GPIO	I/O						
176	ETPUB29_GPIO176	P	ETPUB29	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	Y23	W22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO176	GPIO	I/O						
177	ETPUB30_GPIO177	P	ETPUB30	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	AA24	AB24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO177	GPIO	I/O						
178	ETPUB31_GPIO178	P	ETPUB31	eTPU B channel	I/O	MH	V <sub>DDEH6</sub>	—/WKPCFG	—/WKPCFG	AB24	Y22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO178	GPIO	I/O						
<b>eTPU_C</b>											
440	TCRCLKC_GPIO440	P	TCRCLKC	eTPU C TCR clock	I	MH	V <sub>DDEH7</sub>	—/Up	—/Up	B26	F22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO440	GPIO	I/O						
441	ETPUC0_GPIO441	P	ETPUC0	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	C25	C25
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO441	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
448	ETPUC7_PCSE4_GPIO448	P	ETPUC7	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	F23	F23
		A1		DSPI E peripheral chip select							
		A2	—	—	—						
		G	GPIO448	GPIO	I/O						
449	ETPUC8_PCSE5_GPIO449	P	ETPUC8	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	F24	F24
		A1		DSPI E peripheral chip select							
		A2	—	—	—						
		G	GPIO449	GPIO	I/O						
450	ETPUC9_IRQ0_GPIO450	P	ETPUC9	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	F25	F25
		A1	IRQ0	External interrupt request	I						
		A2	—	—	—						
		G	GPIO450	GPIO	I/O						
451	ETPUC10_IRQ1_GPIO451	P	ETPUC10	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	F26	F26
		A1	IRQ1	External interrupt request	I						
		A2	—	—	—						
		G	GPIO451	GPIO	I/O						
452	ETPUC11_IRQ2_GPIO452	P	ETPUC11	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	G23	G22
		A1	IRQ2	External interrupt request	I						
		A2	—	—	—						
		G	GPIO452	GPIO	I/O						
453	ETPUC12_IRQ3_GPIO453	P	ETPUC12	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	G24	G23
		A1	IRQ3	External interrupt request	I						
		A2	—	—	—						
		G	GPIO453	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
460	ETPUC19_TXDA_GPIO460	P	ETPUC19	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	J23	H21
		A1	TXDA	eSCI A transmit	O						
		A2	—	—	—						
		G	GPIO460	GPIO	I/O						
461	ETPUC20_RXDA_GPIO461	P	ETPUC20	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	J24	H25
		A1	RXDA	eSCI A receive	I						
		A2	—	—	—						
		G	GPIO461	GPIO	I/O						
462	ETPUC21_TXDB_GPIO462	P	ETPUC21	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	J25	H26
		A1	TXDB	eSCI B transmit	O						
		A2	—	—	—						
		G	GPIO462	GPIO	I/O						
463	ETPUC22_RXDB_GPIO463	P	ETPUC22	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	J26	J22
		A1	RXDB	eSCI B receive	I						
		A2	—	—	—						
		G	GPIO463	GPIO	I/O						
464	ETPUC23_PCS5_GPIO464	P	ETPUC23	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	K23	J23
		A1	PCSD5	DSPI D peripheral chip select	O						
		A2	MAA0	ADC A Mux Address 0	O						
		A3	MAB0	ADC B Mux Address 0	O						
		G	GPIO464	GPIO	I/O						
465	ETPUC24_PCS4_GPIO465	P	ETPUC24	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	K24	J24
		A1	PCSD4	DSPI D peripheral chip select	O						
		A2	MAA1	ADC A Mux Address 1	O						
		A4	MAB1	ADC B Mux Address 1	O						
		G	GPIO465	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
472	ETPUC31_SIND_GPIO472	P	ETPUC31	eTPU C channel	I/O	MH	V <sub>DDEH7</sub>	—/WKPCFG	—/WKPCFG	M23	K25
		A1	SIND	DSPI D data input	I						
		A2	—	—	—						
		G	GPIO472	GPIO	I/O						
<b>eMIOS</b>											
179	EMIOS0_ETPUA0_GPIO179	P	EMIOS0	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AE10	AC13
		A1	ETPUA0	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO179	GPIO	I/O						
180	EMIOS1_ETPUA1_GPIO180	P	EMIOS1	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AF10	AB13
		A1	ETPUA1	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO180	GPIO	I/O						
181	EMIOS2_ETPUA2_GPIO181	P	EMIOS2	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AD11	AD13
		A1	ETPUA2	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO181	GPIO	I/O						
182	EMIOS3_ETPUA3_GPIO182	P	EMIOS3	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AE11	AE13
		A1	ETPUA3	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO182	GPIO	I/O						
183	EMIOS4_ETPUA4_GPIO183	P	EMIOS4	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AF11	AF13
		A1	ETPUA4	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO183	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
190	EMIOS11_SIND_GPIO190	P	EMIOS11	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AF13	AB14
		A1	SIND	DSPI D data input	I						
		A2	—	—	—						
		G	GPIO190	GPIO	I/O						
191	EMIOS12_SOUTC_GPIO191	P	EMIOS12	eMIOS channel	O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AF14	AD15
		A1	SOUTC	DSPI C data output	O						
		A2	—	—	—						
		G	GPIO191	GPIO	I/O						
192	EMIOS13_SOUTD_GPIO192	P	EMIOS13	eMIOS channel	O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AE14	AC15
		A1	SOUTD	DSPI D data output	O						
		A2	—	—	—						
		G	GPIO192	GPIO	I/O						
193	EMIOS14_IRQ0_GPIO193	P	EMIOS14	eMIOS channel	O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AC14	AF17
		A1	IRQ0	External interrupt request	I						
		A2	CNTXD	FlexCAN D transmit	O						
		G	GPIO193	GPIO	I/O						
194	EMIOS15_IRQ1_GPIO194	P	EMIOS15	eMIOS channel	O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AD14	AE16
		A1	IRQ1	External interrupt request	I						
		A2	CNRXD	FlexCAN D receive	I						
		G	GPIO194	GPIO	I/O						
195	EMIOS16_ETPUB0_GPIO195	P	EMIOS16	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AF15	AD16
		A1	ETPUB0	eTPU B channel	O						
		A2	FR_DBG[3]	FlexRay debug	O						
		G	GPIO195	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
202	EMIOS23_ETPUB7_GPIO202	P	EMIOS23	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AD16	AA16
		A1	ETPUB7	eTPU B channel	O						
		A2	—	—	—						
		G	GPIO202	GPIO	I/O						
203	EMIOS24_PCSB0_GPIO203	P	EMIOS24	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AF17	AC17
		A1	PCSB0	DSPI B peripheral chip select	I/O						
		A2	—	—	—						
		G	GPIO203	GPIO	I/O						
204	EMIOS25_PCSB1_GPIO204	P	EMIOS25	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AE17	AF18
		A1	PCSB1	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO204	GPIO	I/O						
432	EMIOS26_PCSB2_GPIO432	P	EMIOS26	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AD17	AE18
		A1	PCSB2	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO432	GPIO	I/O						
433	EMIOS27_PCSB3_GPIO433	P	EMIOS27	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AC17	AD18
		A1	PCSB3	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO433	GPIO	I/O						
434	EMIOS28_PCSC0_GPIO434	P	EMIOS28	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AF18	AC18
		A1	PCSC0	DSPI C peripheral chip select	I/O						
		A2	—	—	—						
		G	GPIO434	GPIO	I/O						

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
435	EMIOS29_PCSC1_GPIO435	P	EMIOS29	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AE18	AB17
		A1	PCSC1	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO435	GPIO	I/O						
436	EMIOS30_PCSC2_GPIO436	P	EMIOS30	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AD18	AF19
		A1	PCSC2	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO436	GPIO	I/O						
437	EMIOS31_PCSC5_GPIO437	P	EMIOS31	eMIOS channel	I/O	MH	V <sub>DDEH4</sub>	—/WKPCFG	—/WKPCFG	AC18	AA17
		A1	PCSC5	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO437	GPIO	I/O						
<b>eQADC</b>											
—	ANA0	P	ANA0 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA0	ANA0	A4	A4
—	ANA1	P	ANA1 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA1	ANA1	B5	B5
—	ANA2	P	ANA2 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA2	ANA2	C5	C5
—	ANA3	P	ANA3 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA3	ANA3	D6	D6
—	ANA4	P	ANA4 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA4	ANA4	A5	A5
—	ANA5	P	ANA5 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA5	ANA5	B6	B6
—	ANA6	P	ANA6 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA6	ANA6	C6	C6
—	ANA7	P	ANA7 <sup>9</sup>	eQADC A shared analog input	I	AE/up-down	V <sub>DDA_A1</sub>	ANA7	ANA7	D7	C7

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
—	ANA8	P	ANA8	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA8	ANA8	A6	D7
—	ANA9	P	ANA9	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA9	ANA9	C7	A6
—	ANA10	P	ANA10	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA10	ANA10	B7	B7
—	ANA11	P	ANA11	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA11	ANA11	A7	A7
—	ANA12	P	ANA12	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA12	ANA12	D8	D8
—	ANA13	P	ANA13	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA13	ANA13	C8	C8
—	ANA14	P	ANA14	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA14	ANA14	B8	B8
—	ANA15	P	ANA15	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA15	ANA15	A8	A8
—	ANA16	P	ANA16	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA16	ANA16	D9	D9
—	ANA17	P	ANA17	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA17	ANA17	C9	C9
—	ANA18	P	ANA18	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA18	ANA18	D10	D10
—	ANA19	P	ANA19	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA19	ANA19	C10	C10
—	ANA20	P	ANA20	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA20	ANA20	D11	D11
—	ANA21	P	ANA21	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA21	ANA21	C11	C11
—	ANA22	P	ANA22	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA22	ANA22	D12	C12
—	ANA23	P	ANA23	eQADC A analog input	I	AE	V <sub>DDA_A1</sub>	ANA23	ANA23	C12	D12
—	AN24	P	AN24	eQADC analog input	I	AE	V <sub>DDA_A0</sub>	AN24	AN24	B12	B12
—	AN25	P	AN25	eQADC analog input	I	AE	V <sub>DDA_A0</sub>	AN25	AN25	D13	C13
—	AN26	P	AN26	eQADC analog input	I	AE	V <sub>DDA_A0</sub>	AN26	AN26	C13	D13
—	AN27	P	AN27	eQADC analog input	I	AE	V <sub>DDA_A0</sub>	AN27	AN27	B13	B13
—	AN28	P	AN28	eQADC analog input	I	AE	V <sub>DDA_A0</sub>	AN28	AN28	A13	A13
—	AN29	P	AN29	eQADC analog input	I	AE	V <sub>DDA_A0</sub>	AN29	AN29	B14	A14
—	AN30	P	AN30	eQADC analog input	I	AE	V <sub>DDA_B1</sub>	AN30	AN30	C14	B14
—	AN31	P	AN31	eQADC analog input	I	AE	V <sub>DDA_B1</sub>	AN31	AN31	D14	C14
—	AN32	P	AN32	eQADC analog input	I	AE	V <sub>DDA_B1</sub>	AN32	AN32	A14	B15
—	AN33	P	AN33	eQADC analog input	I	AE	V <sub>DDA_B0</sub>	AN33	AN33	B15	D14
—	AN34	P	AN34	eQADC analog input	I	AE	V <sub>DDA_B0</sub>	AN34	AN34	C15	C15

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
—	AN35	P	AN35	eQADC analog input	I	AE	V <sub>DDA_B0</sub>	AN35	AN35	D15	D15
—	AN36	P	AN36	eQADC analog input	I	AE	V <sub>DDA_B1</sub>	AN36	AN36	A15	A15
—	AN37	P	AN37	eQADC analog input	I	AE	V <sub>DDA_B0</sub>	AN37	AN37	C16	C17
—	AN38	P	AN38	eQADC analog input	I	AE	V <sub>DDA_B0</sub>	AN38	AN38	C17	D16
—	AN39	P	AN39	eQADC analog input	I	AE	V <sub>DDA_B0</sub>	AN39	AN39	D16	C16
—	ANB0	P	ANB0	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB0	ANB0	C18	C18
—	ANB1	P	ANB1	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB1	ANB1	D17	D17
—	ANB2	P	ANB2	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB2	ANB2	D18	D18
—	ANB3	P	ANB3	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB3	ANB3	D19	D19
—	ANB4	P	ANB4	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB4	ANB4	C19	B19
—	ANB5	P	ANB5	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB5	ANB5	C20	A20
—	ANB6	P	ANB6	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB6	ANB6	B19	C20
—	ANB7	P	ANB7	eQADC B shared analog input	I	AE/up-down	V <sub>DDA_B0</sub>	ANB7	ANB7	A20	C19
—	ANB8	P	ANB8	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB8	ANB8	B20	B20
—	ANB9	P	ANB9	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB9	ANB9	D20	A21
—	ANB10	P	ANB10	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB10	ANB10	B21	B21
—	ANB11	P	ANB11	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB11	ANB11	A21	C21
—	ANB12	P	ANB12	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB12	ANB12	C21	A22
—	ANB13	P	ANB13	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB13	ANB13	D21	B22
—	ANB14	P	ANB14	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB14	ANB14	A22	D20
—	ANB15	P	ANB15	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB15	ANB15	B22	C22
—	ANB16	P	ANB16	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB16	ANB16	C22	D21

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
—	ANB17	P	ANB17	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB17	ANB17	A23	D22
—	ANB18	P	ANB18	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB18	ANB18	B23	A23
—	ANB19	P	ANB19	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB19	ANB19	C23	B23
—	ANB20	P	ANB20	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB20	ANB20	D22	C23
—	ANB21	P	ANB21	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB21	ANB21	A24	A24
—	ANB22	P	ANB22	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB22	ANB22	B24	B24
—	ANB23	P	ANB23	eQADC B analog input	I	AE	V <sub>DDA_B0</sub>	ANB23	ANB23	A25	E20
—	VRH_A	P	VRH_A	ADC A Voltage reference high	I	VDDINT	V <sub>RH_A</sub>	VRH_A	VRH_A	A12	A12
—	VRL_A	P	VRL_A	ADC A Voltage reference low	I	VSSINT	V <sub>RL_A</sub>	VRL_A	VRL_A	A11	A11
—	VRH_B	P	VRH_B	ADC B Voltage reference high	I	VDDINT	V <sub>RH_B</sub>	VRH_B	VRH_B	A19	A19
—	VRL_B	P	VRL_B	ADC B Voltage reference low	I	VSSINT	V <sub>RL_B</sub>	VRL_B	VRL_B	A18	A18
—	REFBYPBCB	P	REFBYPBCB	ADC B Reference bypass capacitor	I	AE	V <sub>DDA_B0</sub>	REFBYPBCB	REFBYPBCB	B18	B18
—	REFBYPACA	P	REFBYPACA	ADC A Reference bypass capacitor	I	AE	V <sub>DDA_A1</sub>	REFBYPACA	REFBYPACA	B11	B11
—	VDDA_A0	P	VDDA_A	Internal logic supply input	I	VDDE	V <sub>DDA_A0</sub>	VDDA_A0	VDDA_A0	A9	A9
—	VDDA_A1	P	VDDA_A	Internal logic supply input	I	VDDE	V <sub>DDA_A1</sub>	VDDA_A1	VDDA_A1	B9	B9
—	REFBYPACA1	P	REFBYPACA1	ADC A Reference bypass capacitor	I	AE	V <sub>DDA_A1</sub>	REFBYPACA1	REFBYPACA1	A10	A10
—	VSSA_A1	P	VSSA_A	Ground	I	VSSE	V <sub>SSA_A1</sub>	VSSA_A1	VSSA_A1	B10	B10
—	VDDA_B0	P	VDDA_B	Internal logic supply input	I	VDDE	V <sub>DDA_B0</sub>	VDDA_B0	VDDA_B0	A16	A16
—	VDDA_B1	P	VDDA_B	Internal logic supply input	I	VDDE	V <sub>DDA_B1</sub>	VDDA_B1	VDDA_B1	B16	B16
—	VSSA_B0	P	VSSA_B	Ground	I	VSSE	V <sub>SSA_B0</sub>	VSSA_B0	VSSA_B0	B17	B17
—	REFBYPBCB1	P	REFBYPBCB1	ADC B Reference bypass capacitor	I	AE	V <sub>DDA_B0</sub>	REFBYPBCB1	REFBYPBCB1	A17	A17
<b>FlexRay</b>											
248	FR_A_TX_GPIO248	P	FR_A_TX	FlexRay A transfer	O	FS	V <sub>DDE2</sub>	—/Up (/— for Rev.1 of the device)	—/Up (/— for Rev.1 of the device)	AD4	AD4
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO248	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
84	CNRXA_RXDA_GPIO84	P	CNRXA	FlexCAN A receive	I	MH	V <sub>DDEH4</sub>	—/Up	—/Up	AE19	AD19
		A1	RXDA	eSCI A receive	I						
		A2	—	—	—						
		G	GPIO84	GPIO	I/O						
85	CNTXB_PCSC3_GPIO85	P	CNTXB	FlexCAN B transmit	O	MH	V <sub>DDEH4</sub>	—/Up	—/Up	AD19	AC19
		A1	PCSC3	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO85	GPIO	I/O						
86	CNRXB_PCSC4_GPIO86	P	CNRXB	FlexCAN B receive	I	MH	V <sub>DDEH4</sub>	—/Up	—/Up	AC19	AA19
		A1	PCSC4	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO86	GPIO	I/O						
87	CNTXC_PCS3_GPIO87	P	CNTXC	FlexCAN C transmit	O	MH	V <sub>DDEH4</sub>	—/Up	—/Up	AF20	AF20
		A1	PCSD3	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO87	GPIO	I/O						
88	CNRXC_PCS4_GPIO88	P	CNRXC	FlexCAN C receive	I	MH	V <sub>DDEH4</sub>	—/Up	—/Up	AE20	AE20
		A1	PCSD4	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO88	GPIO	I/O						
246	CNTXD_GPIO246	P	CNTXD	FlexCAN D transmit	O	MH	V <sub>DDEH4</sub>	—/Up	—/Up	AD20	AD20
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO246	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
245	RXDC_GPIO245	P	RXDC	eSCI C receive	I	MH	V <sub>DDEH5</sub>	—/Up	—/Up	AD22	AD22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO245	GPIO	I/O						
<b>DSPI</b>											
93	SCKA_PCSC1_GPIO93	P	SCKA	DSPI A clock	I/O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AD8	AB8
		A1	PCSC1	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO93	GPIO	I/O						
94	SINA_PCSC2_GPIO94	P	SINA	DSPI A data input	I	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AF7	AE7
		A1	PCSC2	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO94	GPIO	I/O						
95	SOUTA_PCSC5_GPIO95	P	SOUTA	DSPI A data output	O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AD7	AC7
		A1	PCSC5	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO95	GPIO	I/O						
96	PCSA0_PCS2D_GPIO96	P	PCSA0	DSPI A peripheral chip select	I/O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AE6	AD6
		A1	PCSD2	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO96	GPIO	I/O						
97	PCSA1_PCSE0_GPIO97	P	PCSA1	DSPI A peripheral chip select	O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AC6	AC6
		A1		DSPI E peripheral chip select							
		A2	—	—	—						
		G	GPIO97	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
104	SOUTB_GPIO104	P	SOUTB	DSPI B data output	O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AF9	AA10
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO104	GPIO	I/O						
105	PCSB0_PCSD2_GPIO105	P	PCSB0	DSPI B peripheral chip select	I/O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AD9	AF8
		A1	PCSD2	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO105	GPIO	I/O						
106	PCSB1_PCSD0_GPIO106	P	PCSB1	DSPI B peripheral chip select	O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AC9	AE8
		A1	PCSD0	DSPI D peripheral chip select	I/O						
		A2	—	—	—						
		G	GPIO106	GPIO	I/O						
107	PCSB2_SOUTC_GPIO107	P	PCSB2	DSPI B peripheral chip select	O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AF8	AD8
		A1	SOUTC	DSPI C data output	O						
		A2	—	—	—						
		G	GPIO107	GPIO	I/O						
108	PCSB3_SINC_GPIO108	P	PCSB3	DSPI B peripheral chip select	O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AD10	AC9
		A1	SINC	DSPI C data input	I						
		A2	—	—	—						
		G	GPIO108	GPIO	I/O						
109	PCSB4_SCKC_GPIO109	P	PCSB4	DSPI B peripheral chip select	O	MH	V <sub>DDEH3</sub>	—/Up	—/Up	AC8	AF7
		A1	SCKC	DSPI C clock	I/O						
		A2	—	—	—						
		G	GPIO109	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
240	PCSC2_GPIO240	P	PCSC2	DSPI C peripheral chip select	O	MH	V <sub>DDEH5</sub>	—/Up	—/Up	AE23	AE23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO240	GPIO	I/O						
241	PCSC3_GPIO241	P	PCSC3	DSPI C peripheral chip select	O	MH	V <sub>DDEH5</sub>	—/Up	—/Up	AD23	AD23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO241	GPIO	I/O						
242	PCSC4_GPIO242	P	PCSC4	DSPI C peripheral chip select	O	MH	V <sub>DDEH5</sub>	—/Up	—/Up	AF24	AF24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO242	GPIO	I/O						
243	PCSC5_GPIO243	P	PCSC5	DSPI C peripheral chip select	O	MH	V <sub>DDEH5</sub>	—/Up	—/Up	AE24	AE24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO243	GPIO	I/O						
<b>EBI</b>											
256	D_CS0_GPIO256	P	D_CS0	EBI chip select 0	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AD9
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO256	GPIO	I/O						
257	D_CS2_D_ADD_DAT31_GPIO257	P	D_CS2	EBI chip select 2	O	F	V <sub>DDE8</sub>	—/Up	—/Up	—	U1
		A1	D_ADD_DAT31	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO257	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
264	D_ADD17_D_ADD_DAT17_GPIO264	P	D_ADD17	EBI address bus	O	F	V <sub>DDE8</sub>	—/Up	—/Up	—	T5
		A1	D_ADD_DAT17	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO264	GPIO	I/O						
265	D_ADD18_D_ADD_DAT18_GPIO265	P	D_ADD18	EBI address bus	O	F	V <sub>DDE8</sub>	—/Up	—/Up	—	T2
		A1	D_ADD_DAT18	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO265	GPIO	I/O						
266	D_ADD19_D_ADD_DAT19_GPIO266	P	D_ADD19	EBI address bus	O	F	V <sub>DDE8</sub>	—/Up	—/Up	—	T3
		A1	D_ADD_DAT19	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO266	GPIO	I/O						
267	D_ADD20_D_ADD_DAT20_GPIO267	P	D_ADD20	EBI address bus	O	F	V <sub>DDE8</sub>	—/Up	—/Up	—	T4
		A1	D_ADD_DAT20	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO267	GPIO	I/O						
268	D_ADD21_D_ADD_DAT21_GPIO268	P	D_ADD21	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AB11
		A1	D_ADD_DAT21	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO268	GPIO	I/O						
269	D_ADD22_D_ADD_DAT22_GPIO269	P	D_ADD22	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AD10
		A1	D_ADD_DAT22	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO269	GPIO	I/O						

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
270	D_ADD23_D_ADD_DAT23_GPIO270	P	D_ADD23	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AE10
		A1	D_ADD_DAT23	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO270	GPIO	I/O						
271	D_ADD24_D_ADD_DAT24_GPIO271	P	D_ADD24	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AF10
		A1	D_ADD_DAT24	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO271	GPIO	I/O						
272	D_ADD25_D_ADD_DAT25_GPIO272	P	D_ADD25	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AD11
		A1	D_ADD_DAT25	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO272	GPIO	I/O						
273	D_ADD26_D_ADD_DAT26_GPIO273	P	D_ADD26	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AE11
		A1	D_ADD_DAT26	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO273	GPIO	I/O						
274	D_ADD27_D_ADD_DAT27_GPIO274	P	D_ADD27	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AF11
		A1	D_ADD_DAT27	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO274	GPIO	I/O						
275	D_ADD28_D_ADD_DAT28_GPIO275	P	D_ADD28	EBI address bus	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AD12
		A1	D_ADD_DAT28	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO275	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
287	D_ADD_DAT9_GPIO287	P	D_ADD_DAT9	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V <sub>DDE10</sub>	—/Up	—/Up	—	M22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO287	GPIO	I/O						
288	D_ADD_DAT10_GPIO288	P	D_ADD_DAT10	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V <sub>DDE10</sub>	—/Up	—/Up	—	L26
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO288	GPIO	I/O						
289	D_ADD_DAT11_GPIO289	P	D_ADD_DAT11	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V <sub>DDE10</sub>	—/Up	—/Up	—	L25
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO289	GPIO	I/O						
290	D_ADD_DAT12_GPIO290	P	D_ADD_DAT12	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V <sub>DDE10</sub>	—/Up	—/Up	—	L24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO290	GPIO	I/O						
291	D_ADD_DAT13_GPIO291	P	D_ADD_DAT13	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V <sub>DDE10</sub>	—/Up	—/Up	—	L23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO291	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
298	D_TS_GPIO298	P	D_TS	EBI transfer start	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AE9
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO298	GPIO	I/O						
299	D_ALE_GPIO299	P	D_ALE	EBI Address Latch Enable	O	F	V <sub>DDE10</sub>	—/Up	—/Up	—	P24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO299	GPIO	I/O						
300	D_TA_GPIO300	P	D_TA	EBI transfer acknowledge	I/O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AF9
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO300	GPIO	I/O						
301	D_CS1_GPIO301	P	D_CS1	EBI chip select	O	F	V <sub>DDE9</sub>	—/Up	—/Up	—	AB10
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO301	GPIO	I/O						
302	D_BDIP_GPIO302	P	D_BDIP	EBI burst data in progress	O	F	V <sub>DDE8</sub>	—/Up	—/Up	—	M2
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO302	GPIO	I/O						
303	D_WE2_GPIO303	P	D_WE2	EBI write enable	O	F	V <sub>DDE8</sub>	—/Up	—/Up	—	N2
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO303	GPIO	I/O						

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
212	BOOTCFG1_IRQ3_GPIO212	P	BOOTCFG1	Boot configuration	I	MH	V <sub>DDEH1</sub>	BOOTCFG/Down	—/Down	N2	L3
		A1	IRQ3	External interrupt request	I						
		A2	—	—	—						
		G	GPIO212	GPIO	I/O						
213	WKPCFG_NMI_GPIO213 <sup>10</sup>	P	WKPCFG	Weak pull configuration input	I	MH	V <sub>DDEH1</sub>	WKPCFG/Up	—/Up	N3	M5
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO213	GPIO	I						
208	PLLCFG0_IRQ4_GPIO208	P	PLLCFG0	FMPPLL mode configuration input	I	MH	V <sub>DDEH1</sub>	PLLCFG/Up	—/Up	R3	M3
		A1	IRQ4	External interrupt request	I						
		A2	—	—	—						
		G	GPIO208	GPIO	I/O						
209	PLLCFG1_IRQ5_GPIO209	P	PLLCFG1	FMPPLL mode configuration input	I	MH	V <sub>DDEH1</sub>	PLLCFG/Up	—/Up	P2	L1
		A1	IRQ5	External interrupt request	I						
		A2	SOUTD	DSPI D data output	O						
		G	GPIO209	GPIO	I/O						
—	PLLCFG2	P	PLLCFG2	FMPPLL mode configuration input	I	MH	V <sub>DDEH1</sub>	PLLCFG/Down	—/Down	P3	L2
—	XTAL	P	XTAL	Crystal oscillator output	O	AE	V <sub>DD33</sub>	XTAL	XTAL	AC26	AC26
—	EXTAL	P	EXTAL	Crystal oscillator input	I	AE	V <sub>DD33</sub>	EXTAL	EXTAL	AB26	AB26
229	D_CLKOUT	P	D_CLKOUT	EBI system clock output	O	F	V <sub>DDE9</sub>	CLKOUT/Enabled	CLKOUT/Enabled	—	AF12
214	ENGCLK	P	ENGCLK	EBI engineering clock output Note: EXTCLK (External clock input) selected through SIU register)	O	F	V <sub>DDE2</sub>	ENGCLK/Enabled	ENGCLK/Enabled	AD1	AD1
JTAG and Nexus (see footnote <sup>11</sup> about resets)											
—	EVTI	— <sup>12</sup>	EVTI	Nexus event in	I	F	V <sub>DDE2</sub>	—/Up	EVTI/Up	T4	V1

**Table 39. Signal Properties and Muxing Summary (continued)**

**Table 39. Signal Properties and Muxing Summary (continued)**

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
82	MDO11_GPIO82	- <sup>12</sup>	MDO11 <sup>14</sup>	Nexus message data out	O	F	V <sub>DDE2</sub>	O/Low	—/Down	Y3	Y4
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO82	GPIO	I/O						
231	MDO12_GPIO231	- <sup>12</sup>	MDO12 <sup>14</sup>	Nexus message data out	O	F	V <sub>DDE2</sub>	O/Low	—/Down	AA1	Y5
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO231	GPIO	I/O						
232	MDO13_GPIO232	- <sup>12</sup>	MDO13 <sup>14</sup>	Nexus message data out	O	F	V <sub>DDE2</sub>	O/Low	—/Down	AA2	AA1
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO232	GPIO	I/O						
233	MDO14_GPIO233	- <sup>12</sup>	MDO14 <sup>14</sup>	Nexus message data out	O	F	V <sub>DDE2</sub>	O/Low	—/Down	AA3	AA2
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO233	GPIO	I/O						
234	MDO15_GPIO234	- <sup>12</sup>	MDO15 <sup>14</sup>	Nexus message data out	O	F	V <sub>DDE2</sub>	O/Low	—/Down	Y4	AA3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO234	GPIO	I/O						
224	<u>MSEO0</u>	- <sup>12</sup>	MSEO0 <sup>14</sup>	Nexus message start/end out	O	F	V <sub>DDE2</sub>	O/Low	MSEO/HI	U2	U6
225	<u>MSEO1</u>	- <sup>12</sup>	MSEO1 <sup>14</sup>	Nexus message start/end out	O	F	V <sub>DDE2</sub>	O/Low	MSEO/HI	T3	U5
226	RDY	- <sup>12</sup>	RDY	Nexus ready output	O	F	V <sub>DDE2</sub>	O/Low	RDY/HI	R4	U3
—	TCK	- <sup>12</sup>	TCK	JTAG test clock input	I	F	V <sub>DDE2</sub>	TCK/Down	TCK/Down	AB2	AB2
—	TDI	- <sup>12</sup>	TDI	JTAG test data input	I	F	V <sub>DDE2</sub>	TDI/Up	TDI/Up	AC2	AC2
228	TDO	- <sup>12</sup>	TDO	JTAG test data output	O	F	V <sub>DDE2</sub>	TDO/Up	TDO/Up	AB1	AB1
—	TMS	- <sup>12</sup>	TMS	JTAG test mode select input	I	F	V <sub>DDE2</sub>	TMS/Up	TMS/Up	AB3	AB3

Table 39. Signal Properties and Muxing Summary (continued)

GPIO/PCR <sup>1</sup>	Signal Name <sup>2</sup>	P/A/G <sup>3</sup>	Function <sup>4</sup>	Function Summary	Direction	Pad Type <sup>5</sup>	Voltage <sup>6</sup>	State during RESET <sup>7</sup>	State after RESET <sup>8</sup>	Package Location	
										416	516
—	JCOMP	- <sup>12</sup>	JCOMP	JTAG TAP controller enable	I	F	V <sub>DDE2</sub>	JCOMP/Down	JCOMP/Down	R1	U2
—	TEST	—	TEST	Test mode select (not for customer use)	I	F	V <sub>DDEH1</sub>	TEST/Down	TEST/Down	B4	B4
—	VDDSYN	—	VDDSYN	Clock synthesizer power input	I/O	VDDE	V <sub>DDSYN</sub>	VDDSYN	VDDSYN	AD26	AD26
—	VSSYN	—	VSSYN	Clock synthesizer ground input	I	VSSE	V <sub>DDSYN</sub>	VSSYN	VSSYN	AA26	AA26
—	VSTBY	—	VSTBY	SRAM standby power input	I	VHV	V <sub>DDEH1</sub>	VSTBY	VSTBY	M4	M4
—	REGSEL	—	REGSEL	Selects regulator mode (Linear/Switch mode)	I	AE	V <sub>DDREG</sub>	REGSEL	REGSEL	W23	W23
—	REGCTL	—	REGCTL	Regulator controller output to base/gate of power transistor	O	AE	V <sub>DDREG</sub>	REGCTL	REGCTL	Y26	Y26
—	VSSFL	—	VSSFL	Tie to V <sub>SS</sub>	I	VSS	V <sub>DDREG</sub>	VSSFL	VSSFL	AB25	AB25
—	VDDREG	—	VDDREG	Source voltage for on-chip regulators and Low voltage detect circuits	I	VDDINT	V <sub>DDREG</sub>	VDDREG	VDDREG	AA25	AA25

<sup>1</sup> The GPIO number is the same as the corresponding pad configuration register (SIU\_PCRn) number in pins that have GPIO functionality. For pins that do not have GPIO functionality, this number is the PCR number.

<sup>2</sup> The primary signal name is used as the pin label on the BGA map for identification purposes. However, the primary signal function is not available on all devices and is indicated by a dash in the following table columns: Signal Functions, P/F/G, and I/O Type.

<sup>3</sup> P/A/G stands for Primary/Alternate/GPIO . This column indicates which function on a pin is Primary, Alternate 1, Alternate 2, (Alternate n) and GPIO.

<sup>4</sup> Each line in the Function column corresponds to a separate signal function on the pin. For all device I/O pins, the primary, alternate, or GPIO signal functions are designated in the PA field of the SIU\_PCRn registers except where explicitly noted.

<sup>5</sup> MH = High voltage, medium speed

F = Fast speed

FS = Fast speed with slew

AE = Analog with ESD protection circuitry (up/down = pull up and pull down circuits included in the pad)

VHV = Very high voltage

<sup>6</sup> VDDE (fast I/O) and VDDEH (slow I/O) power supply inputs are grouped into segments. Each segment of VDDEH pins can connect to a separate 3.3–5.0 V (+5%/-10%) power supply input. Each segment of VDDE pins can connect to a separate 1.8–3.3 V ( $\pm 10\%$ ) power supply.

<sup>7</sup> All pins are sampled after the internal POR is negated. The terminology used in this column is: O – output, I – input, Up – weak pull up enabled, Down – weak pulldown enabled, Low – output driven low, High – output driven high, ABS — Auto Baud Select (during Reset or until JCOMP assertion). A dash on the left side of the slash denotes that both the input and output buffers for the pin are off. A dash on the right side of the slash denotes that there is no weak pull up/down enabled on the pin. The signal name to the left or right of the slash indicates the pin is enabled.

<sup>8</sup> The Function After Reset of a GPI function is general purpose input. A dash on the left side of the slash denotes that both the input and output buffers for the pin are off. A dash on the right side of the slash denotes that there is no weak pull up/down enabled on the pin.

- <sup>9</sup> During and just after POR negates, internal pull resistors can be enabled, resulting in as much as 4 mA of current draw. The pull resistors are disabled when the system clock propagates through the device.
- <sup>10</sup> NMI function is selected using the SIU\_IREER/SIU\_IFEER registers and has priority over any other function on this pin.
- <sup>11</sup> Nexus reset is different than system reset; MDO0-11 are enabled in RPM or FPM trace modes, while MDO12-15 are enabled in FPM trace mode only. MSEO and MCKO are also dependent on trace (RPM or FPM) being enabled.
- <sup>12</sup> The Nexus pins don't have a "primary" function as they are not configured by the SIU. The pins are selected by asserting JCOMP and configuring the NPC. SIU values have no effect on the function of these pins once enabled.
- <sup>13</sup> MCKO is disabled from reset; it can be enabled from the tool (controlled by Nexus NPC\_PCR register).
- <sup>14</sup> Do not connect pin directly to a power supply or ground.
- <sup>15</sup> While JCOMP is negated, the MDO0 pad is pulled up because of the default values in its SIU PCR. When JCOMP is asserted, the MDO0 pad is enabled as an output and goes low when the system clock is present.

## Appendix B Revision History

Table 40 describes the changes made to this document between revisions.

**Table 40. Revision History**

Revision	Date	Description
Rev 1	5 Aug 2011	Initial customer release
Rev 2	21 Dec 2011	<p>Added information about specs 1a through 1d in the PMC Electrical Specifications table.</p> <p>Updated the footnote reference (changed from <sup>13</sup> to <sup>14</sup>) of spec 18 of the PMC Electrical Specifications table.</p> <p>Updated the Operating Current 5.0 V Supplies @ fsys = 180MHz VDDA Max value (changed from 30 to 50).</p> <p>Updated footnote <sup>1</sup> of the VDD33 Pad Average DC Current table (changed IDDE to IDD33).</p> <p>Updated the pF value of 11 SRC/DSC Fast with Slew Rate (changed from 2.6 to 200) in the Pad AC Specifications (VDDEH = 5.0 V, VDDE = 3.3 V) table.</p> <p>Added a footnote for ANA0-ANA7 (<sup>9</sup>) functions in the "Signal Properties and Muxing Summary" table.</p> <p>Added a footnote for MDO0-MDO15 (<sup>14</sup>) and MSE00 functions in the "Signal Properties and Muxing Summary" table.</p> <p>Updated figure numbers 25, 27, 29, and 31: Added specs 1-4.</p> <p>Changed the title of the "PFCPR1 Settings" table to "BIUCR1/BIUCR3".</p> <p>Added a new row "Load" under "Termination" in the "DSPI LVDS Pad Specification" table.</p> <p>Updated the "Max" and "Typical" values of "Delay, Z to Normal", "Rise/Fall Time", and "Data Frequency" in the "DSPI LVDS Pad Specification" table.</p> <p>Changed "V<sub>DDE</sub>" to "V<sub>DDEH</sub>" in footnote <sup>10</sup> of the "DC Electrical Specifications" table.</p> <p>Made the following changes in the "DSPI Timing" table:</p> <ul style="list-style-type: none"> <li>• Update the minimum peripheral bus frequencies for "Data Setup Time for Inputs" and "Data Hold Time for Outputs".</li> <li>• Updated the maximum peripheral bus frequencies for "Data Valid (after SCK edge)".</li> <li>• Added "Master (LVDS)" information for "Data Valid (after SCK edge)" and "Data Hold Time for Outputs".</li> </ul> <p>Changed the minimum voltage value of the "I/O Supply Voltage (fast I/O pads)" from "1.62 V" to "3.0 V" in the "DC Electrical Specifications" table.</p> <p>Changed "V<sub>DDE</sub>" values from "1.62 V to 1.98 V" to "3.0 V to 3.6 V" in footnote <sup>1</sup> of the "Pad AC Specifications (V<sub>DDEH</sub> = 5.0 V, V<sub>DDE</sub> = 3.3 V)" table.</p> <p>Removed voltage ranges "1.62 V–1.98 V" and "2.25 V–2.75 V" from "Fast I/O Weak Pull Up/Down Current" in the "DC Electrical Specifications" table.</p>

## Revision History

**Table 40. Revision History (continued)**

Revision	Date	Description
Rev 3	10 August 2012	<p>Added minimum and maximum “Nominal bandgap reference voltage” values in the “PMC Electrical Specifications” table.</p> <p>Updated the maximum “Medium I/O Output Low Voltage” value (changed from <math>0.2 \times V_{DDEH}</math> to <math>0.2 \times V_{DDEH}</math> and <math>0.15 \times V_{DDEH}</math>) in the “DC Electrical Specifications” table, moved reference to the footnote <sup>10</sup> (<math>I_{OH\_S} = \{11.6\}</math> mA and <math>I_{OL\_S} = \{17.7\}</math> mA for {medium} I/O with <math>V_{DDEH} = 4.5</math> V; <math>I_{OH\_S} = \{5.4\}</math> mA and <math>I_{OL\_S} = \{8.1\}</math> mA for {medium} I/O with <math>V_{DDEH} = 3.0</math> V) to “<math>0.2 \times V_{DDEH}</math>”, and added a new footnote <sup>11</sup> (<math>I_{OL\_S}=2</math> mA) to “<math>0.15 \times V_{DDEH}</math>”.</p> <p>Updated footnote<sup>9</sup> (<math>I_{OH\_F} = \{12,20,30,40\}</math> mA and <math>I_{OL\_F} = \{24,40,50,65\}</math> mA for {00,01,10,11} drive mode with <math>V_{DDE} = 3.0</math> V): Removed “<math>I_{OH\_F} = \{7,13,18,25\}</math> mA and <math>I_{OL\_F} = \{18,30,35,50\}</math> mA for {00,01,10,11} drive mode with <math>V_{DDE} = 2.25</math> V; <math>I_{OH\_F} = \{3,7,10,16\}</math> mA and <math>I_{OL\_F} = \{12,20,27,35\}</math> mA for {00,01,10,11} drive mode with <math>V_{DDE} = 1.62</math> V”.</p> <p>Added minimum and maximum values to all rows of the “Power Management Control (PMC) Specification” table.</p> <p>Updated the “Accuracy” temperature values in the “Temperature Sensor Electrical Specifications” table: Changed “–40 C to 100 C to 40 C to 150 C, removed the corresponding “Typ” value, removed “100 C to 150 C, and added minimum (10) and maximum (+10) values.</p> <p>Added a new section “ADC Internal Resource Measurements” and moved “Power Management Control (PMC) Specification”, “Standby RAM Regulator Electrical Specifications”, “ADC Band Gap Reference / LVI Electrical Specifications”, and “Temperature Sensor Electrical Specifications” tables to the section.</p> <p>Changed “Minimum Data Retention at 25 °C ambient temperature” to “Minimum Data Retention at 85 °C ambient temperature” in the “Flash EEPROM Module Life” table.</p> <p>Added the following note after “Flash Program and Erase Specifications (Pending Si characterization)” table in the “C90 Flash Memory Electrical Characteristics” section: “The low, mid, and high address blocks of the flash arrays are erased (all bits set to 1) before leaving the factory.</p> <p>Updated the “DSPI LVDS Pad Specification” table: Changed maximum “Load” value from “25” to “32”; minimum values for “Differential Output Voltage SRC=0b00 or 0b11, SRC=0b01, SRC=0b10” from “150, 90, 160” to “215, 170, 260”; “Transmission lines (Differential) to “Termination Resistance”; “Z<sub>c</sub>” to “R<sub>Load</sub>”; and added the following footnote: “The termination resistance spec is not meant to specify the receiver termination requirements. They are there to establish the measurement criteria for the specs in this table. As per the TIA/EIA-644A standard, the LVDS receiver termination resistance can vary from 90 to 132 Ω .</p>
Rev 4	21 January 2016	<p>Added a table “Flash Memory AC Timing Specifications”.</p> <p>Updated the min and max values from -10 and +10 to -20 and +20 for “Accuracy” in the “Temperature Sensor Electrical Specifications” table.</p>

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